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RF Power Amplifier Design Using LDMOS Semiconductors

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Presentation Outline

- Introduction
- The Market
- Amplifier Concepts
- PA Fundamentals
- Digital Modulation Characterization
- Inside The RF Power Transistor
- Transistor Characteristics
- Pulsed Applications
- Application Circuits
- Thermal Resistance
- Reliability / Electro migration

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Market

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Market

The consumer wants:

- Higher data rates (wireless internet/video/e-mail)

The OEM/Service Provider wants:

- Higher network capacity
- Higher data rates
- More efficient amplifiers (electricity bill, heat generation)
- More quiet amplifiers (environmental noise; “fan-less”)
- Cheap solutions
- Small solutions

The design community of these base stations wants/needs:

- More integrated functionality / Building blocks / Easy of use
- Small solutions
- High efficiency / high gain / highly linear transistors
- Low cost

Market

- **Higher Subscriber Capacity**
 - Digital Modulation Techniques
 - Multiple users per carrier
 - Multi Carrier Applications
- **Higher data rate capacity**
 - To support wireless e-mail, wireless video, wireless internet access etc.
 - More bandwidth
- **All leads to digital wireless networks (GSM, Edge GSM, CDMA, UMTS/W-CDMA) which requires linear PA's**

Higher data rates and higher capacity

- Can be achieved by more complex modulation techniques.
- Can be achieved by “combining” or “using” multiple voice channels simultaneously.
- Higher data rates require more bandwidth.
 - Examples:
 - GSM carrier bandwidth = 200kHz
 - CDMAone carrier bandwidth = 1.2288MHz
 - UMTS carrier bandwidth = 3.84MHz

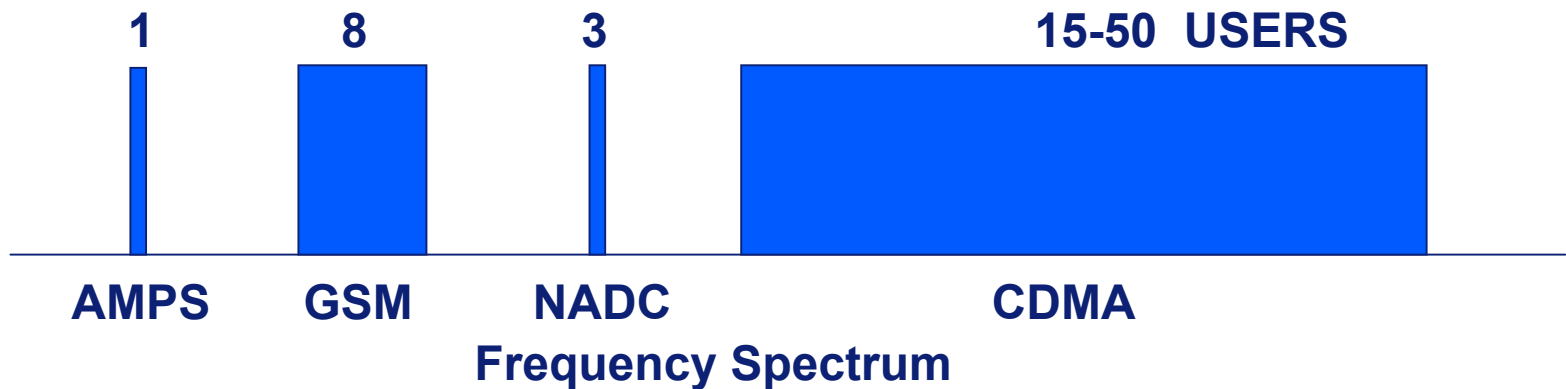
Higher Subscriber Capacity
Higher Data Rate Capacity

It is all about

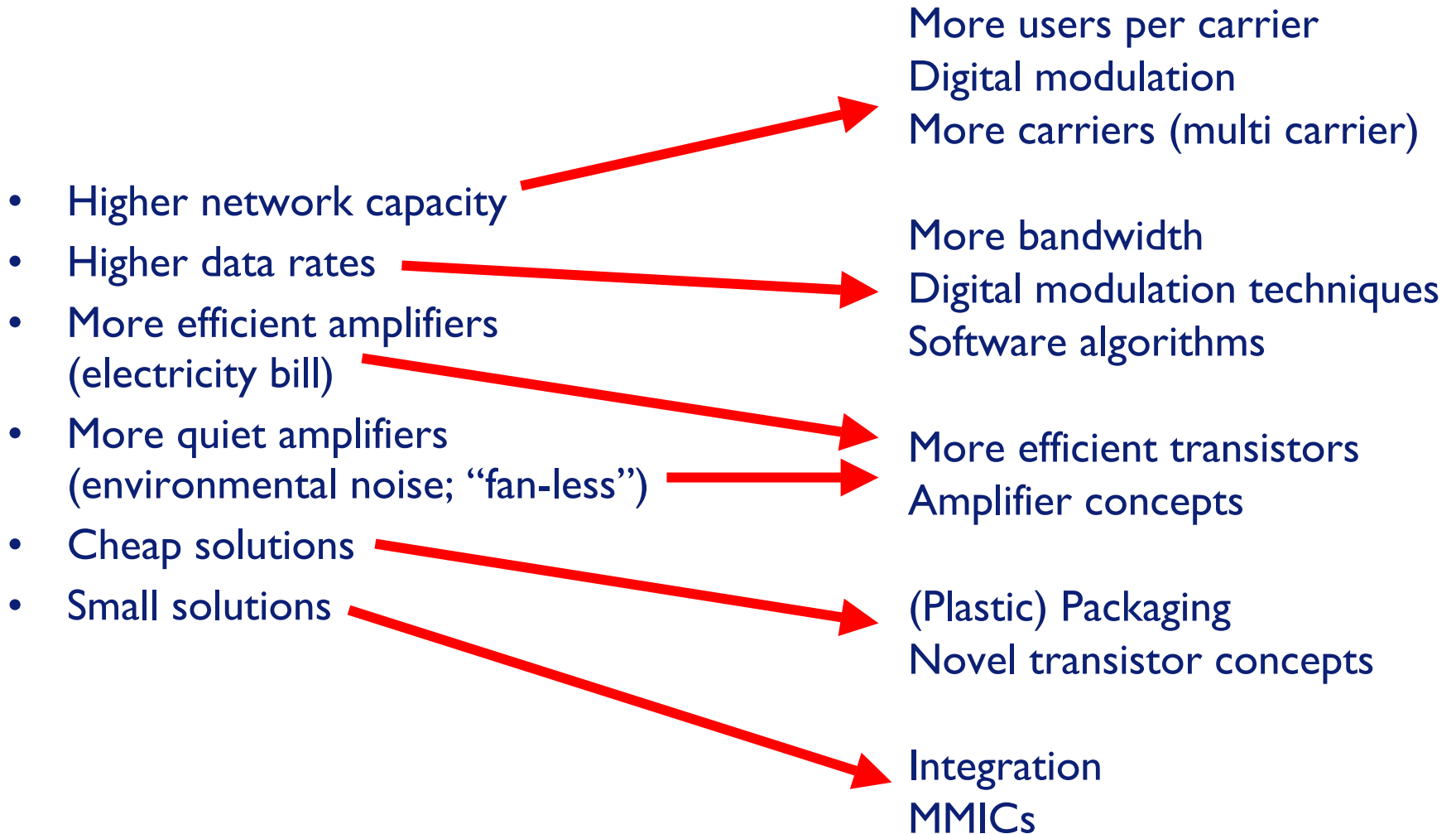
Multi Carrier Applications
and/or
Digital Modulation Techniques
which puts a strain on ...
Amplifier Linearity

Higher Subscriber Capacity

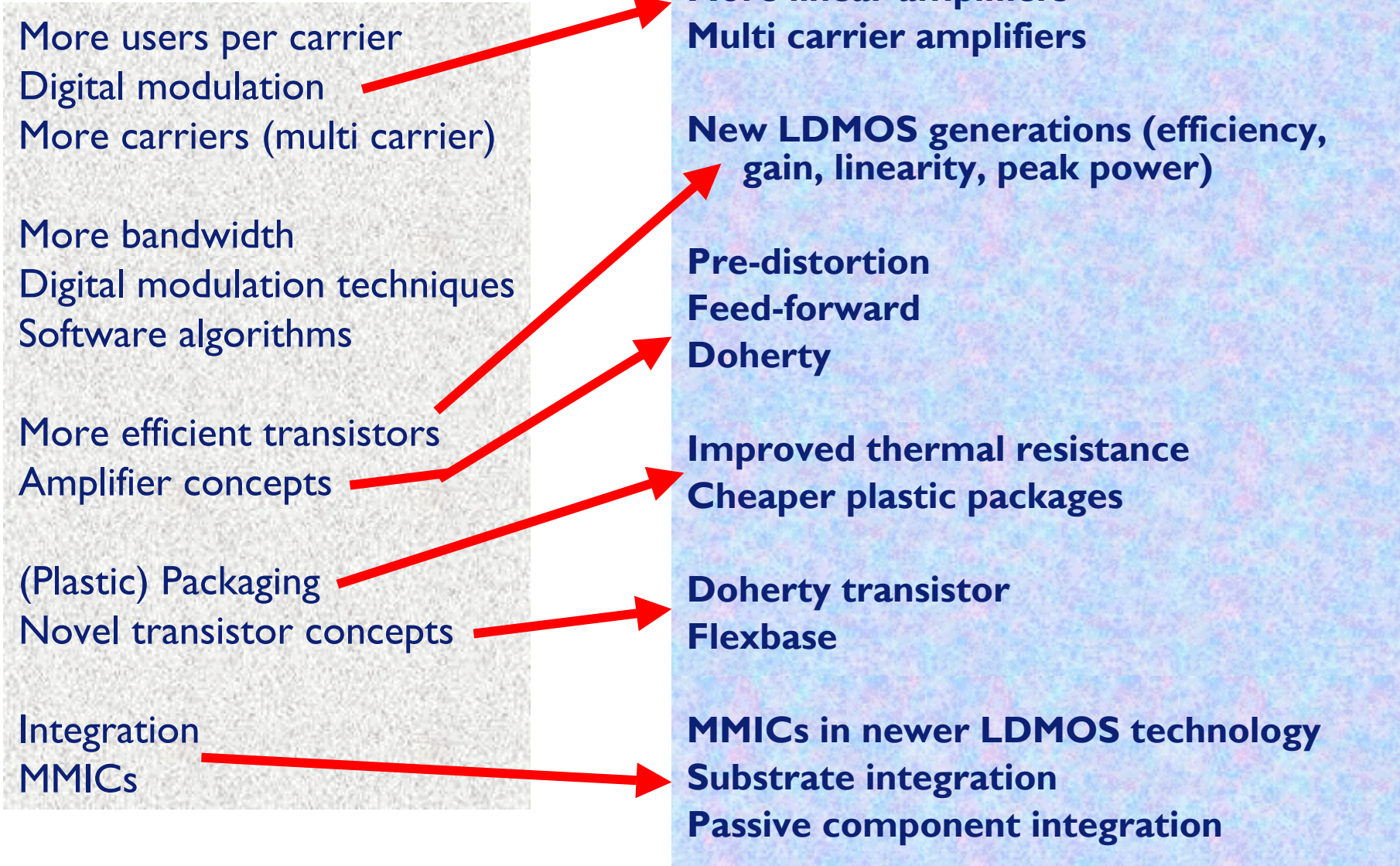
System Standard	Users Per Carrier	Modulation	Channel Spacing
AMPS	1	FDMA	30 kHz
GSM	8	GMSK	200 kHz
NADC (IS-54)	3	$\pi/4$ DQPSK	30 kHz
CDMA	15-50	QPSK	1.25 MHz
W-CDMA	196	QPSK	3.84MHz



Market



Market



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Amplifier Concepts

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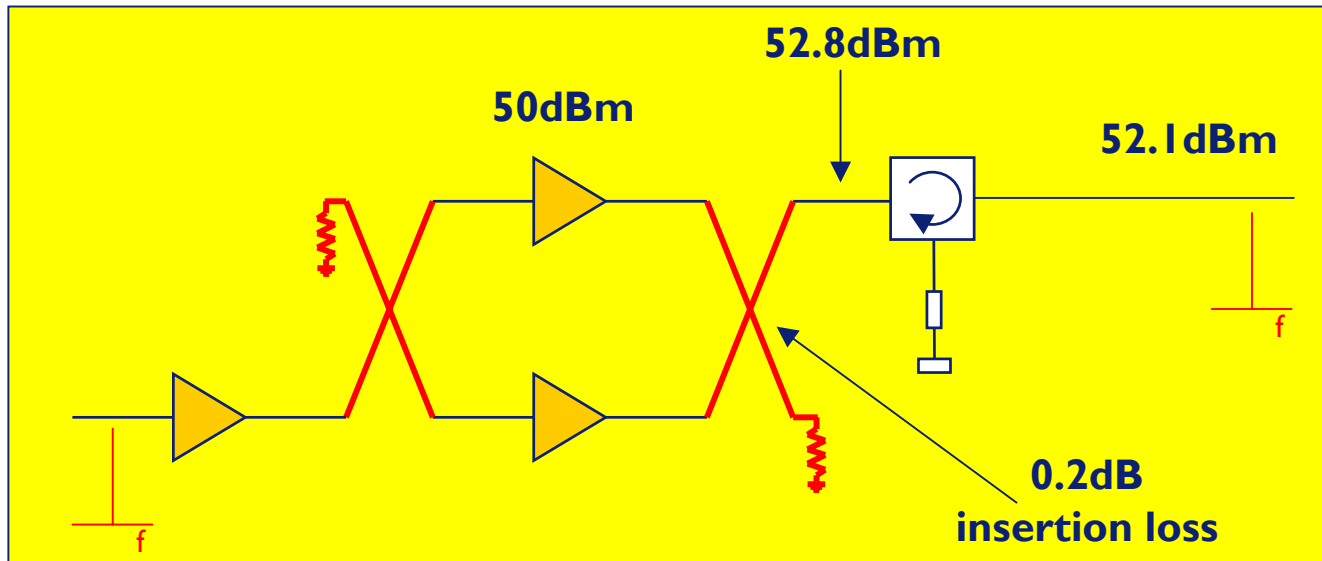
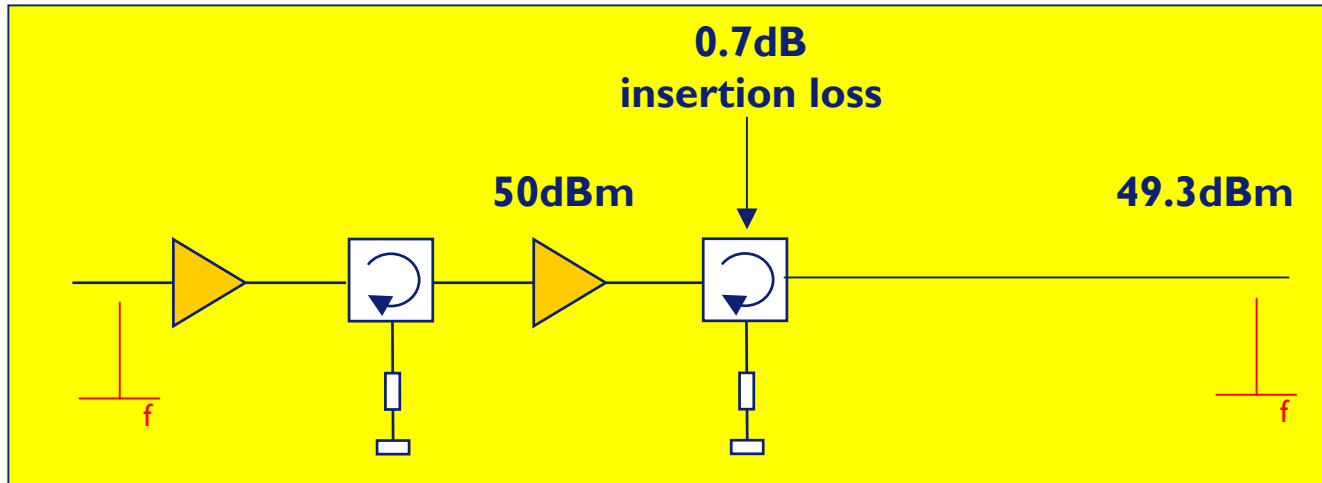
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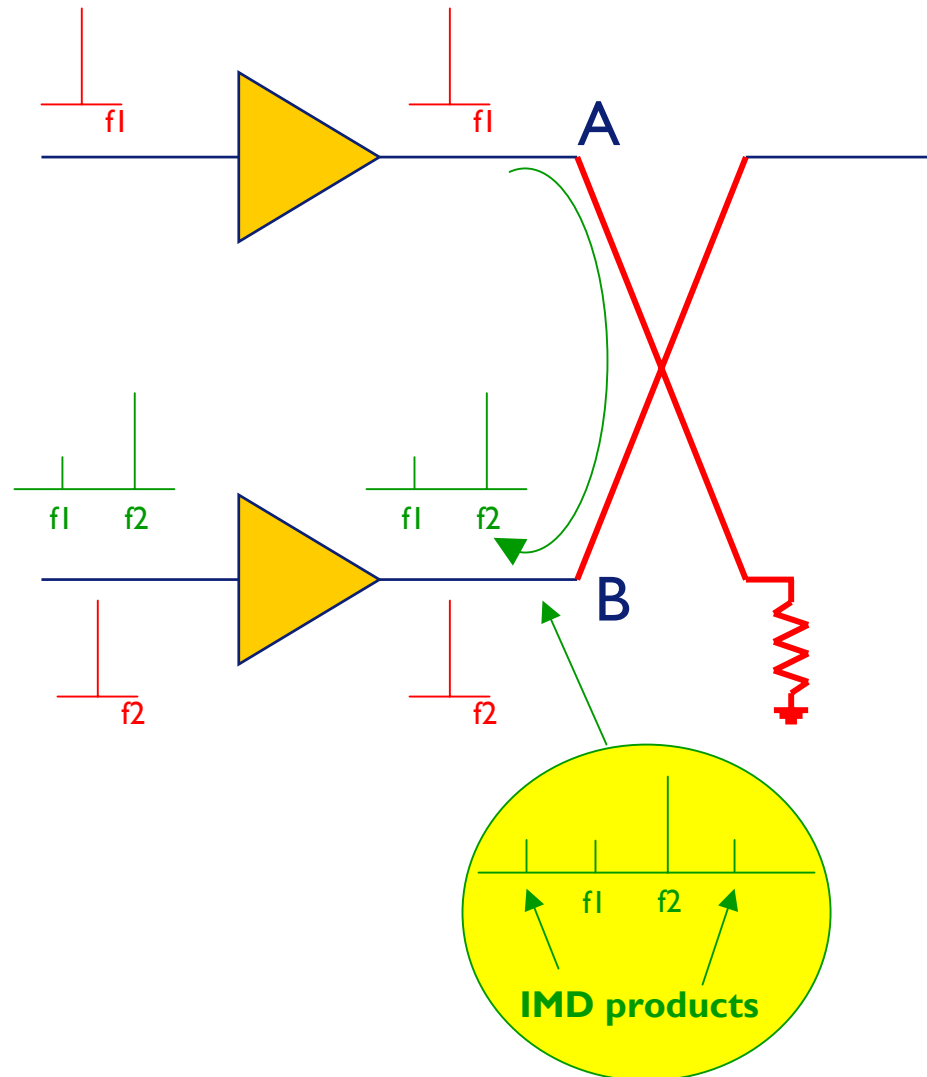
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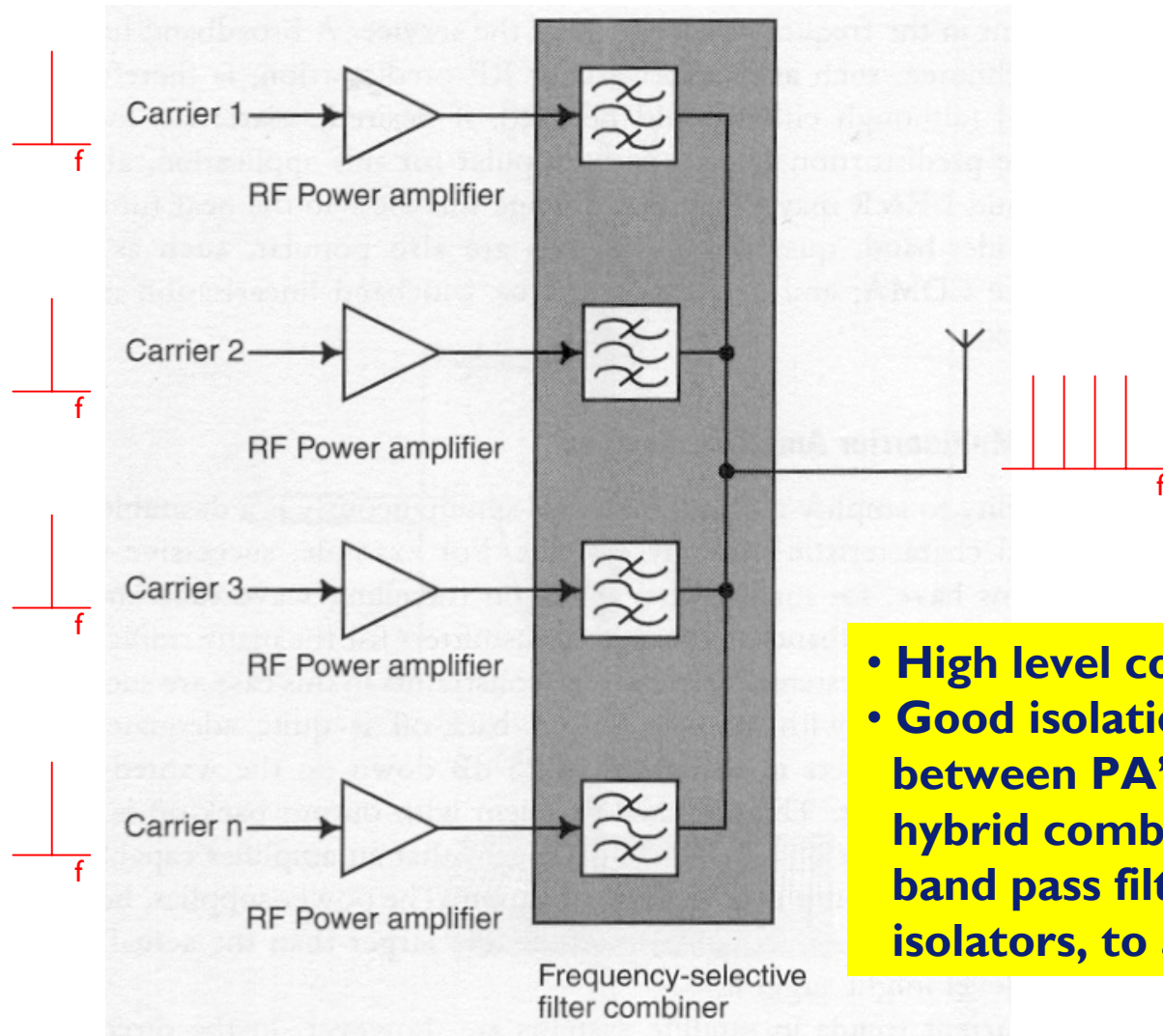
Single carrier amplifiers



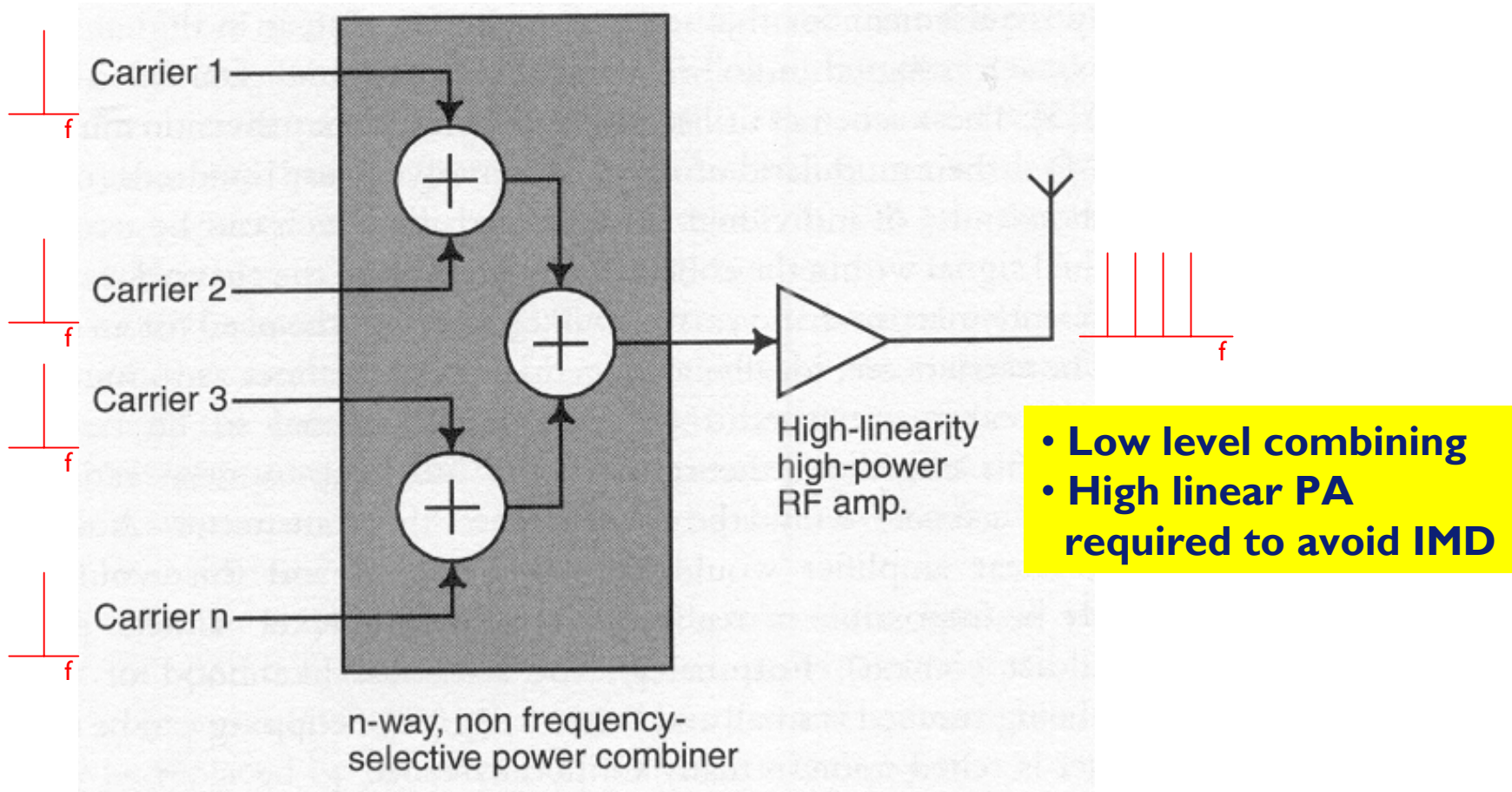
Reverse intermodulation



Combined single carrier amplifiers



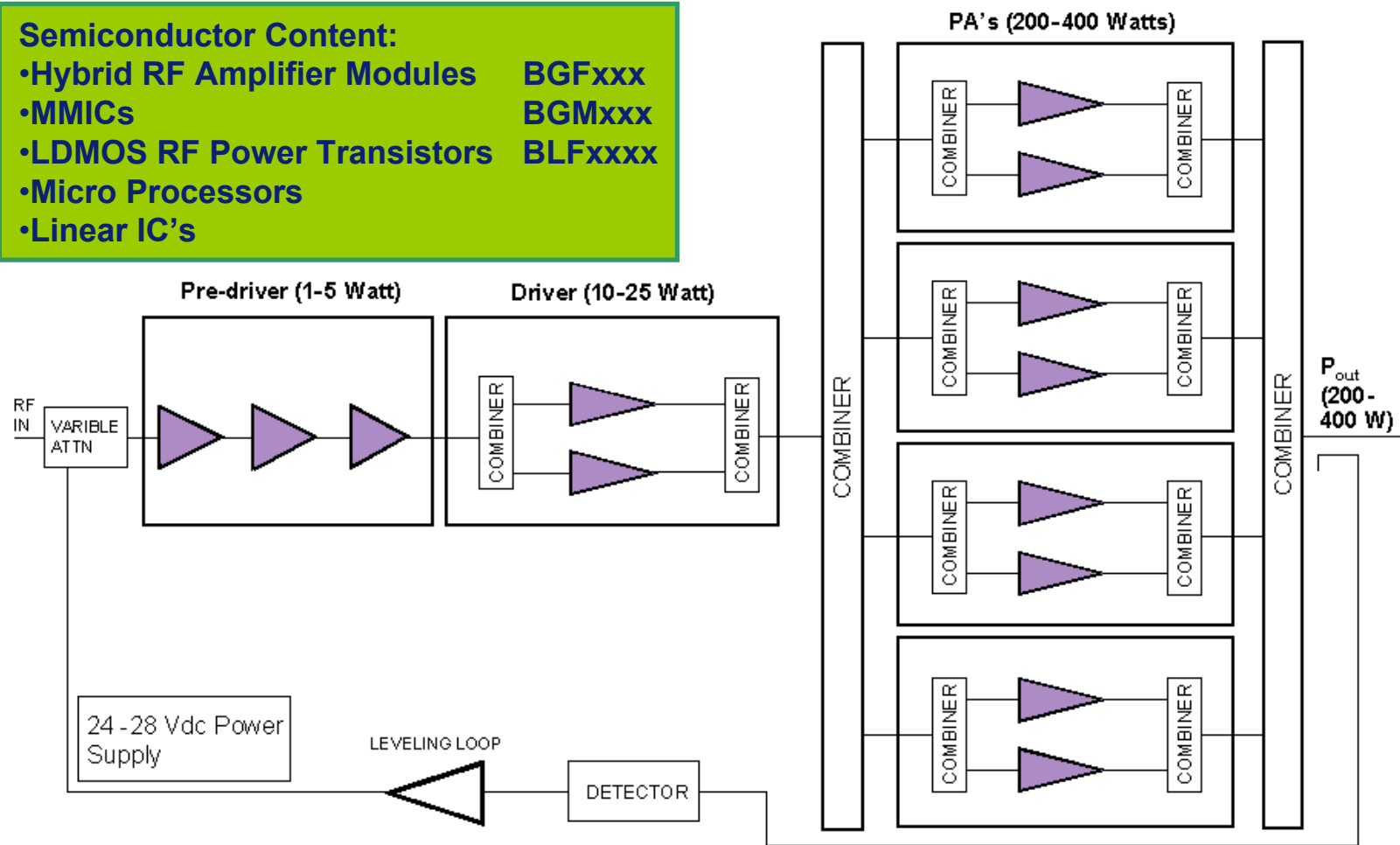
Multi carrier power amplifiers



Multi Carrier Power Amplifier (MCPA)

Semiconductor Content:

- Hybrid RF Amplifier Modules BGFxxx
- MMICs BGMxxx
- LDMOS RF Power Transistors BLFxxxx
- Micro Processors
- Linear IC's



Peak Power in an MCPA

- In multi carrier amplifiers, the maximum peak power that occurs, when all carriers are phase aligned, can be expressed as:

$$P_{peak} = P_{average (all carriers combined)} \cdot n$$

where n is the number of carriers

- For instance: In case of two 10W carriers, the average power is 20W, the peak power is 40W (i.e. 3dB above $P_{average}$ of all carriers combined and 6dB above $P_{one-carrier}$)
- The above is valid for CW carriers. For digital modulated signal, the relation is much more complex and outside the scope of this training.

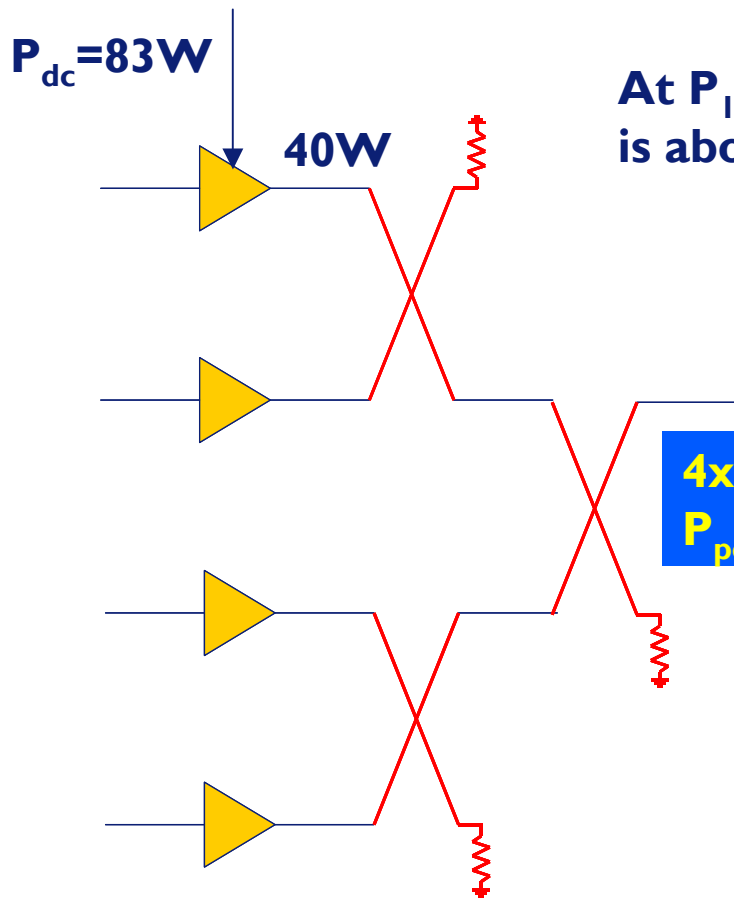
Peak Power in an MCPA

Numbers of Carriers (n) (1W each)	Average Power (Pavg)		Peak Power (Ppk = n*Pavg)		Peak-to-Average Power Contribution Ratio	
	Watts	dBm	Watts	dBm	Ratio	dB
1	1	30	1	30	1:1	0
2	2	33	4	36	2:1	3
4	4	36	16	42	4:1	6
8	8	39	64	48	8:1	9
16	16	42	256	54	16:1	12
32	32	45	1024	60	32:1	15
64	64	48	4096	66	64:1	18
128	128	51	16.4 k	72	128:1	21

Efficiency SCPA vs. MCPA

- Theoretical example
- Let's assume we have four CW carriers with an output power of 10W each at the antenna of a base station.
- We can use two configurations:
 - four SCPA, combined with 3dB hybrids
 - combine the carriers at a low level, and amplify them with an MCPA.
- We'll now calculate the overall amplifier efficiency for both.

SCPA solution with 3dB hybrids



At P_{1dB} , the drain efficiency is about 48% for a 2GHz device

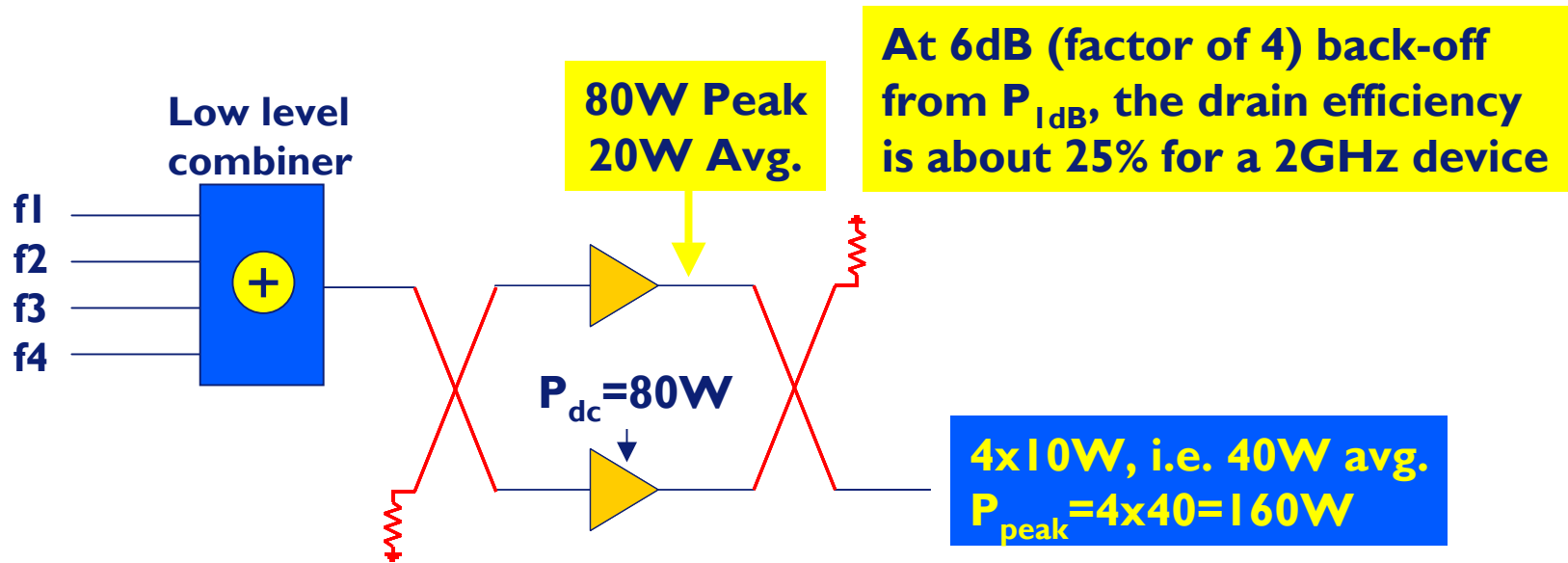
4x10W, i.e. 40W avg.
 $P_{peak} = 4 \times 40 = 160W$

Each 3dB hybrid has 3dB loss

$$\text{Total } P_{dc} = 4 \times 83W = 332W$$

$$\eta_{amplifier} = \frac{P_{rf,out}}{P_{dc}} = \frac{40}{332} = 12\%$$

MCPA solution



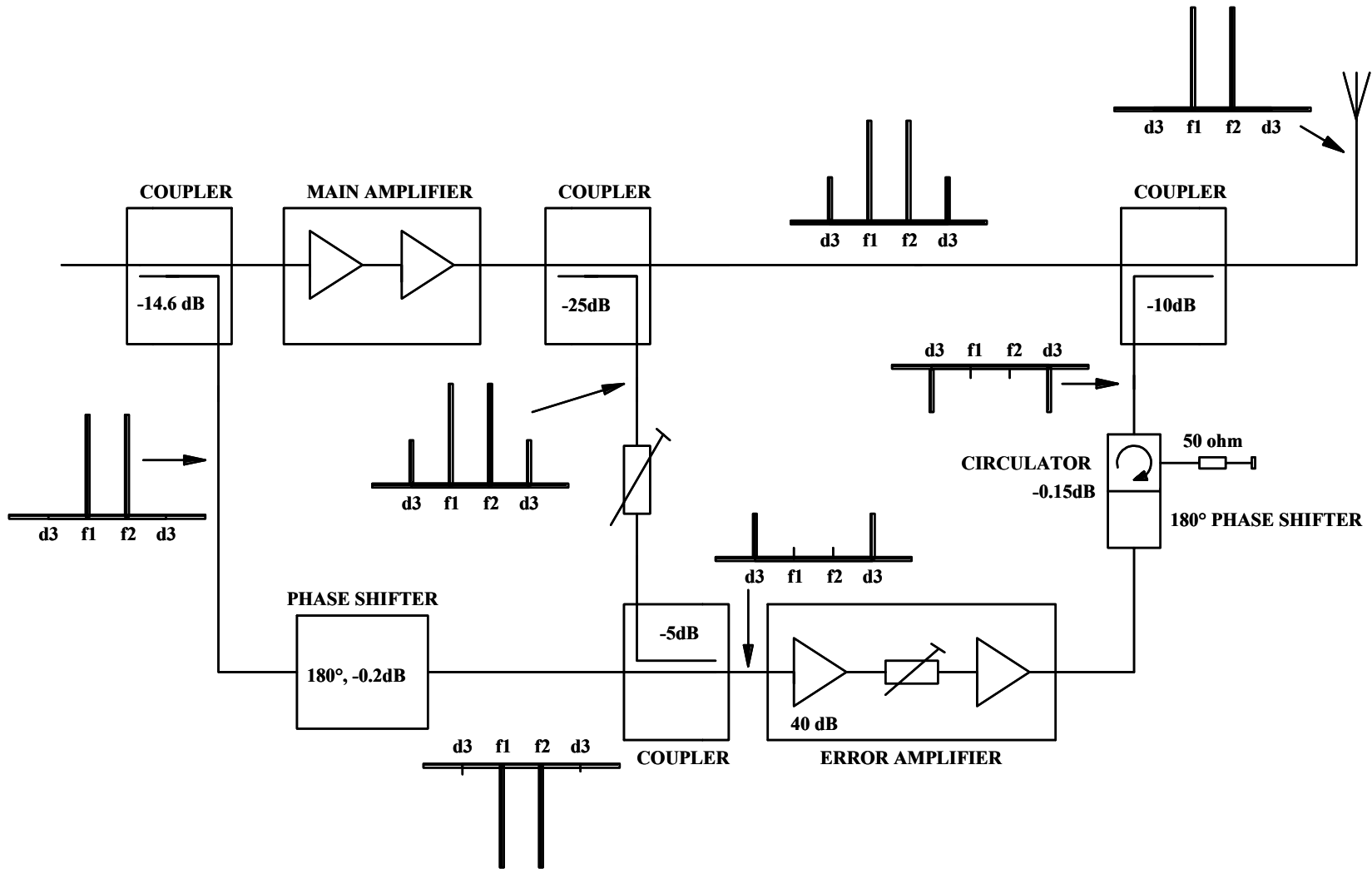
Total $P_{dc} = 2 \times 80W = 160W$

$$\eta_{amplifier} = \frac{P_{rf,out}}{P_{dc}} = \frac{40}{160} = 25\%$$

MCPA solution

- But, since we are now sending 4 carriers through an amplifier, we are generation distortion (IMD) products.
- Since we have designed the amplifier for 6dB back-off ($PAR=6dB$), the level of the IMD products will be about $-30dBc$.
- FCC requires $-60dBc$, so we need to fix this.
- This can be done with a feed-forward amplifier.

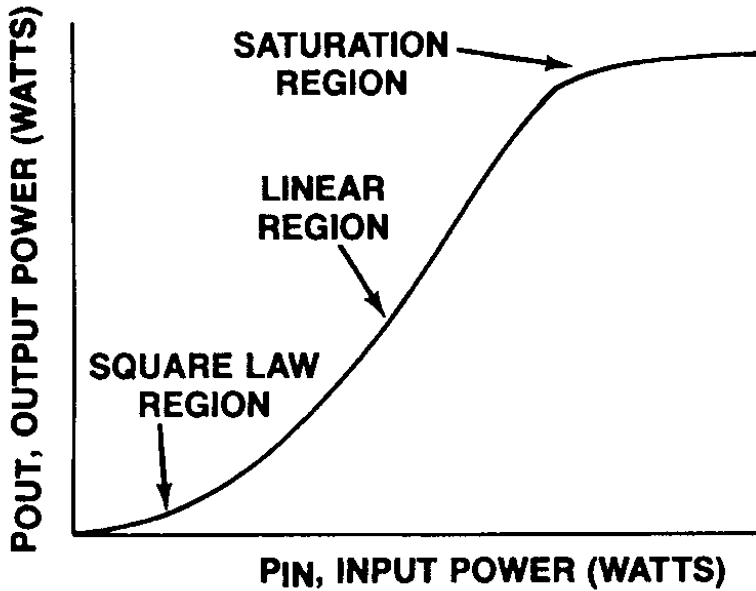
Feed Forward Principle



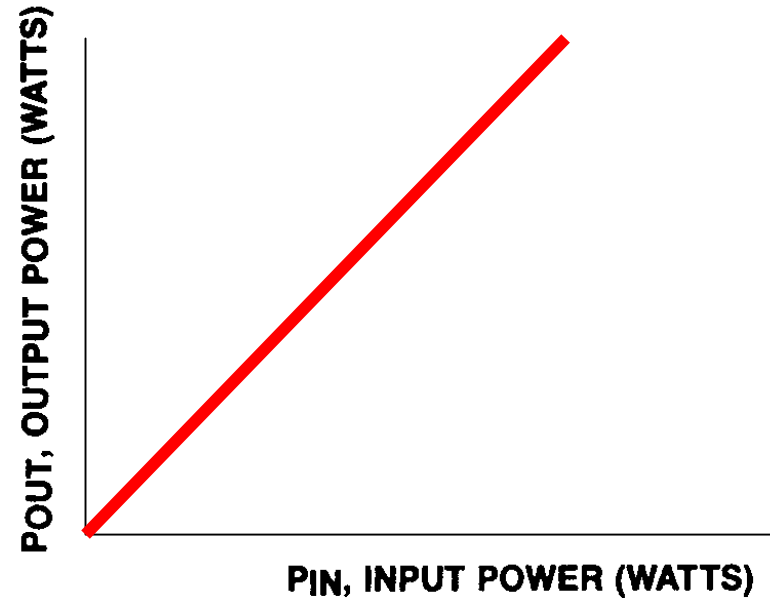
Feed Forward MCPA

- If we assume that the error amplifier consumes 40W, the overall MCPA efficiency degrades to 20%, still a significant savings.
- With a \$0.10 kWh price, the annual cost to run the:
 - SCPA \$290.83
 - MCPA \$175.20, a 40% energy savings
- Other disadvantage is the more complex MCPA design obviously.
- But, the higher MCPA efficiency also requires less cooling (smaller heatsink, less environmental noise)

Pre-Distortion

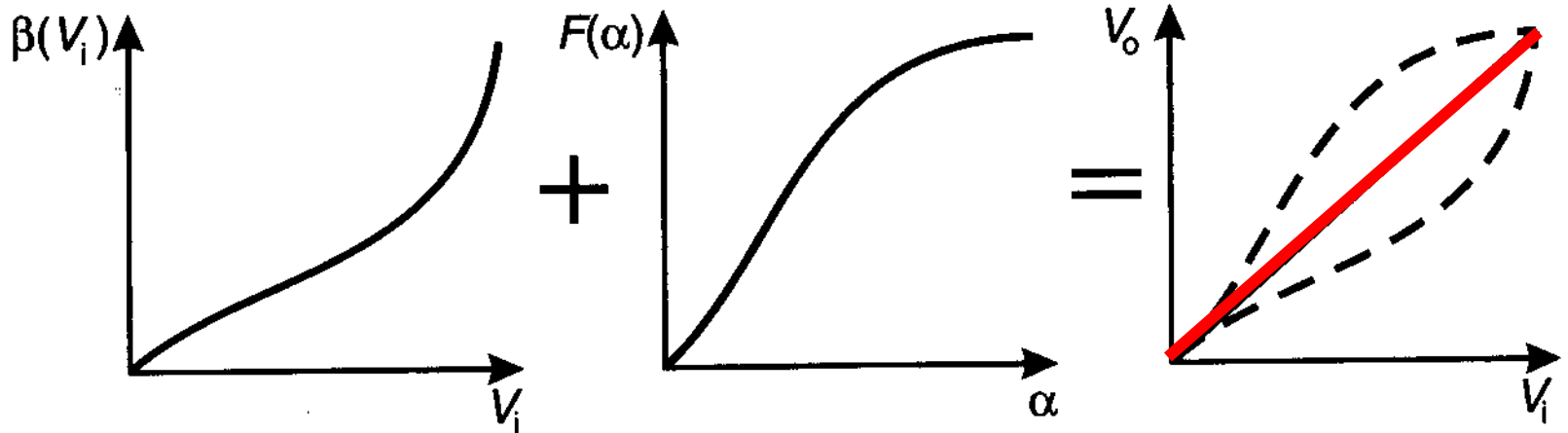
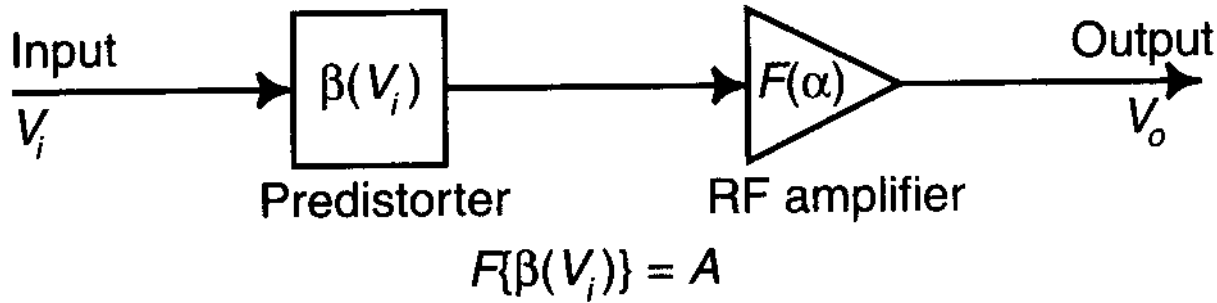


REAL

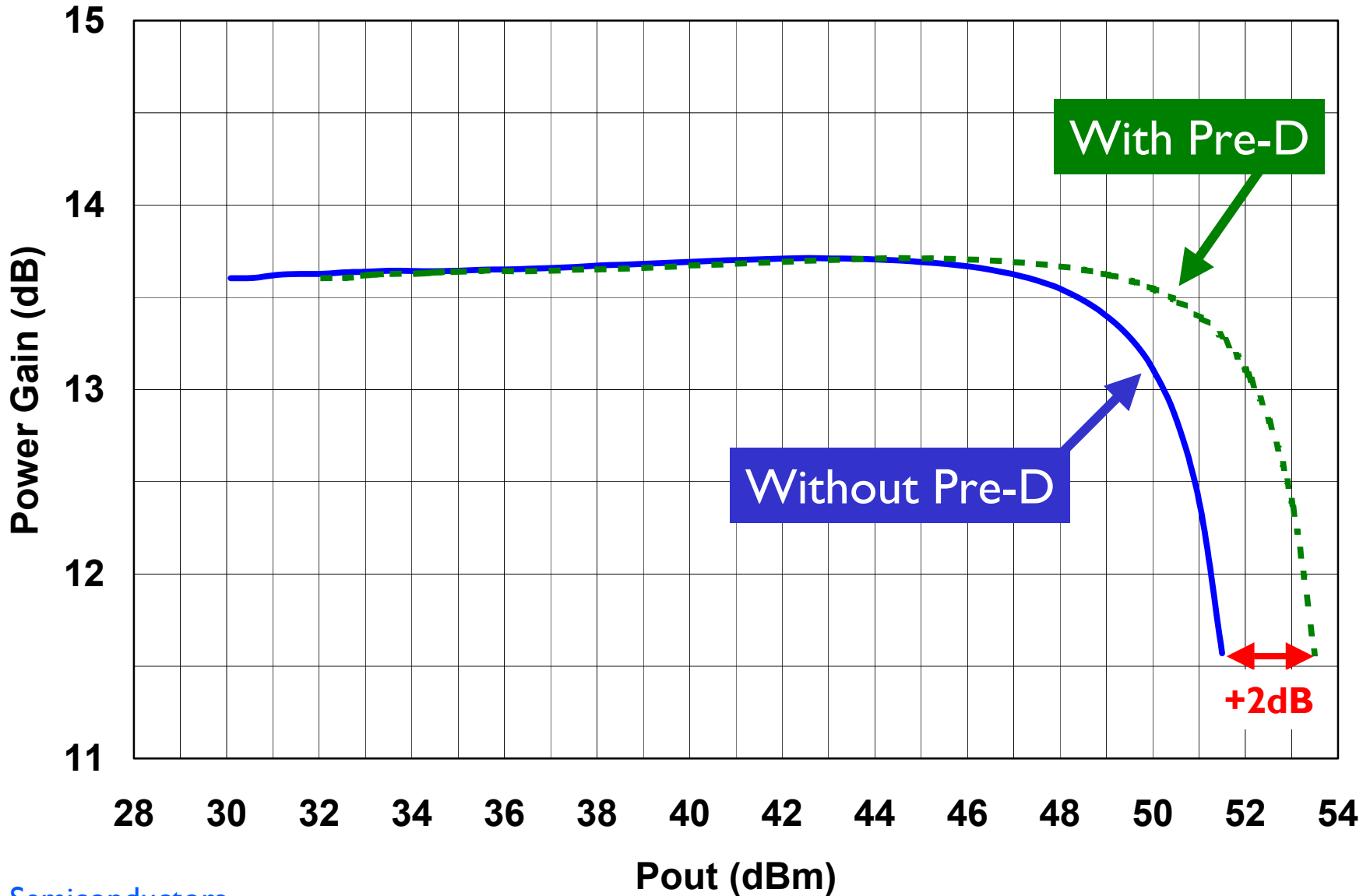


IDEAL

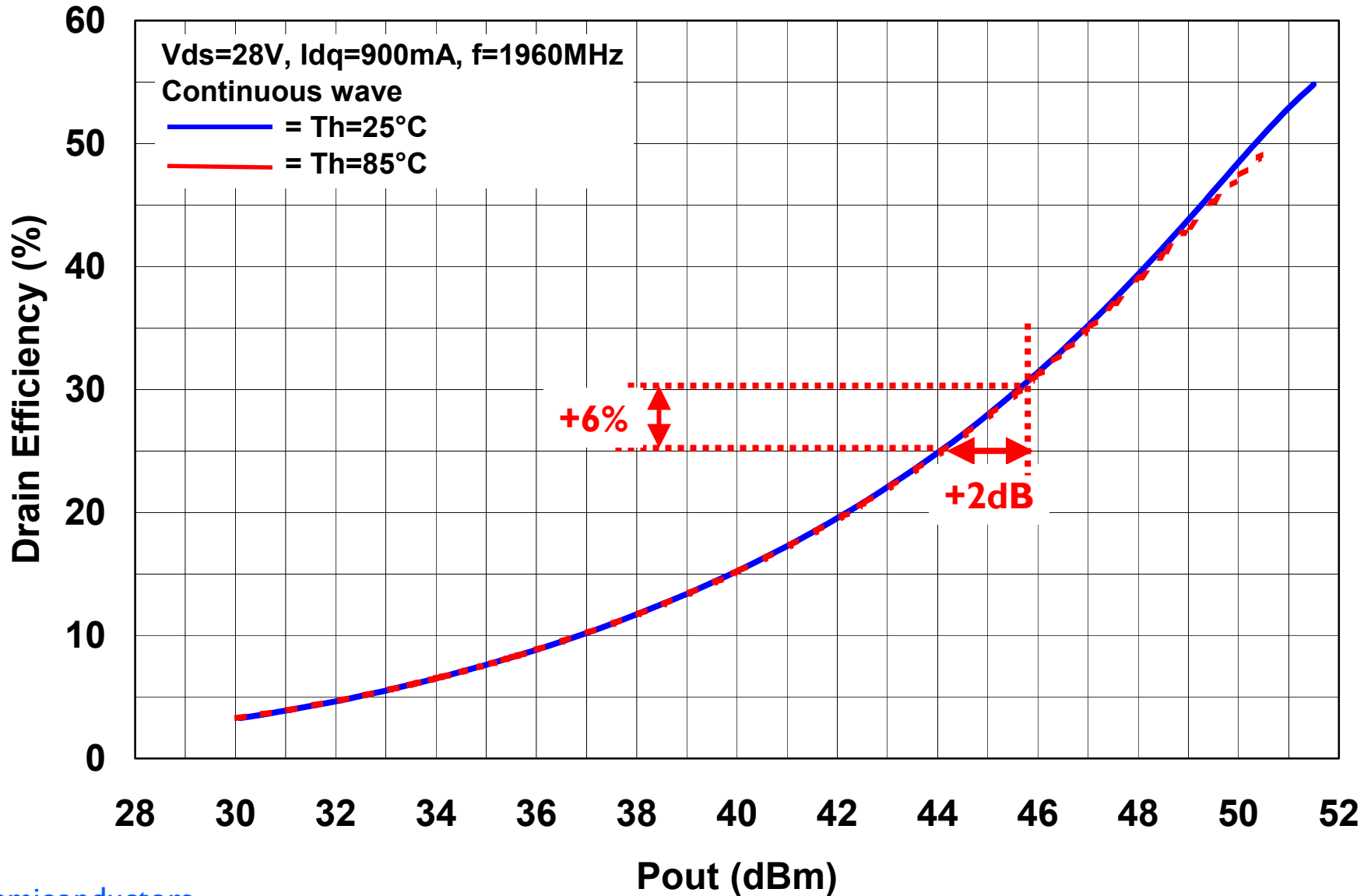
Pre-Distortion



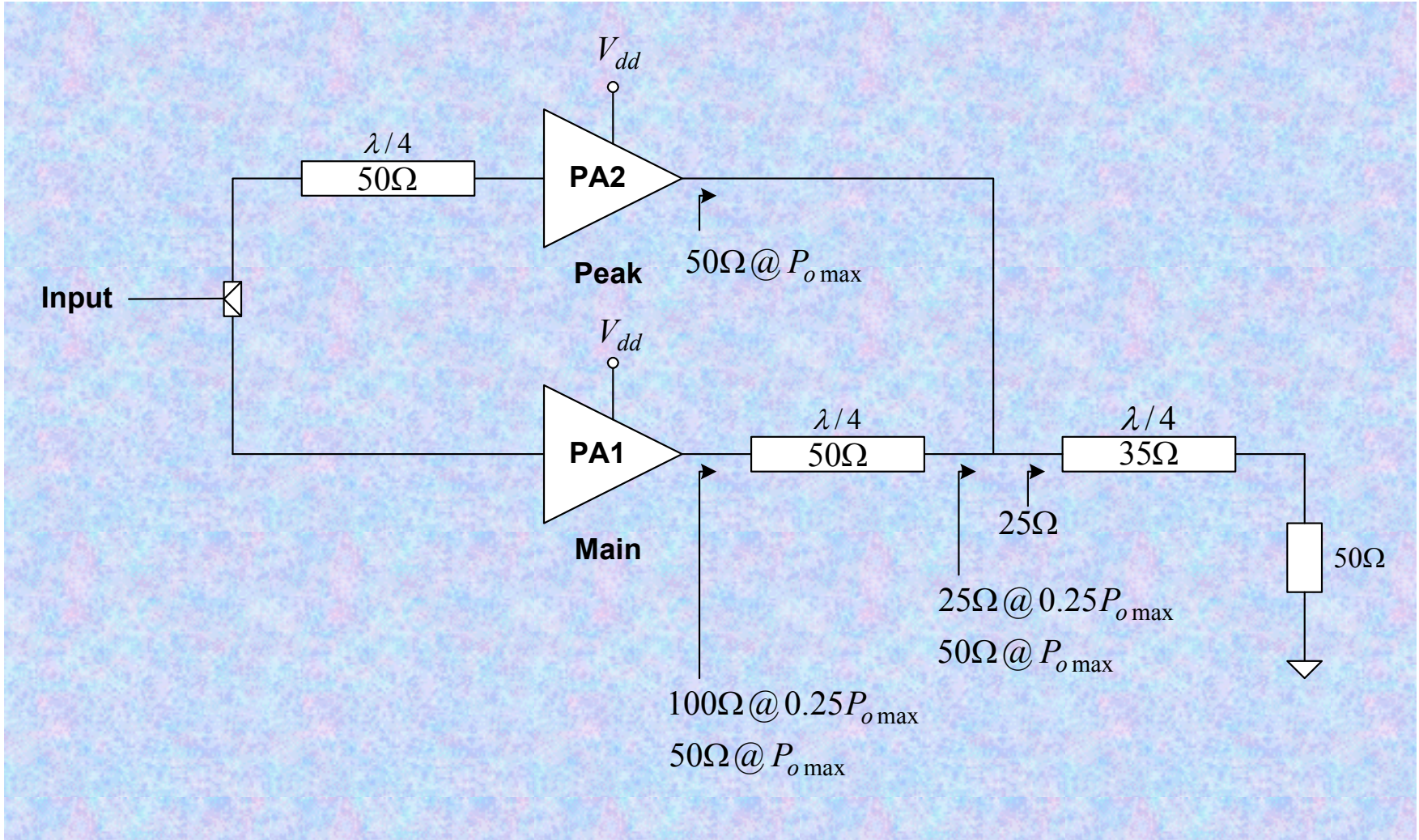
Pre-Distortion



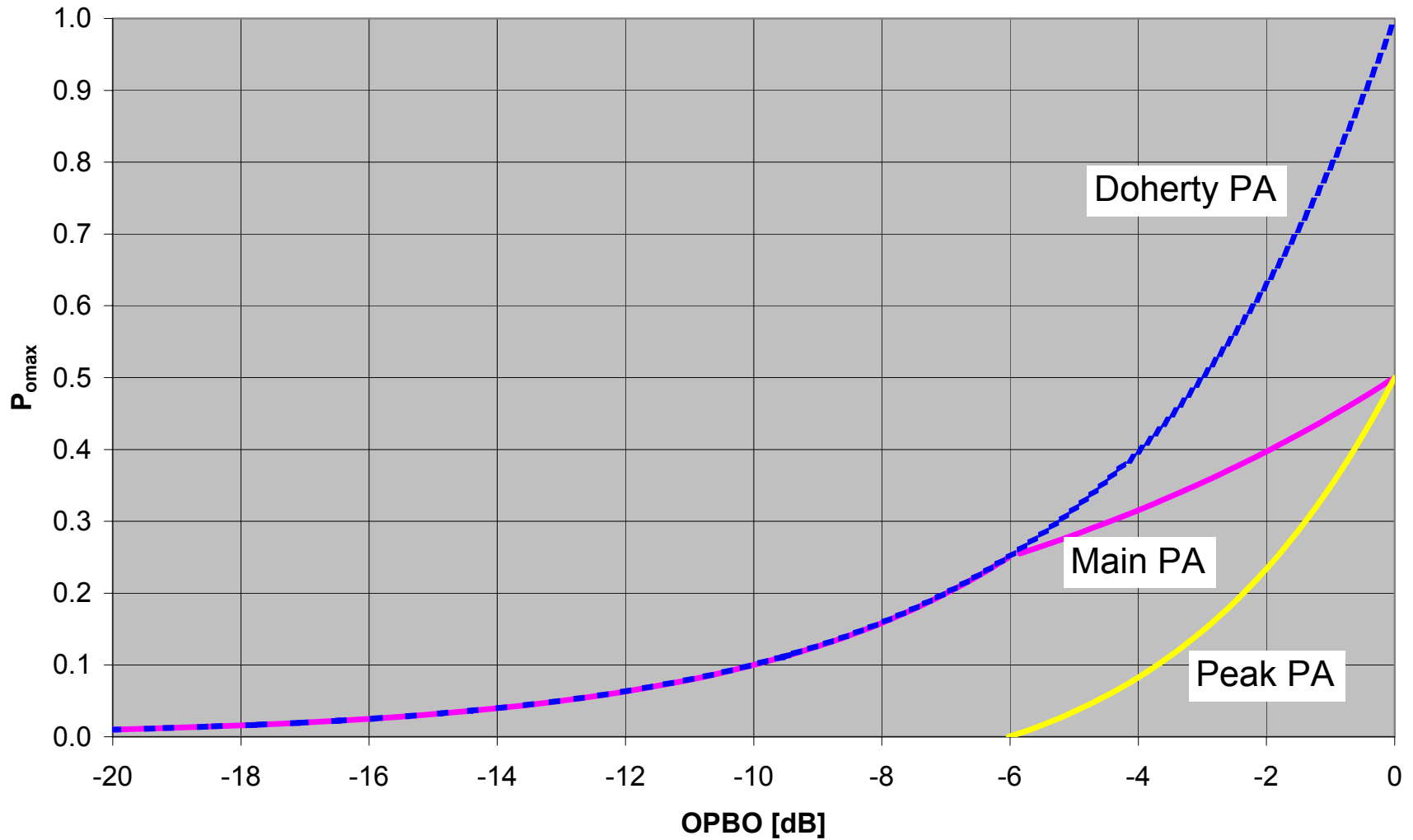
Pre-Distortion



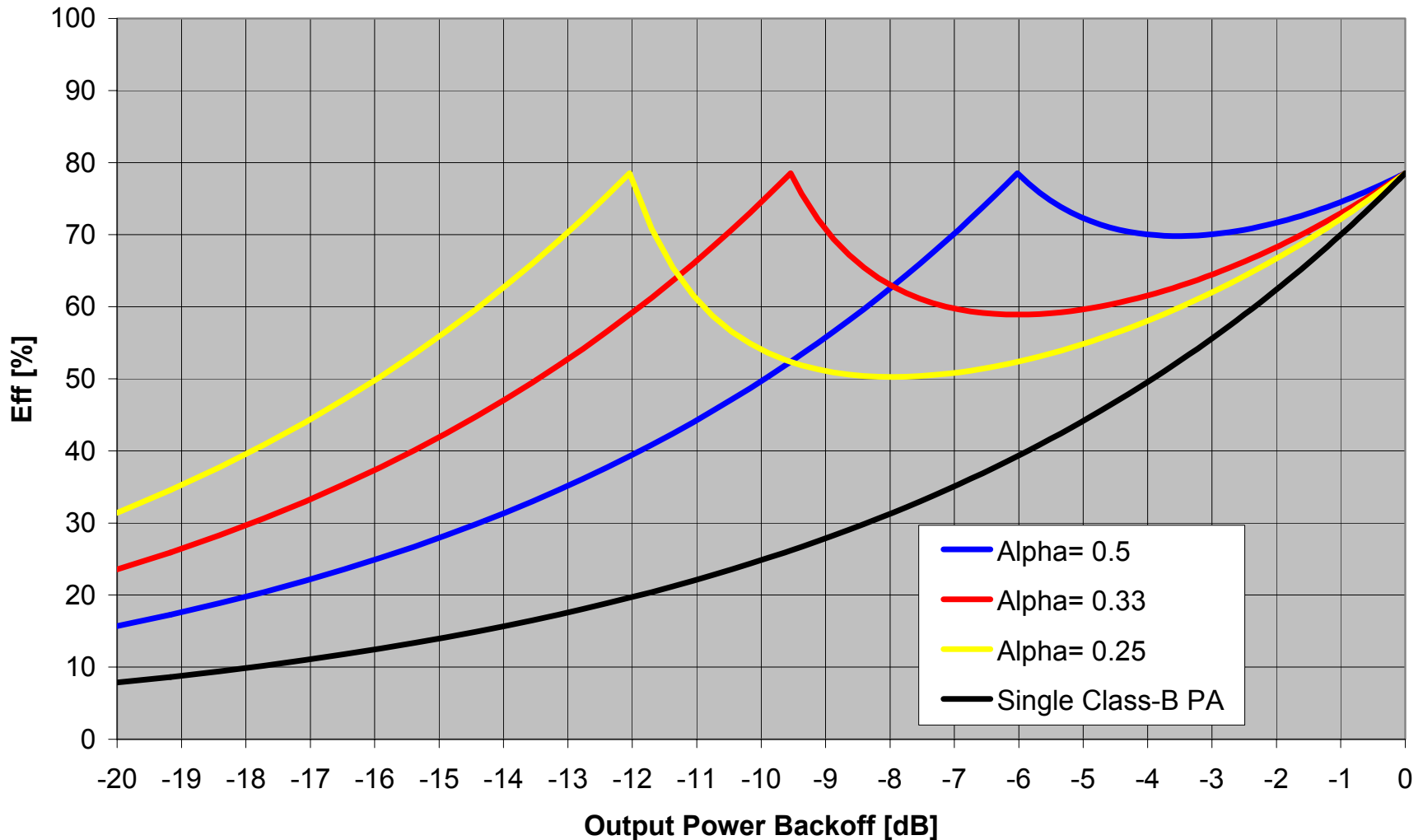
Doherty (Classical)



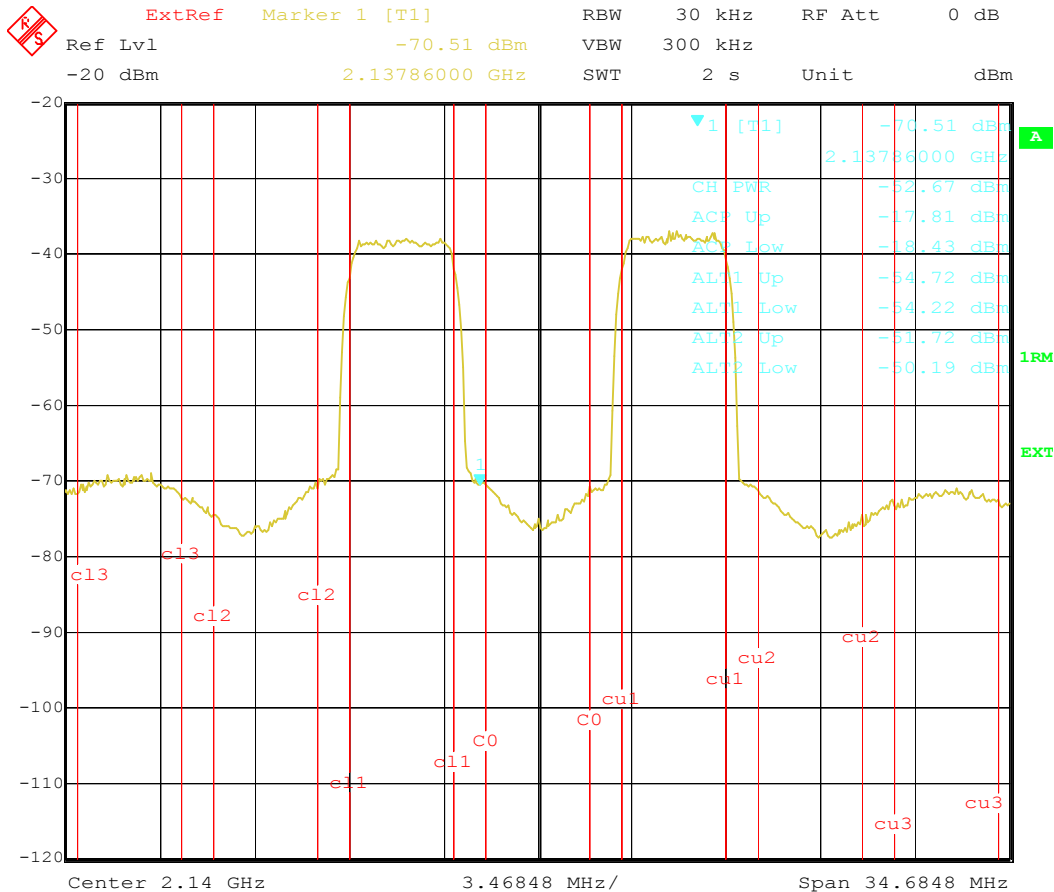
Doherty



Doherty – Theoretical Efficiency



2C-WCDMA Doherty Performance



**Vds= 28V, Idq= 825mA, Id= 5.22A,
f1= 2135MHz, f2=2145MHz**

Po-avg= 50W, Eff= 34.2%

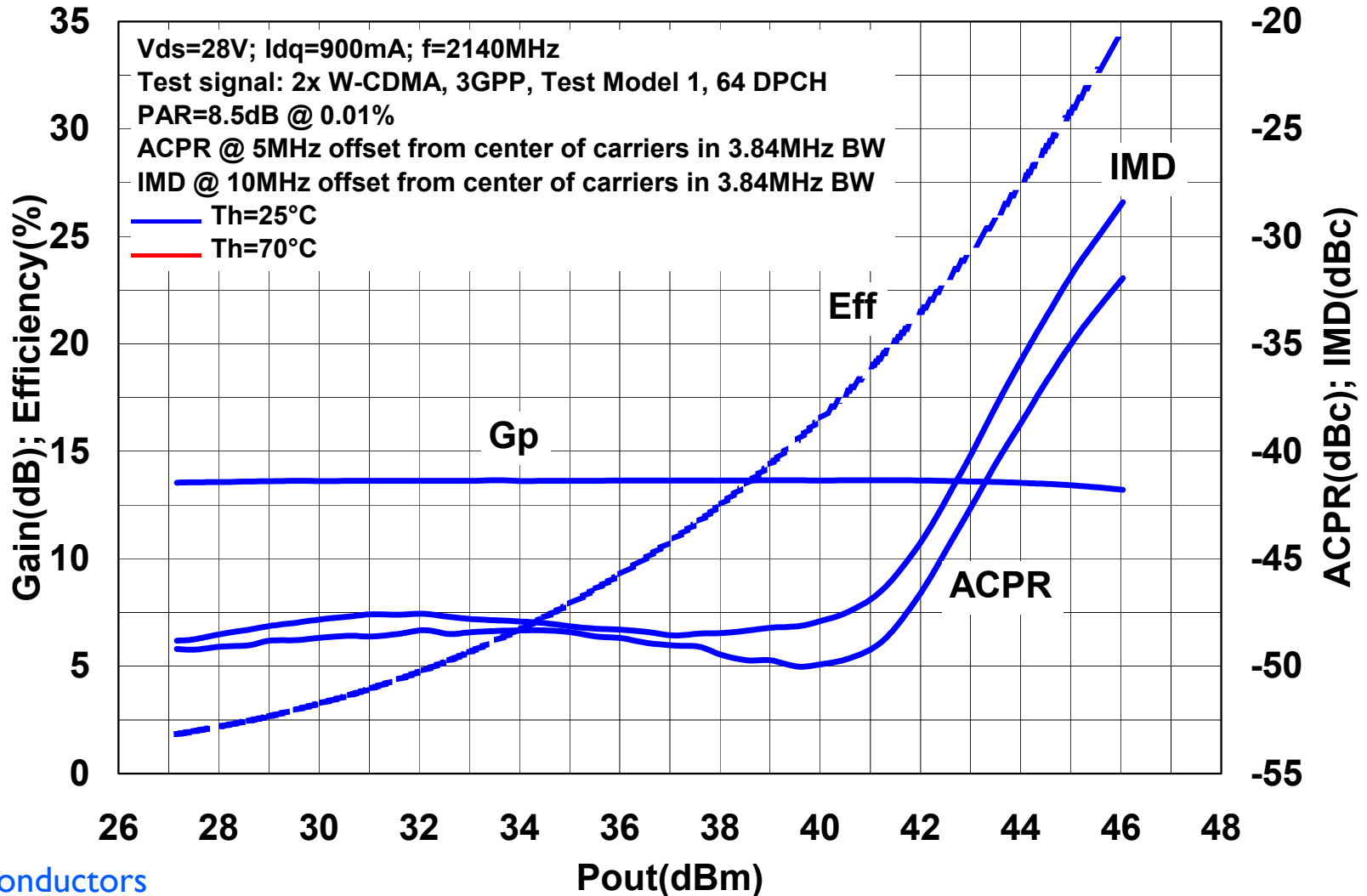
**ACLR5_up= -36.9dBc
ACLR5_low= -35.8dBc**

**IM3_up= -33.9dBc
IM3_low= -31.8dBc**

**Carrier: 3GPP Testmodel1, 64 DPCH,
46% Clipping**

Date: 17.JAN.2003 17:04:00

2C WCDMA Class-AB amplifier.



Quick comparison

Conventional vs. Doherty PA

- At 44.6dBm, one final stage has an efficiency of about 30% (@ -33dBc IMD). So at 47dBm (50W), two of these are needed.
- Total required DC power is therefore 192.3W. This translates into an efficiency of **26%** for the finals only (drivers not taken into account).
- The Doherty amplifier gives **34%**, an 8% improvement!

Conclusions

- Higher efficiency:
 - reduces required power (cost)
 - keeps the transistor cooler (reliability)
 - requires less heatsink or airflow
- Other ways to improve efficiency
 - devices with higher gain (reduces driver size)
 - devices with higher peak power capability (ability to pre-distort)
- Combinations of the amplifier concepts presented.

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PA Fundamentals

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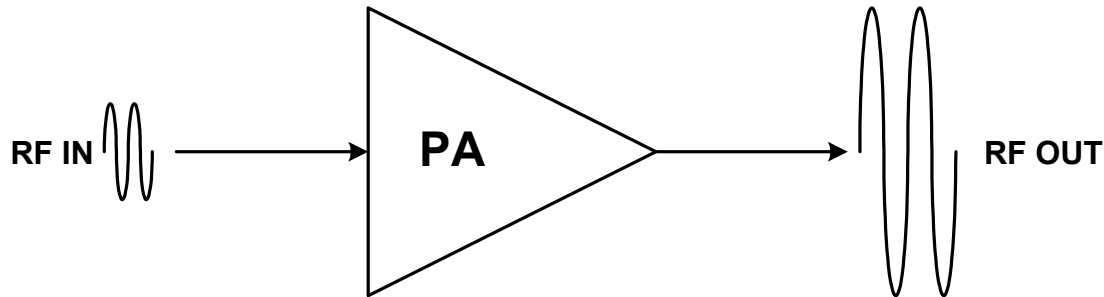
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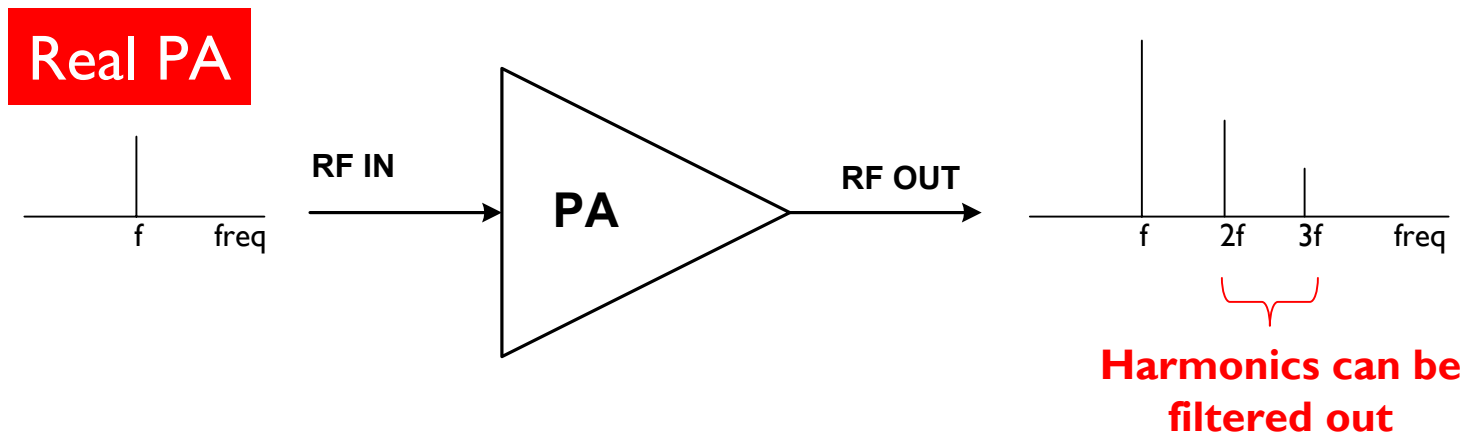
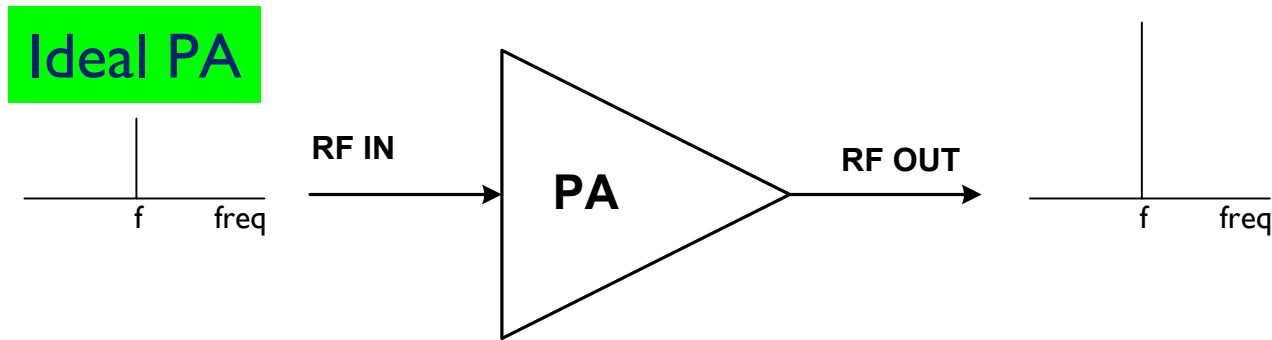
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Power Amplifier (PA)



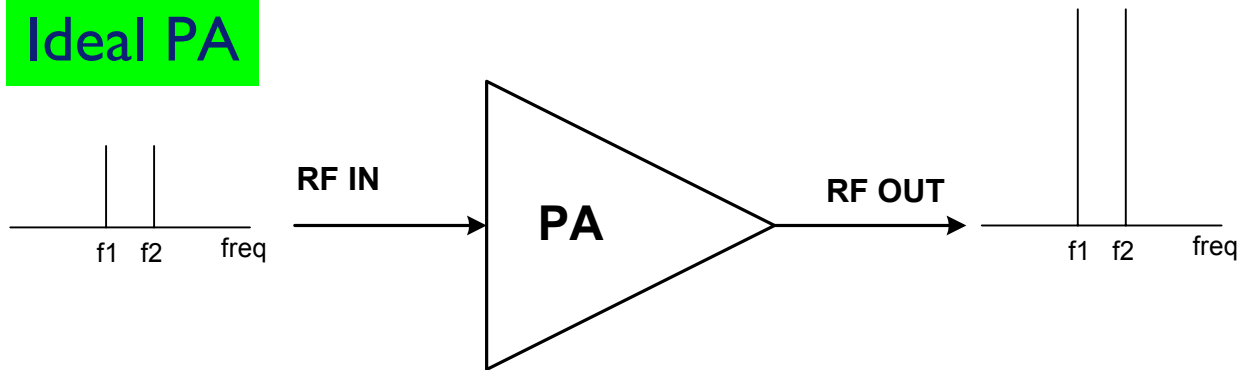
A Power Amplifier serves one fundamental function:
It amplifies the incoming signal. In an *ideal case* no distortion, noise or spurious is added by the PA

Ideal and Real PA (single carrier)

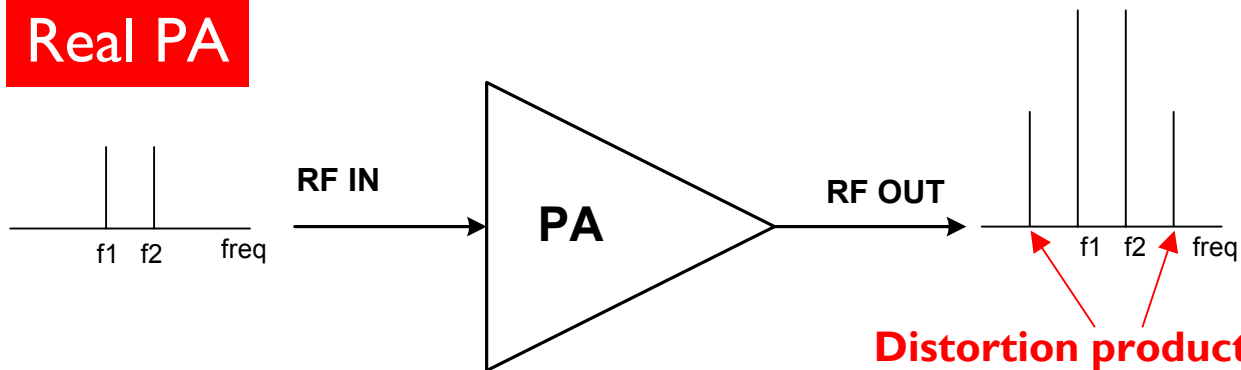


Ideal and Real PA (Multi Carrier)

Ideal PA



Real PA



**Distortion products can
not be filtered out**

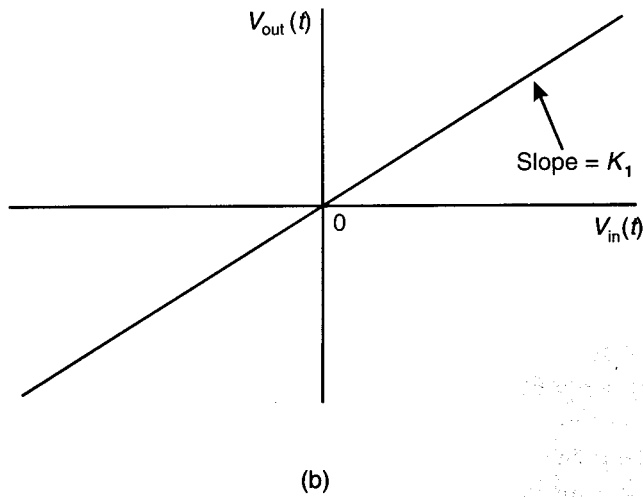
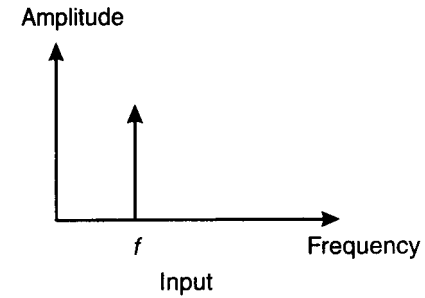
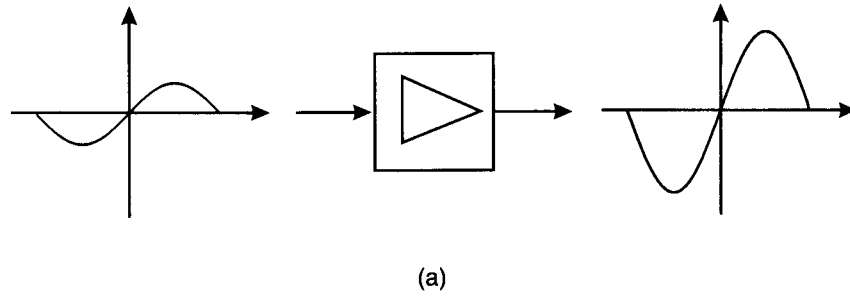
Distortion

- Multi carrier signals and every modulated signal (non constant envelope) that is amplified by a power amplifier creates distortion:
 - harmonics ($2f_0$, $3f_0$, etc.)
 - intermodulation distortion (unwanted products in close proximity to f_0)
- Constant envelope signals create harmonics, but these can be filtered out.
- Non-constant envelope signals create intermodulation distortion (IMD), and can not be filtered out.

Intermodulation Distortion (IMD)

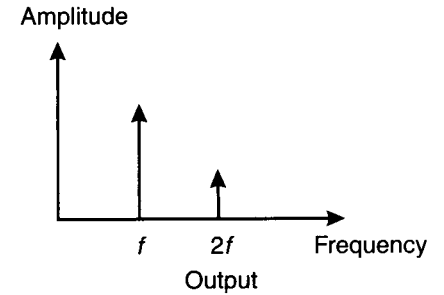
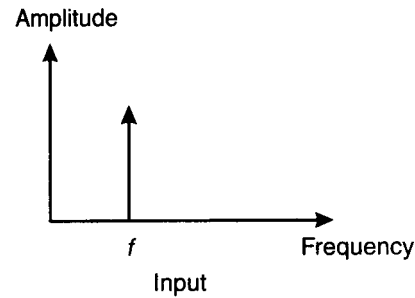
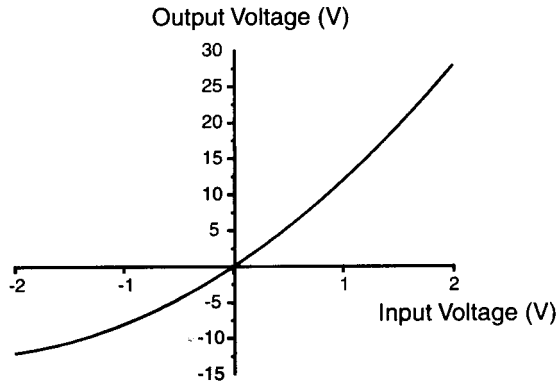
- IMD needs to be kept at a minimum to avoid interference (in neighboring channels for instance – FCC requirements).
- The amount of intermodulation distortion is determined by the power amplifier, and thus the power transistor used.
- Intermodulation is caused by non-linearity in the transfer characteristic of the RF power transistor.

The perfect amplifier

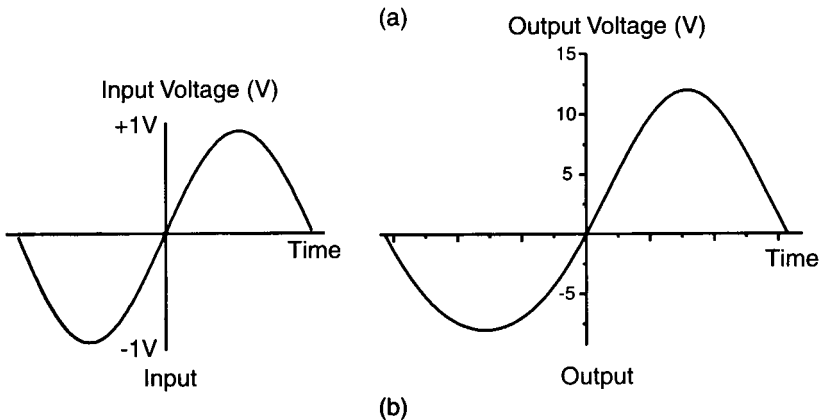


$$V_{out}(t) = K_1 \cdot V_{in}(t)$$

Square-Law Characteristic or Second Order Characteristic



(c)



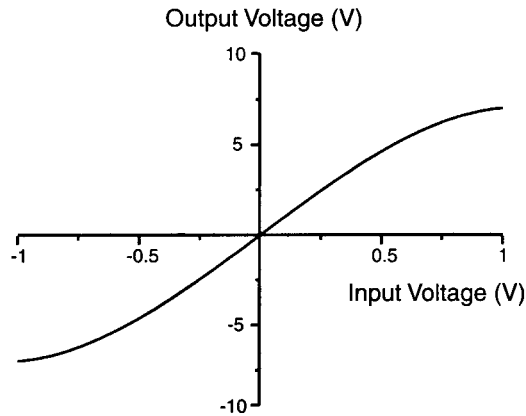
(a)

(b)

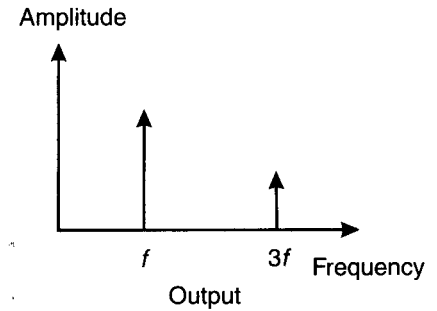
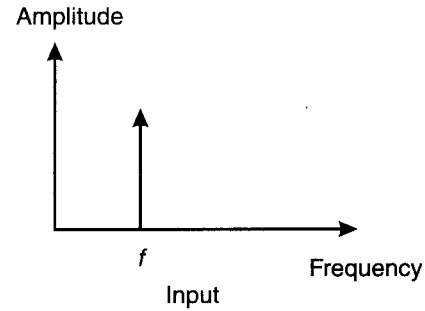
$$V_{out}(t) = K_1 \cdot V_{in}(t) + K_2 \cdot V_{in}^2(t)$$

$$K_1 = 10; K_2 = 2$$

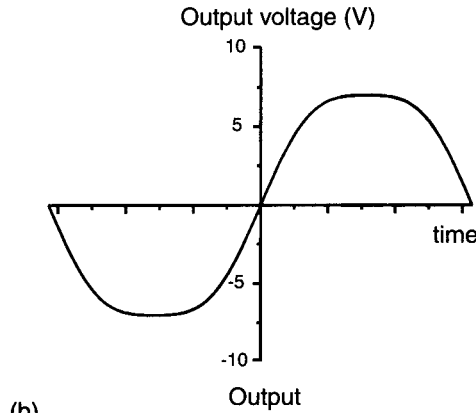
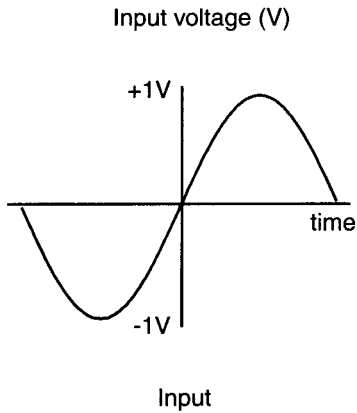
Third Order Characteristic



(a)



(c)

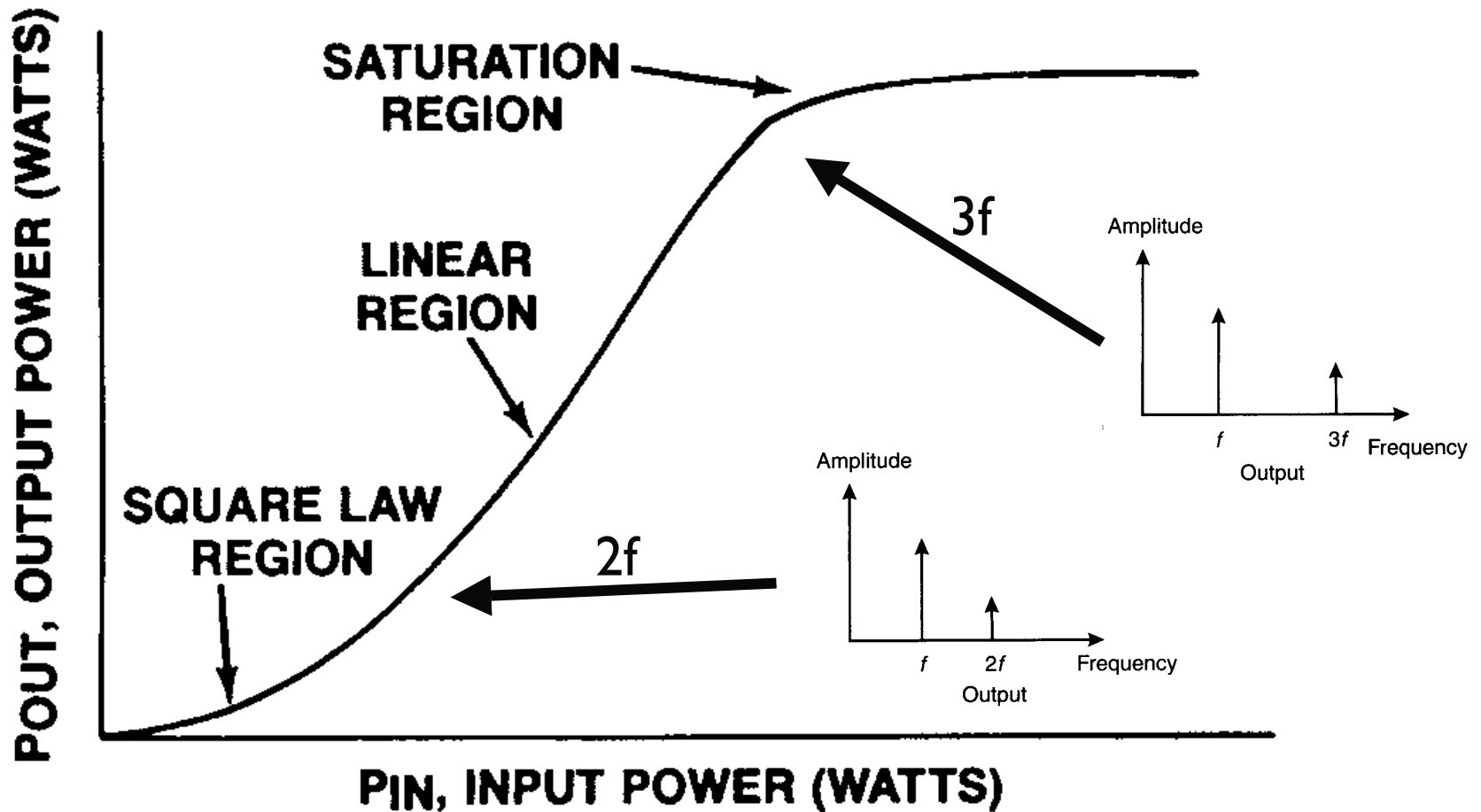


(b)

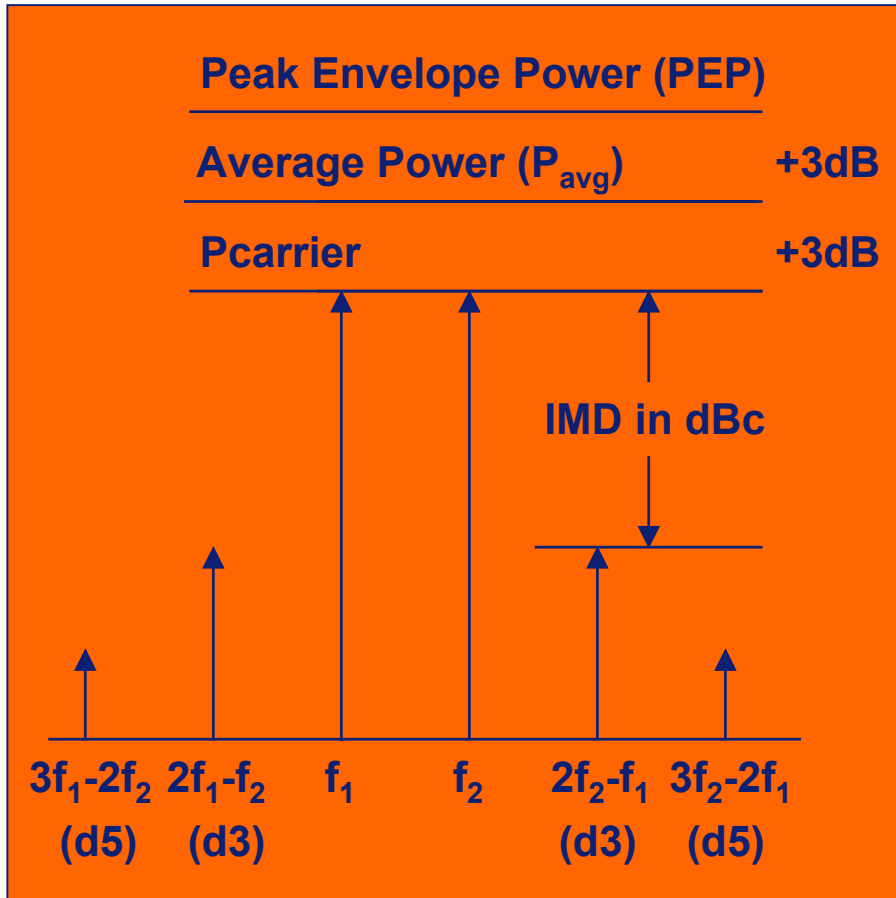
$$V_{out}(t) = K_1 \cdot V_{in}(t) + K_3 \cdot V_{in}^3(t)$$

$$K_1 = 10; K_3 = -3$$

The complete transfer characteristic



Intermodulation Distortion Products

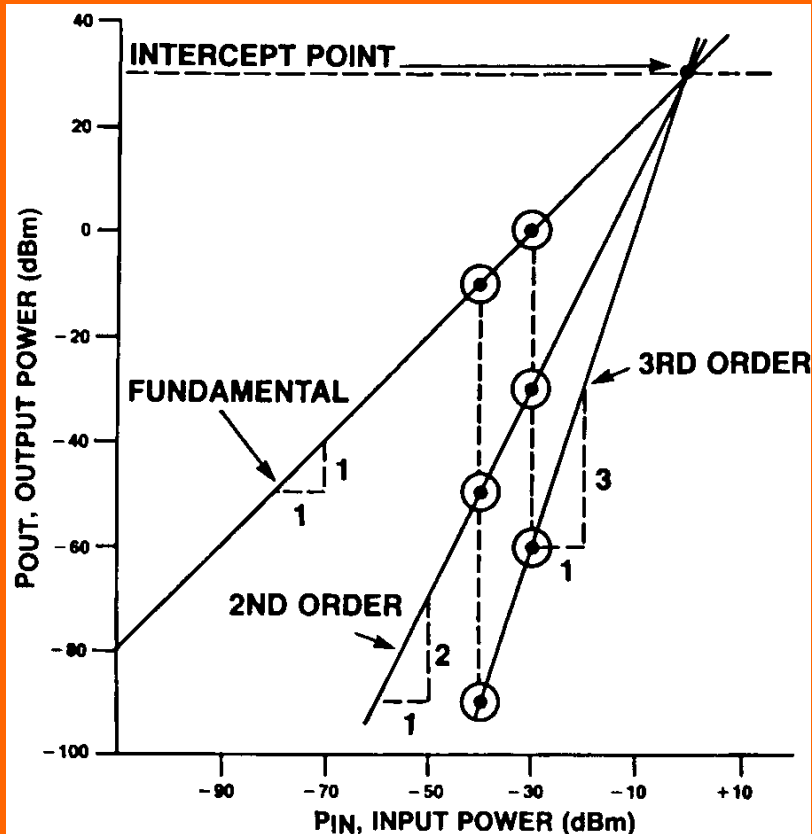


f_x = fundamental
 $2f_x$ = second harmonic (square law)
 $3f_x$ = third harmonic (third order)

d3 = third order IMD product
 d5 = fifth order IMD product

IMD is expressed in “dBc”, which means relative to one of the two carriers f_1 or f_2

Intercept Points



Intercept points are THEORETICAL power levels that are a measure for the linearity of an amplifier (transistor)

ITO2 (2nd order intercept) is the point where fundamental and 2nd order line (2:1 slope) meet

ITO3 (3rd order intercept) is the point where fundamental and 3rd order line (3:1 slope) meet

$$\text{ITO3 (dBm)} = \text{Pout (dBm)} + 1/2 \text{ IMD3 (dBc)}$$

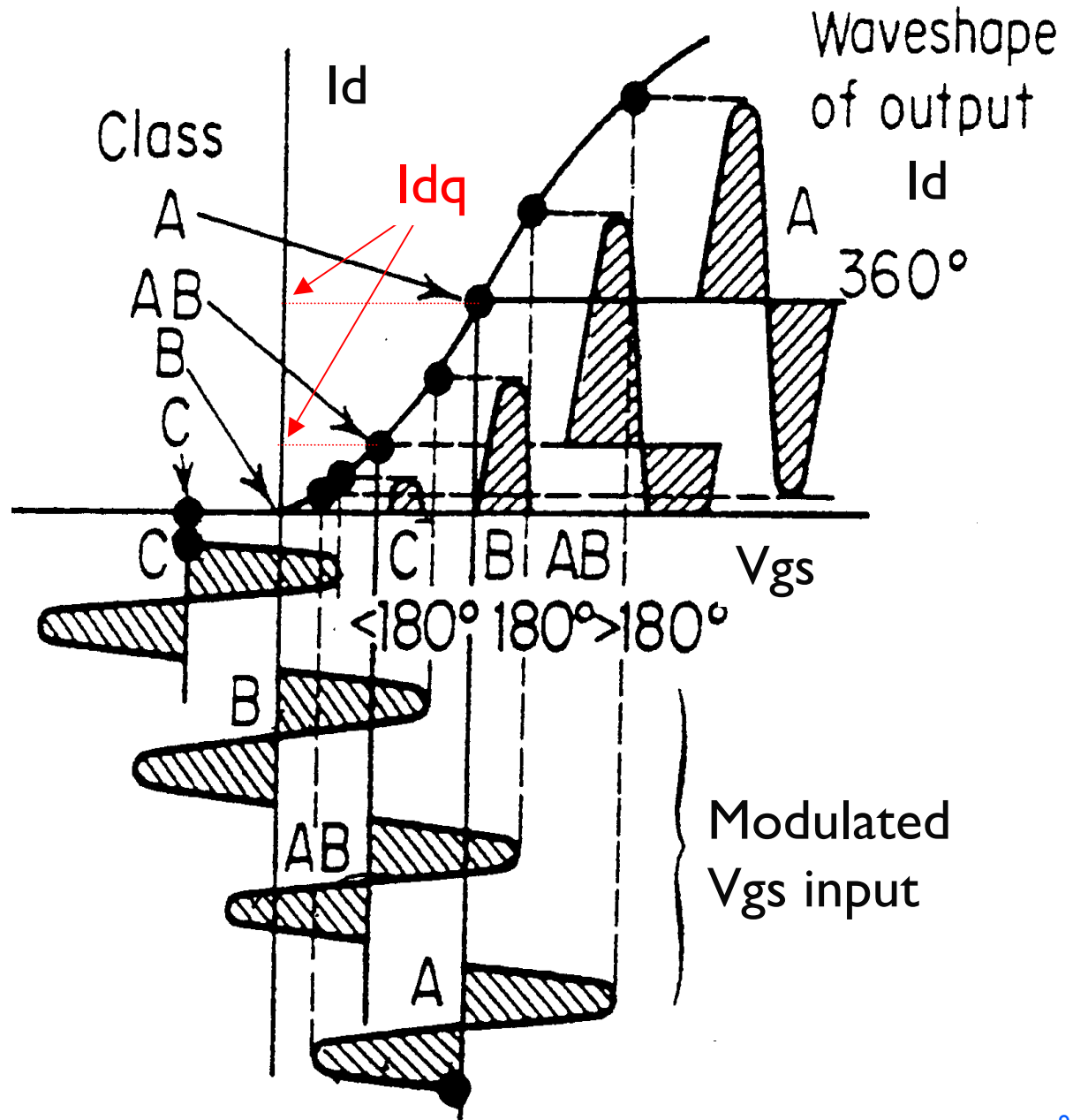
How to improve linearity

- Use a linear transistor technology such as LDMOS
- Adjust the class of operation of the PA (class A, class AB, etc)
- Use a feed-forward amplifier
- Use (digital) pre distortion (DPD)

Classes of Operation

- Class-A
- Class-AB
- Class-B
- Class-C
- Class-D,E,F,G,H

The class of operation is defined by the conduction angle, i.e. the time the transistor conducts current



Overview classes of operation

• Class A

- Ultra Linear Amplifier
- Extremely High Power Gain
- Low Efficiency (50% max)
- Conduction Angle 360°

• Class B

- Non-Linear Amplifier
- Low Power Gain
- High Efficiency (78.5%)
- Conduction Angle 180°

• Class AB

- Linear Amplifier
- High Power Gain
- Medium Efficiency (50-78.5%)
- Conduction Angle $180-360^\circ$

• Class C

- Extremely Non-Linear Amplifier
- Extremely Low Power Gain
- Extremely High Efficiency (90%)
- Conduction Angle $<180^\circ$

RF Power

- Can be expressed in **Watts** or **dBm**
- **0dBm = 1mW in 50Ω**


- | | | |
|-------|-------------|----------------------------|
| • 1GW | (Gigawatt) | • 1×10^9 Watt |
| • 1MW | (Megawatt) | • 1×10^6 Watt |
| • 1kW | (kilowatt) | • 1×10^3 Watt |
| • 1W | (Watt) | • 1×10^0 Watt |
| • 1mW | (milliwatt) | • 1×10^{-3} Watt |
| • 1μW | (microwatt) | • 1×10^{-6} Watt |
| • 1nW | (nanowatt) | • 1×10^{-9} Watt |
| • 1pW | (picowatt) | • 1×10^{-12} Watt |

Conversion between Watts and dBm

$$P_{out} [Watts] = \frac{10^{\frac{P_{out} [dBm]}{10}}}{1000}$$

dBm  Watts

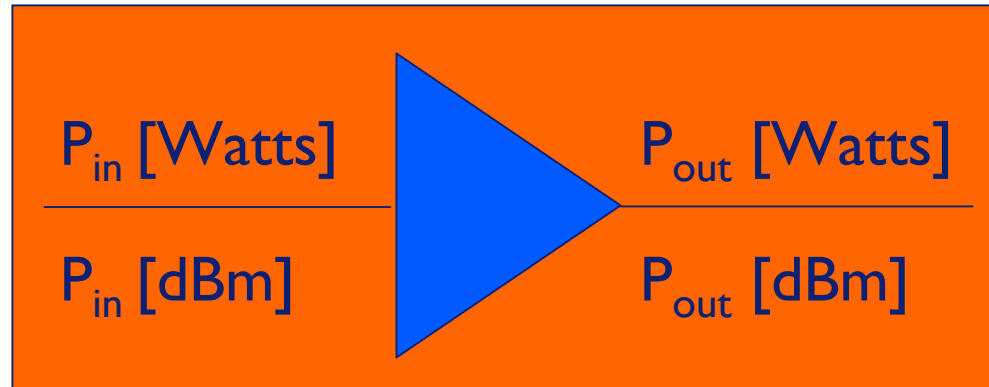
$$P_{out} [dBm] = 10 \log \frac{P_{out} [Watts]}{0.001}$$

Watts  dBm

Examples:

- 0 dBm = 1mW
- 20 dBm = 100mW
- 43 dBm = 20W
- 100W = 50dBm

Power Gain



$$G_p [dB] = 10 \log \frac{P_{out} [Watts]}{P_{in} [Watts]}$$

or

$$G_p [dB] = P_{out} [dBm] - P_{in} [dBm]$$

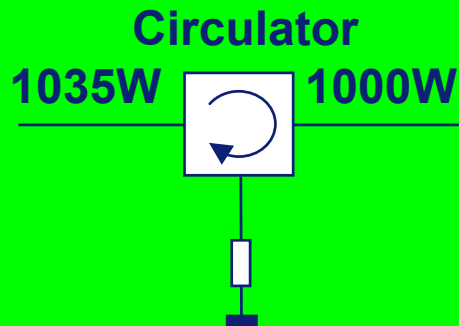
Power Gain Conversions / Insertion Loss

$$P_{in} = \frac{P_{out} [in\ Watts]}{10^{\frac{G_p [in\ dB]}{10}}} [in\ Watts]$$

$$P_{out} [Watts] = P_{in} [Watts] \cdot 10^{\frac{G_p [dB]}{10}}$$

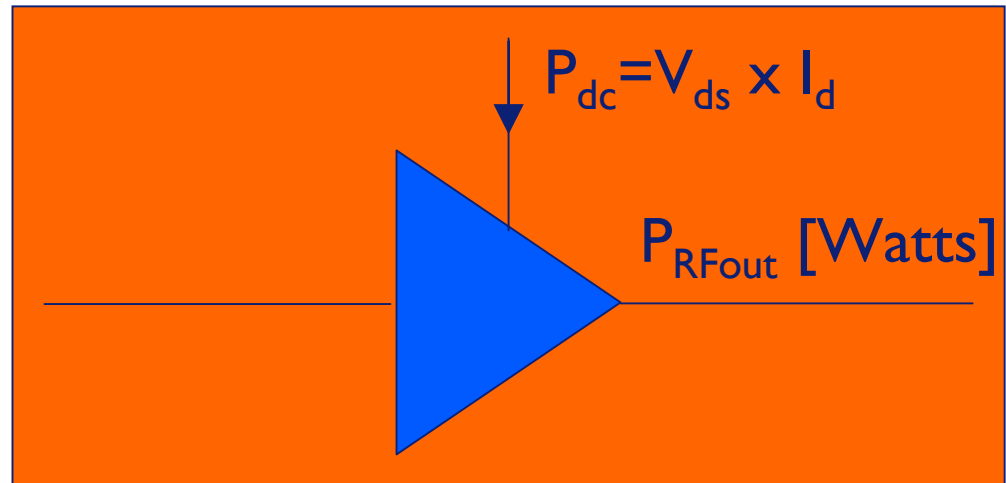
- Insertion loss is **negative** power gain (loss), i.e. P_{out} is lower than P_{in}

Example:



$$G_p = 10 \log \frac{1000}{1035} = -0.15\text{dB}$$

Efficiency



- Efficiency (often referred to as **drain efficiency**) is the ratio between RF output power and DC input power.

$$\eta_D [\%] = \frac{P_{RFout} [Watts]}{P_{dc} [Watts]} \cdot 100 = \frac{P_{RFout} [Watts]}{V_{ds} [V] \cdot I_d [A]} \cdot 100$$

Example:

$$\left. \begin{array}{l} V_{ds} = 50V, \\ I_d = 8.8A, \\ P_{RFout} = 277W \end{array} \right\} \eta_D = \frac{277W}{50V \cdot 8.8A} \cdot 100 = 63\%$$

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Digital Modulation Characterization

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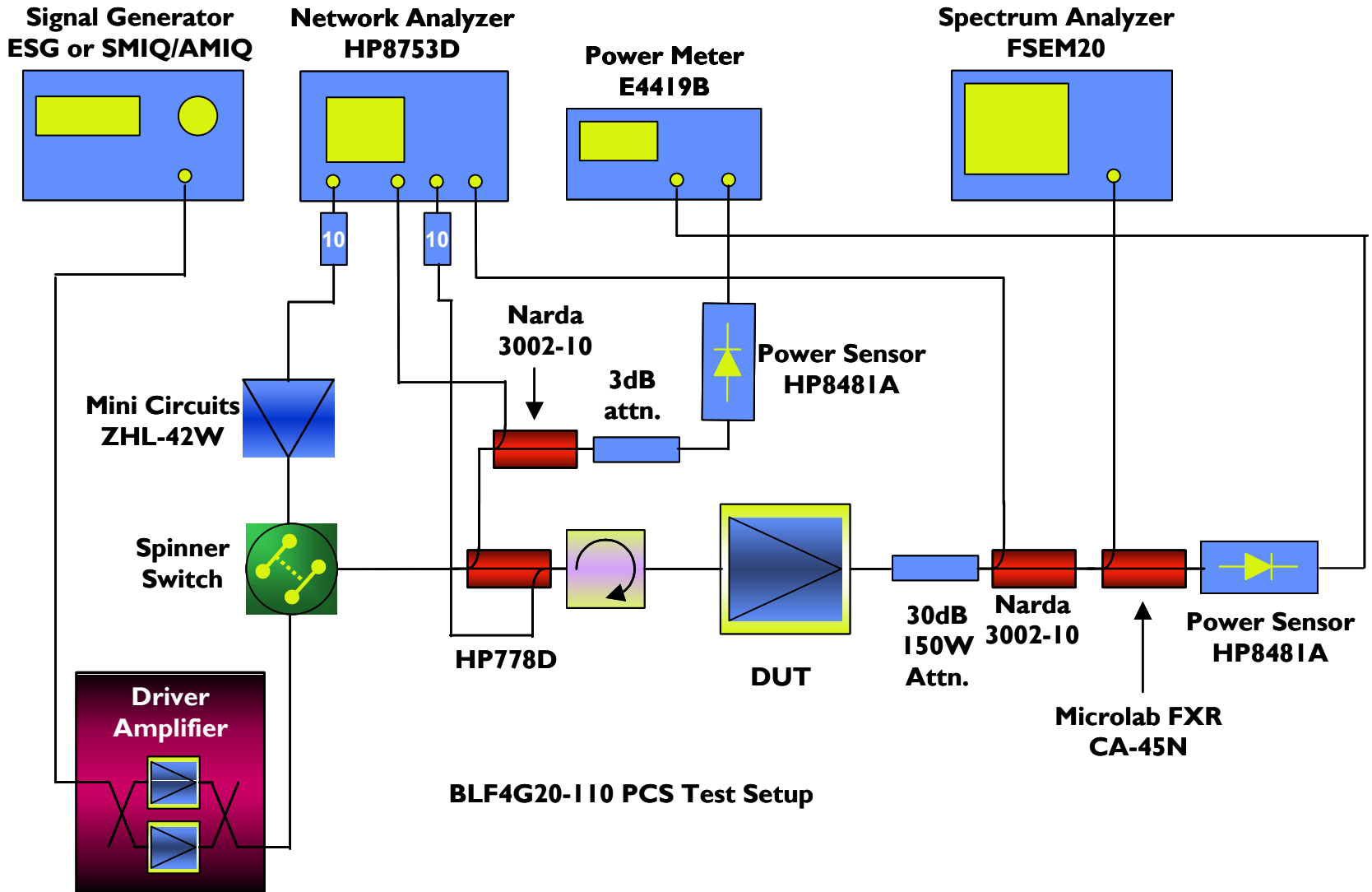
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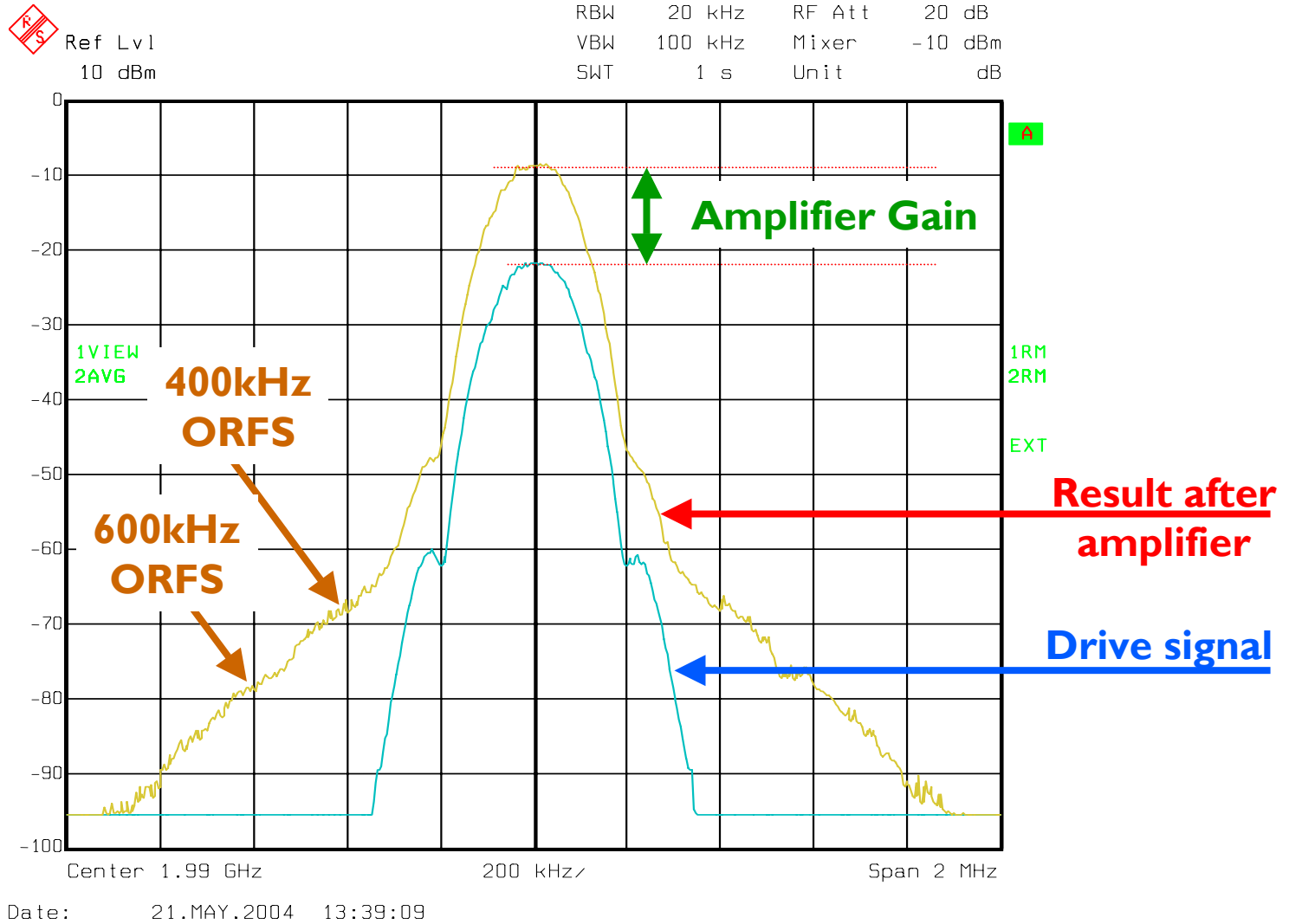
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Typical RF Power Test Setup

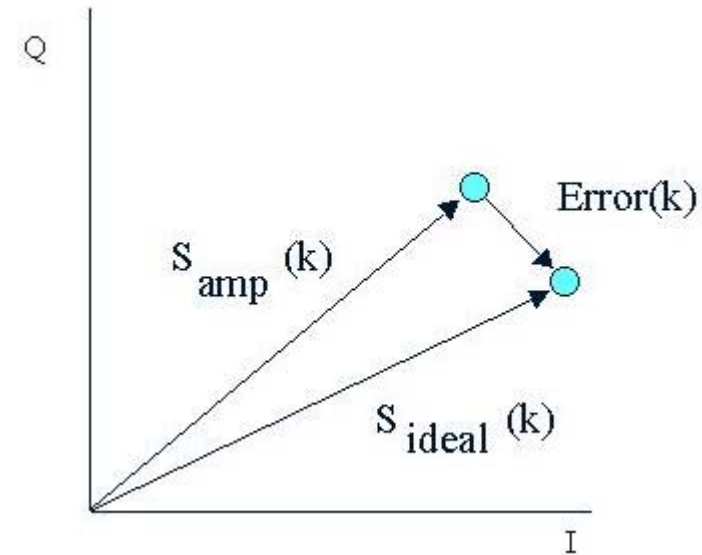


Edge GSM

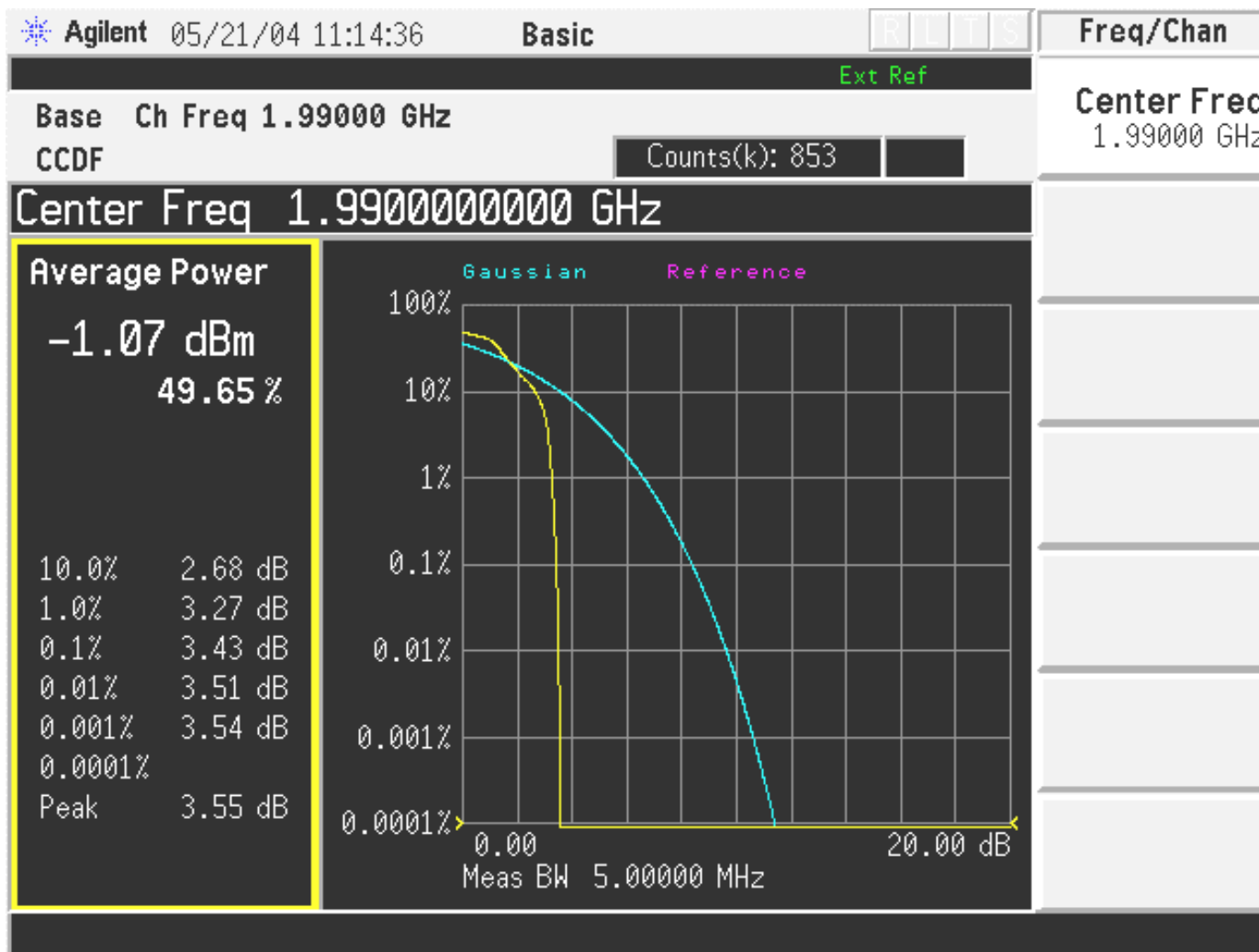


Edge GSM Characterization

- Modulation: 8-PSK
- PAR=3.2-3.5dB
- Linearity:
 - EVM (Error Vector Magnitude)[%]
 - ORFS (Output RF spectrum)[dBc]
 - at offsets with 200kHz increments.
 - 400kHz and 600kHz are most critical ones

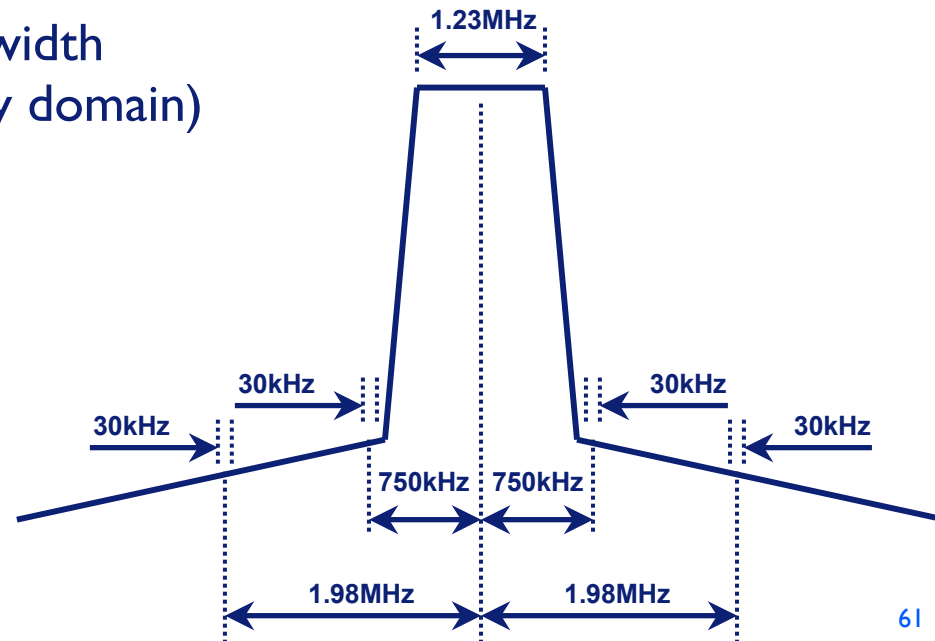


Edge GSM PAR

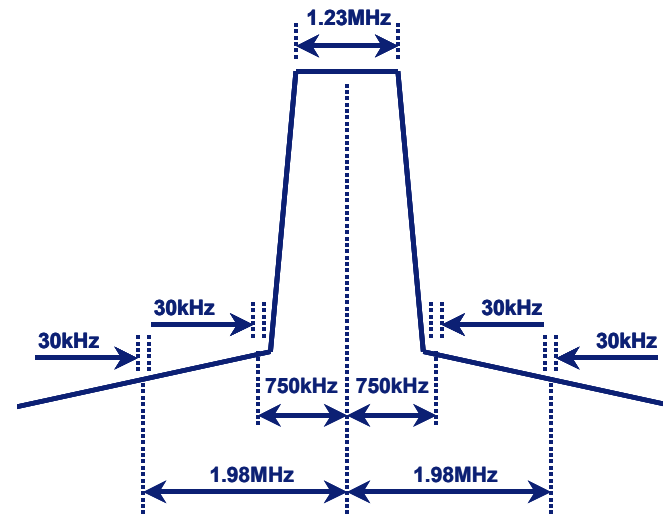
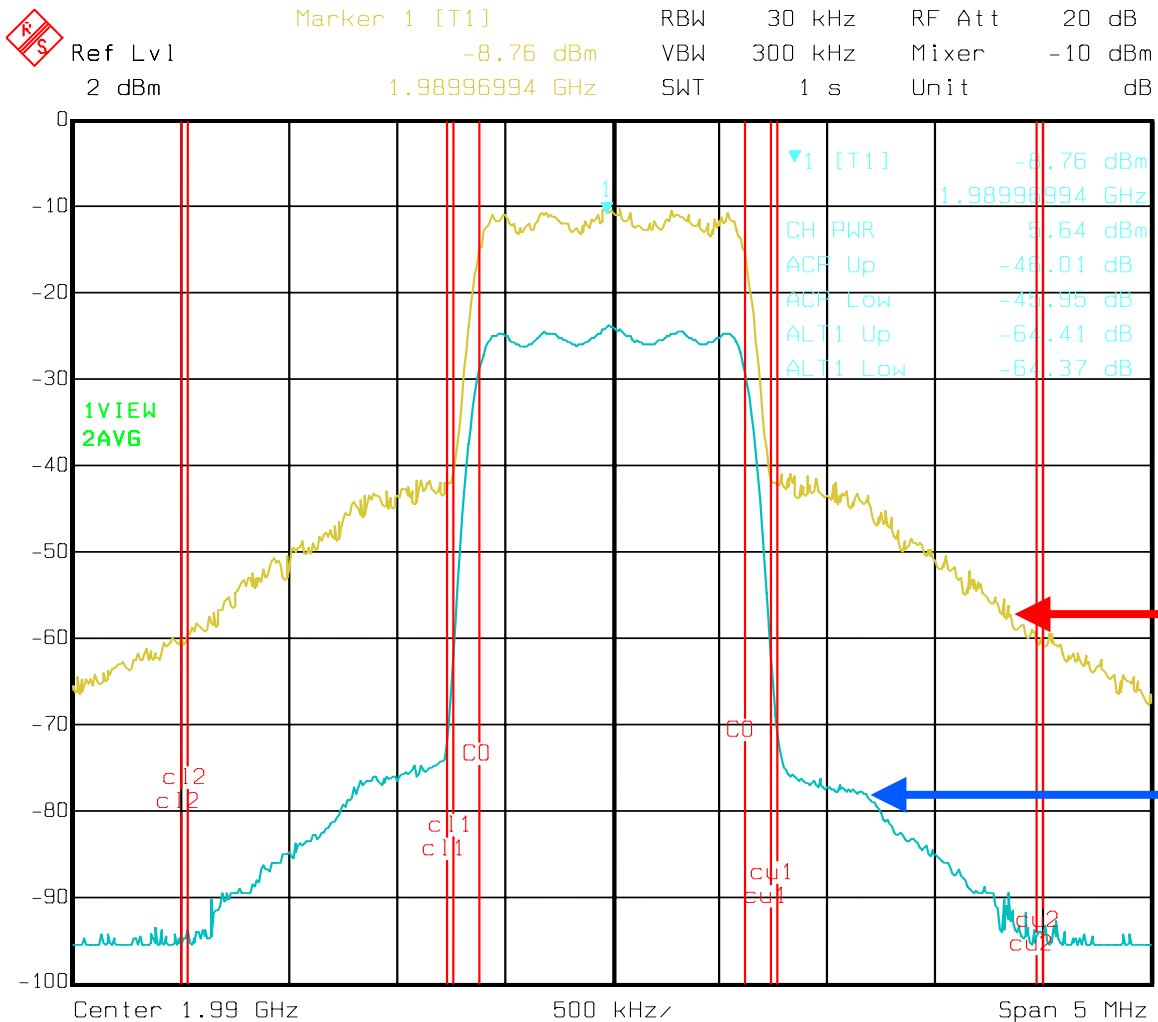


CDMA

- Modulation: QPSK
- Channel bandwidth: 1.23MHz
- PAR=9.8dB (single carrier, not clipped)
- Linearity:
 - ACPR (Adjacent Channel Power Ratio)
 - at multiple offsets, 750kHz, 885kHz, 1.98MHz
 - in a certain integration bandwidth (a small slice in the frequency domain)



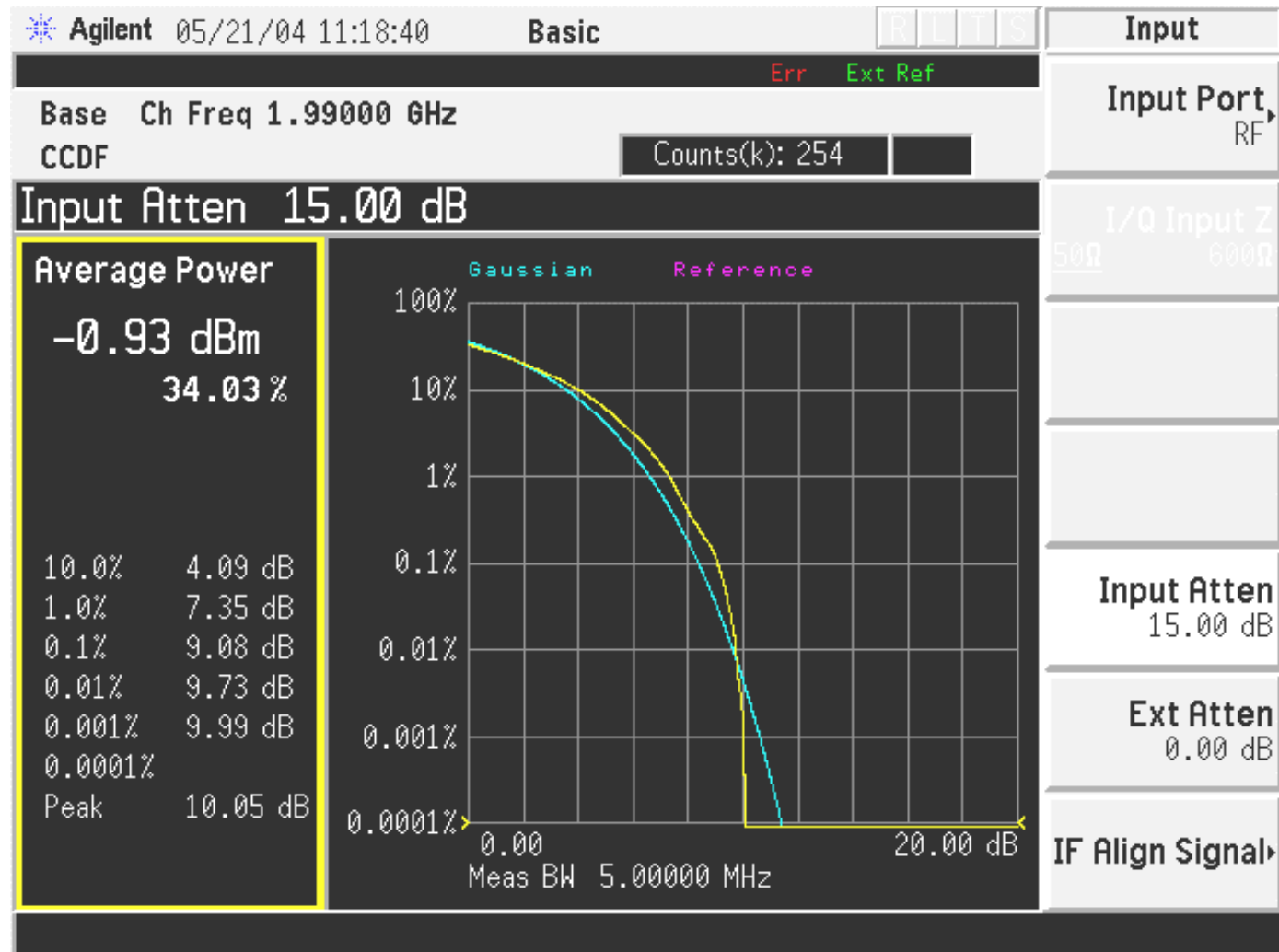
CDMA



Result after amplifier

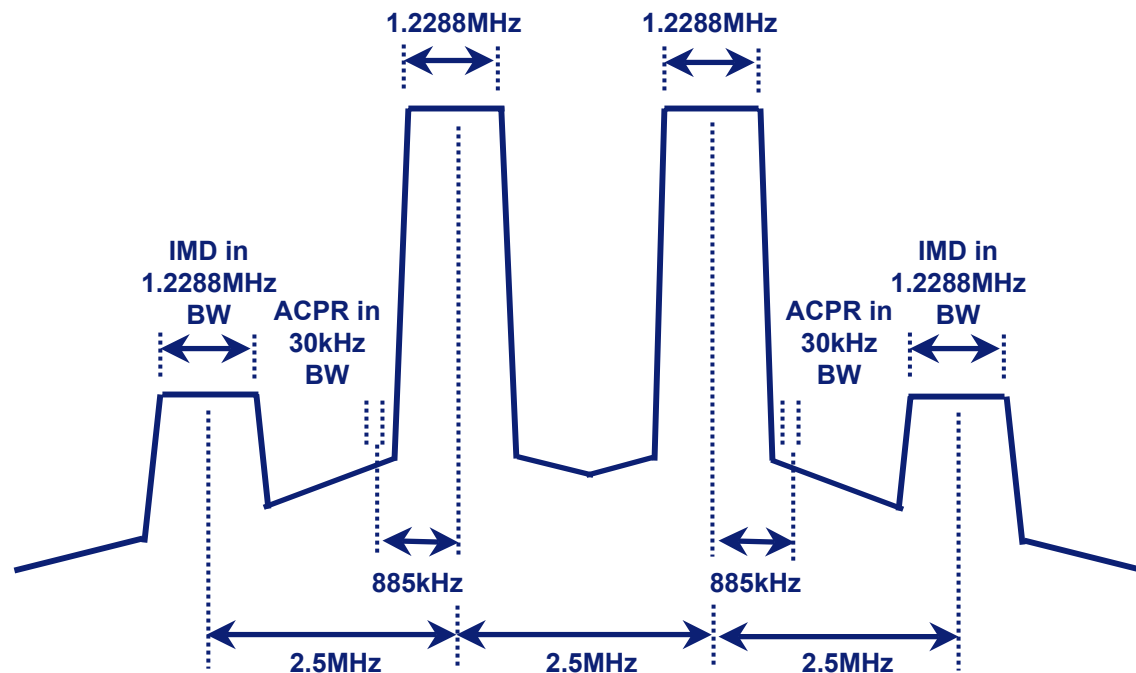
Drive signal

CDMA PAR



CDMA (Multi Carrier)

- Linearity:
 - ACPR (Adjacent Channel Power Ratio)
 - at 885kHz offset in 30kHz IBW
 - IMD (Intermodulation Distortion)
 - at offset depending on carrier spacing in 1.2288MHz IBW



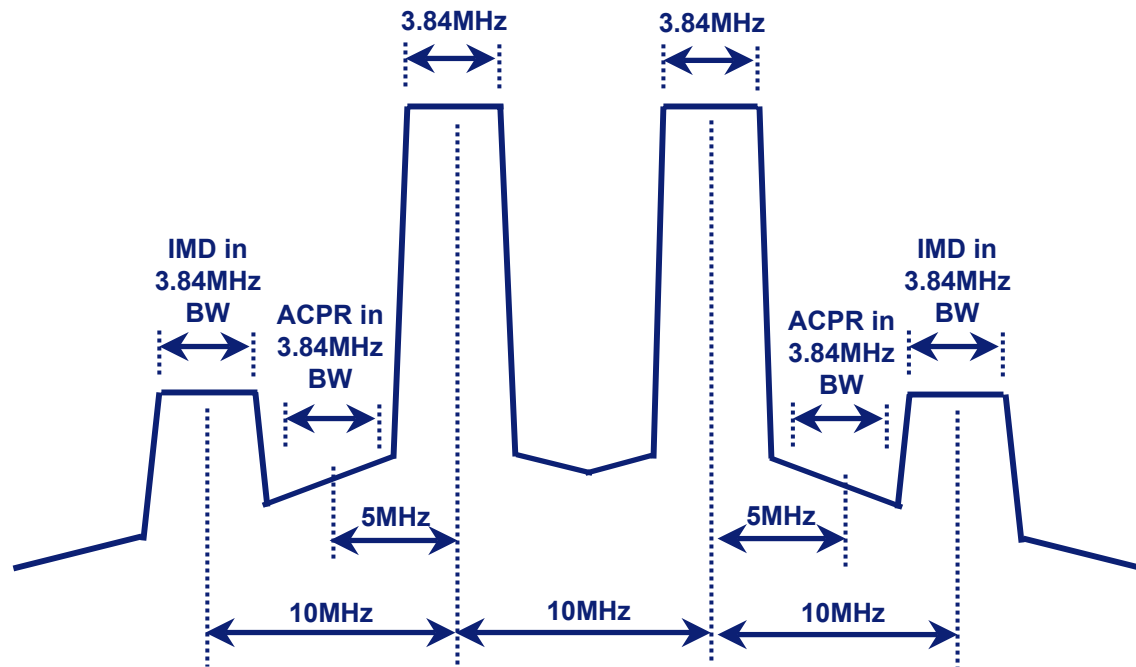
CDMA (Multi Carrier)

- Both ACPR and IMD are relative figures, with as reference one of the two (equal) carriers.
- Therefore, both ACPR and IMD are expressed in dBc.
- The offsets are defined from the center of the carriers.
- As can be seen is the IBW for the ACPR and IMD different. The IBW is defined by the standard.
- Sometimes the ACPR and/or IMD are also expressed in dBm, an actual power level. For that purpose the spectrum analyzer needs to be calibrated to read actual power levels.

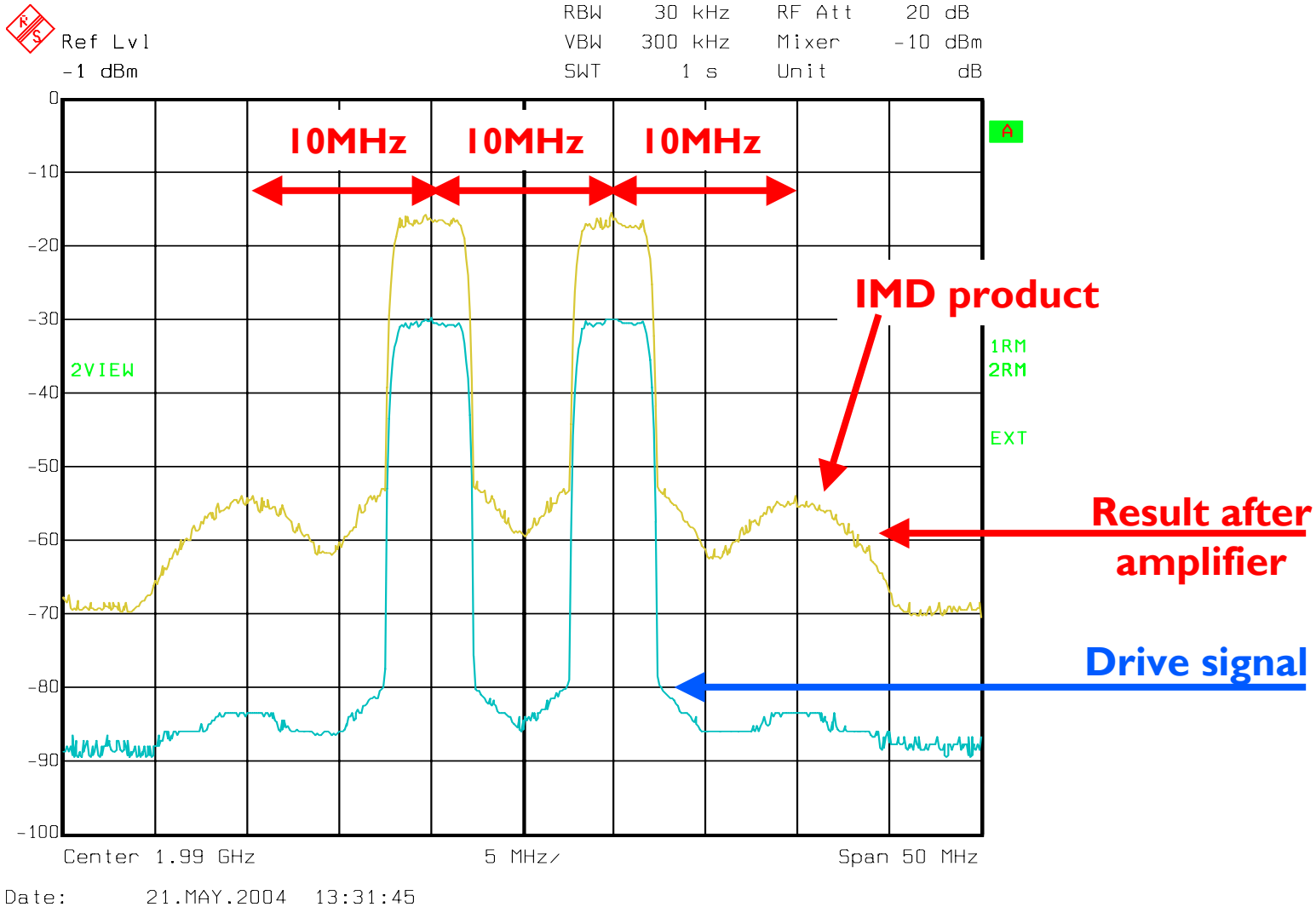
UMTS (Multi Carrier)

- Modulation: QPSK
- Channel bandwidth: 3.84MHz
- PAR=7-10dB (single carrier, depending on clipping)
- Linearity:
 - ACPR (Adjacent Channel Power Ratio)
 - at 5MHz offset in 3.84MHz IBW
 - IMD (Intermodulation Distortion)
 - at 10MHz offset for 10MHz carrier spacing in 3.84MHz IBW

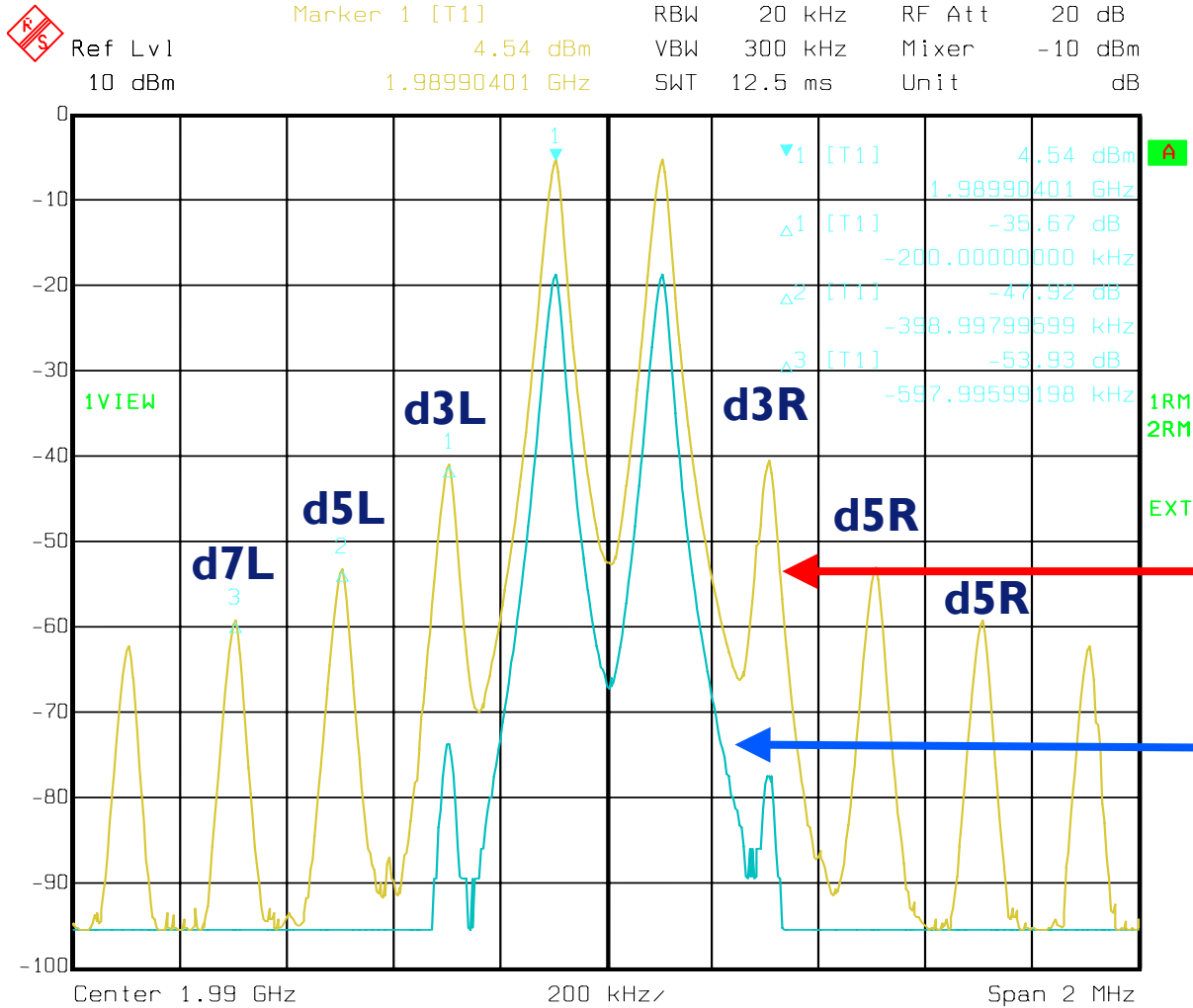
UMTS (Multi Carrier)



UMTS (Multi Carrier)



Two Tone CW

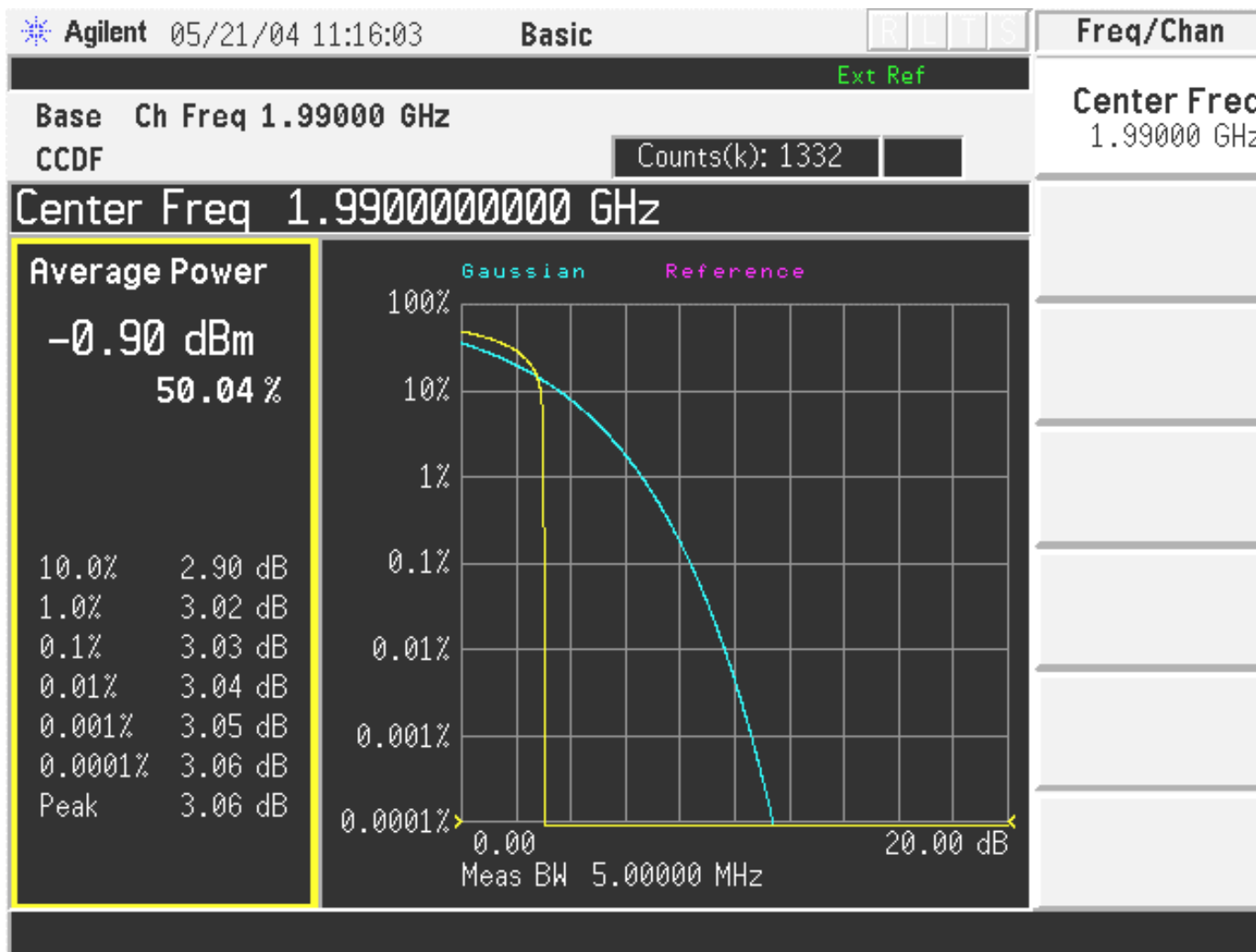


Result after amplifier

Drive signal

Date: 21.MAY.2004 13:08:49

Two Tone PAR



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Inside the RF Power transistor

Korné Vennema

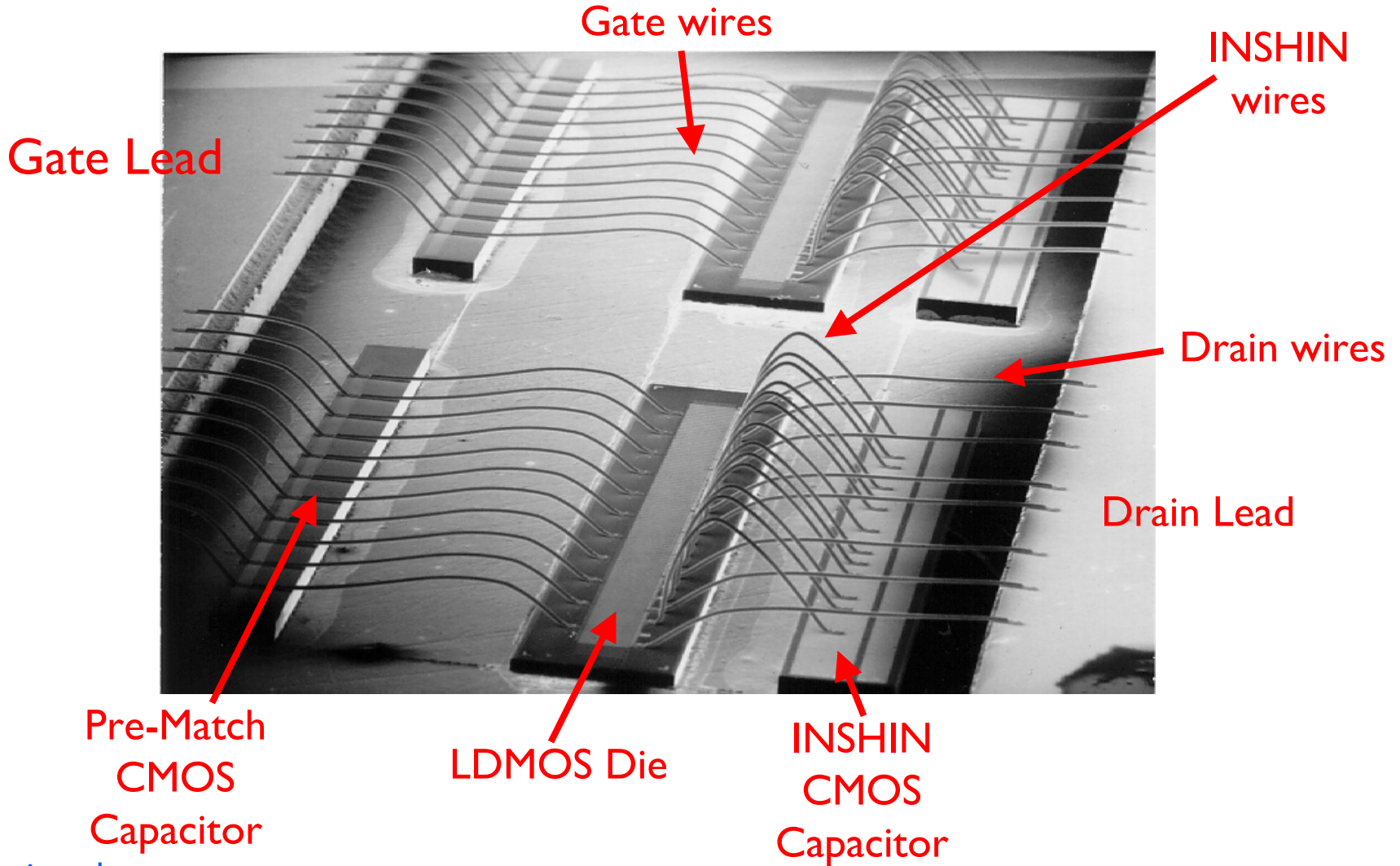
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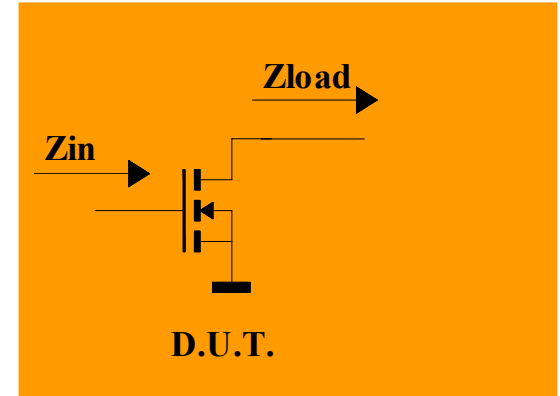
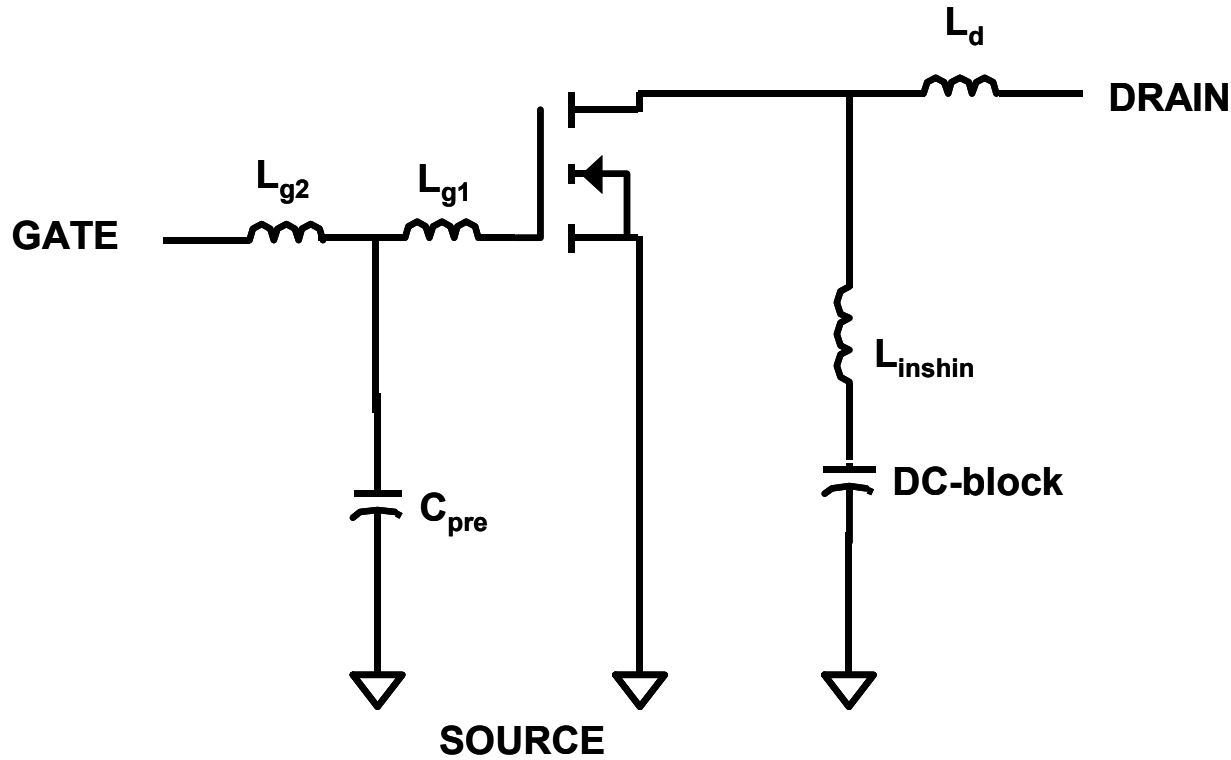
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A look inside the RF Power transistor



Schematic

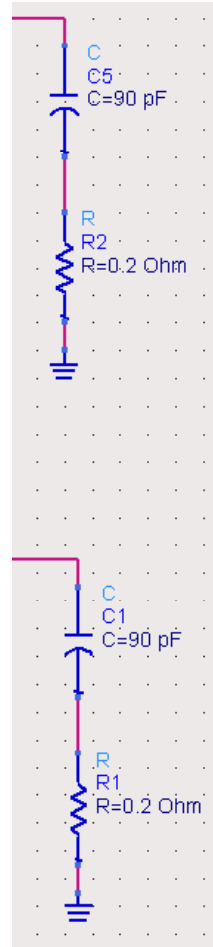


$$Z_{in} = R \pm jX$$

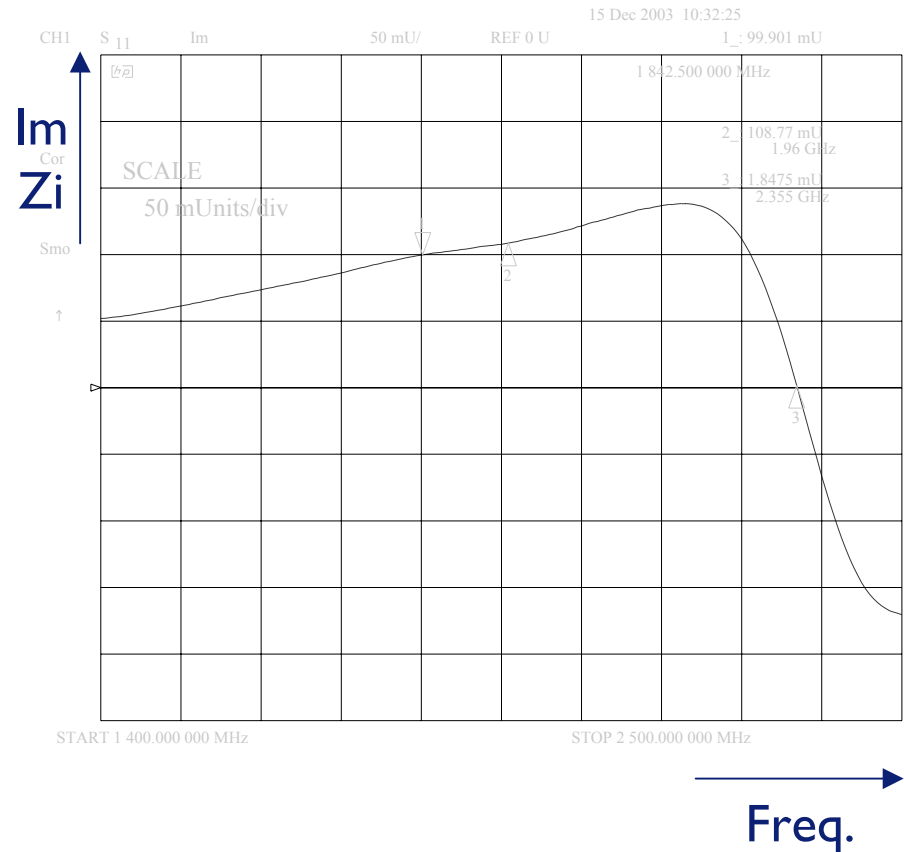
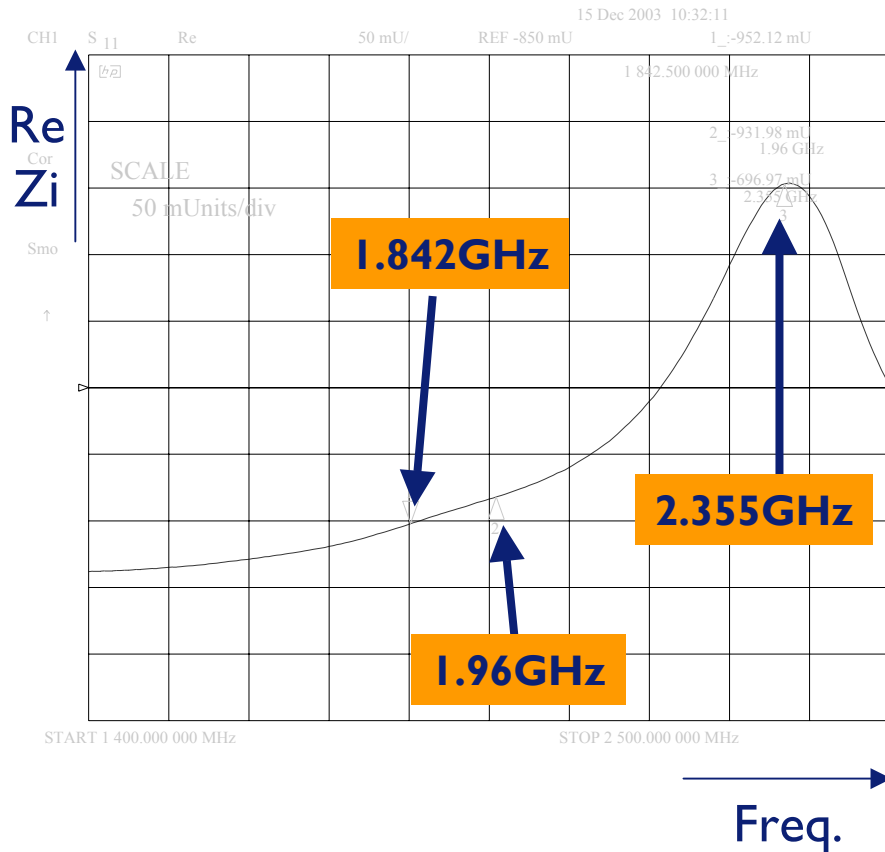
$$Z_{load} = R \pm jX$$

Why internal matching ?

- Impedance levels at the die are low. Extremely low. Internal matching brings these impedances to an acceptable level at the transistor terminals (leads) so the part can be matched more easily (also enable broadband matching) without too much insertion loss.
- To ensure a higher gain (transistor roll-off)
- The pre-match has a low pass characteristic. The output match has a high pass characteristic.
- Therefore, a transistor with pre- and output match inside has a band pass characteristic.

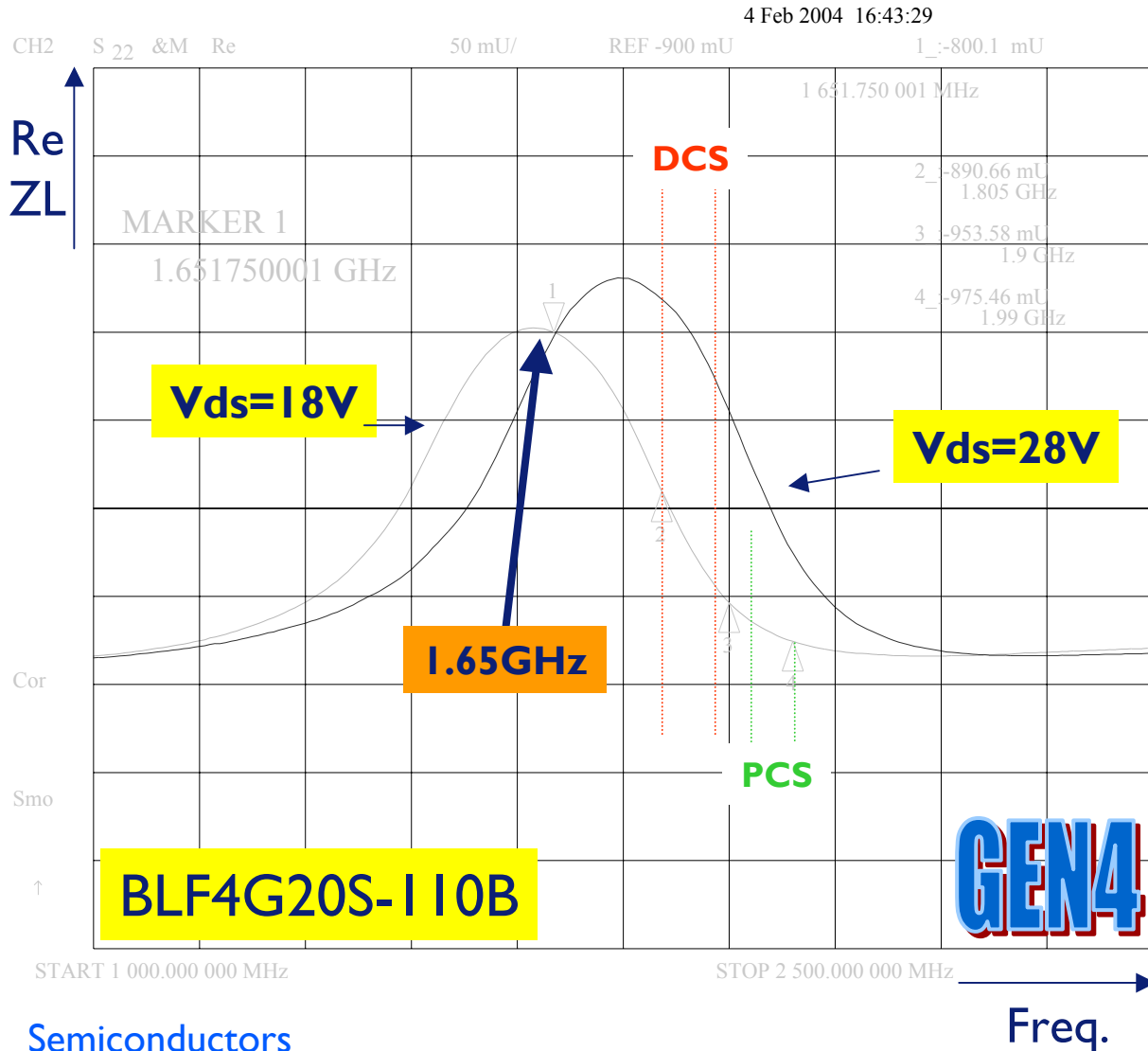


Input Resonance Frequency



BLF4G20-110B

Output Resonance Frequency

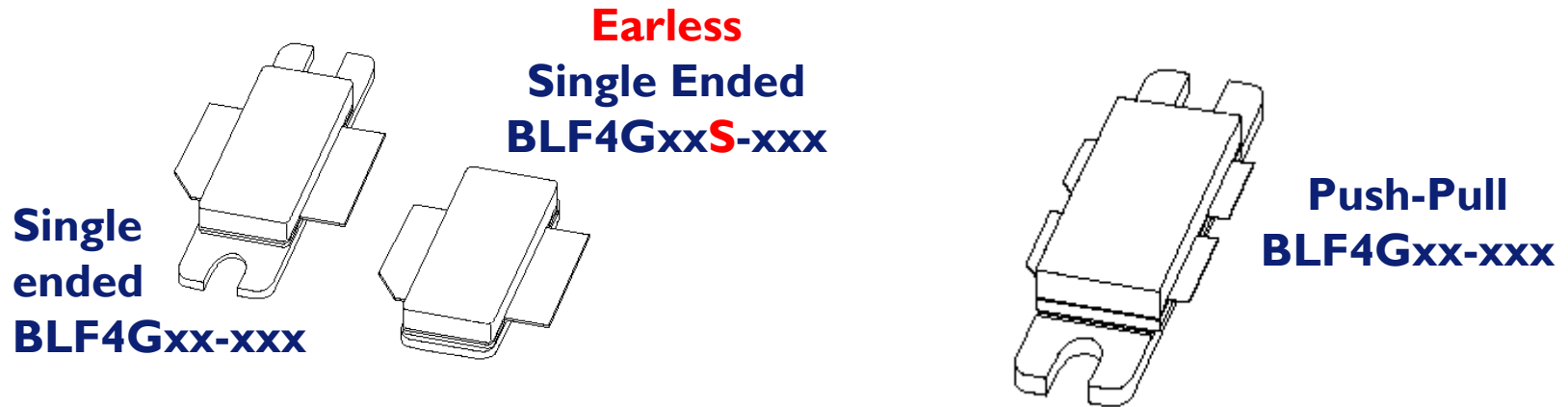


Typically:

Input resonance lies above the band of interest

Output resonance lies below the band of interest.

Single Ended vs. Push-Pull



A push-pull transistor is the same as two independent single ended transistors in one package (in most cases), operated 180° out of phase.

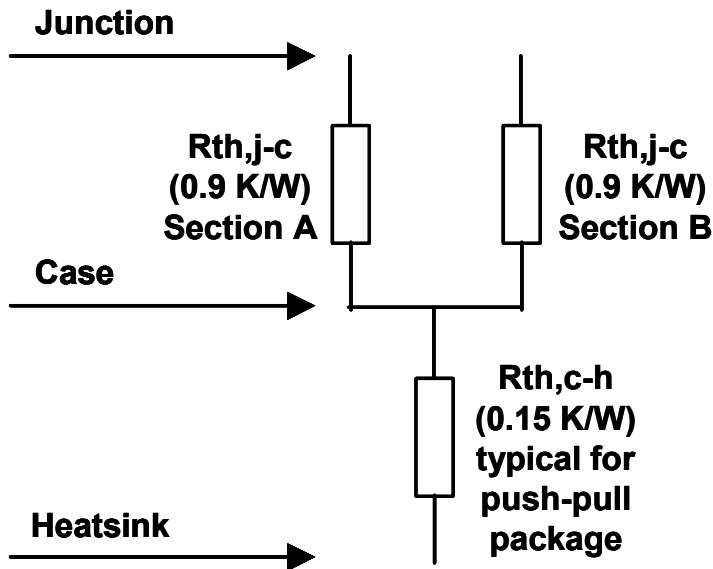
The advantages are:

- Higher impedances (between the two sections)
- Matched die
- 2nd harmonic suppression

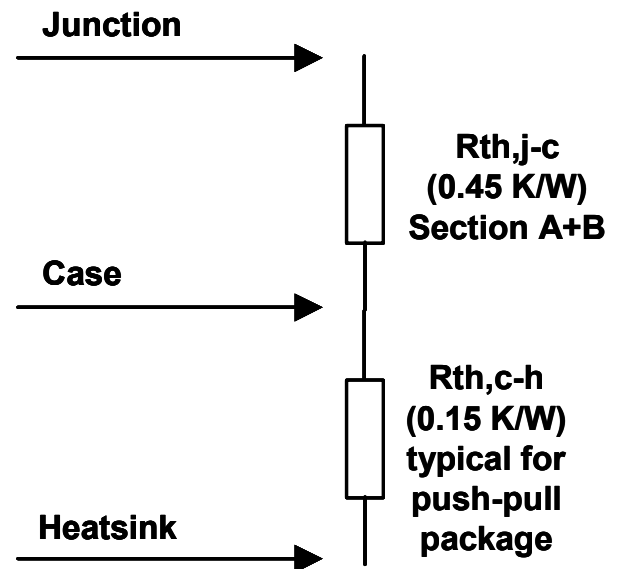
The disadvantages are

- More heat in a small area
- More expensive package

Thermal Resistance Push-Pull Transistor



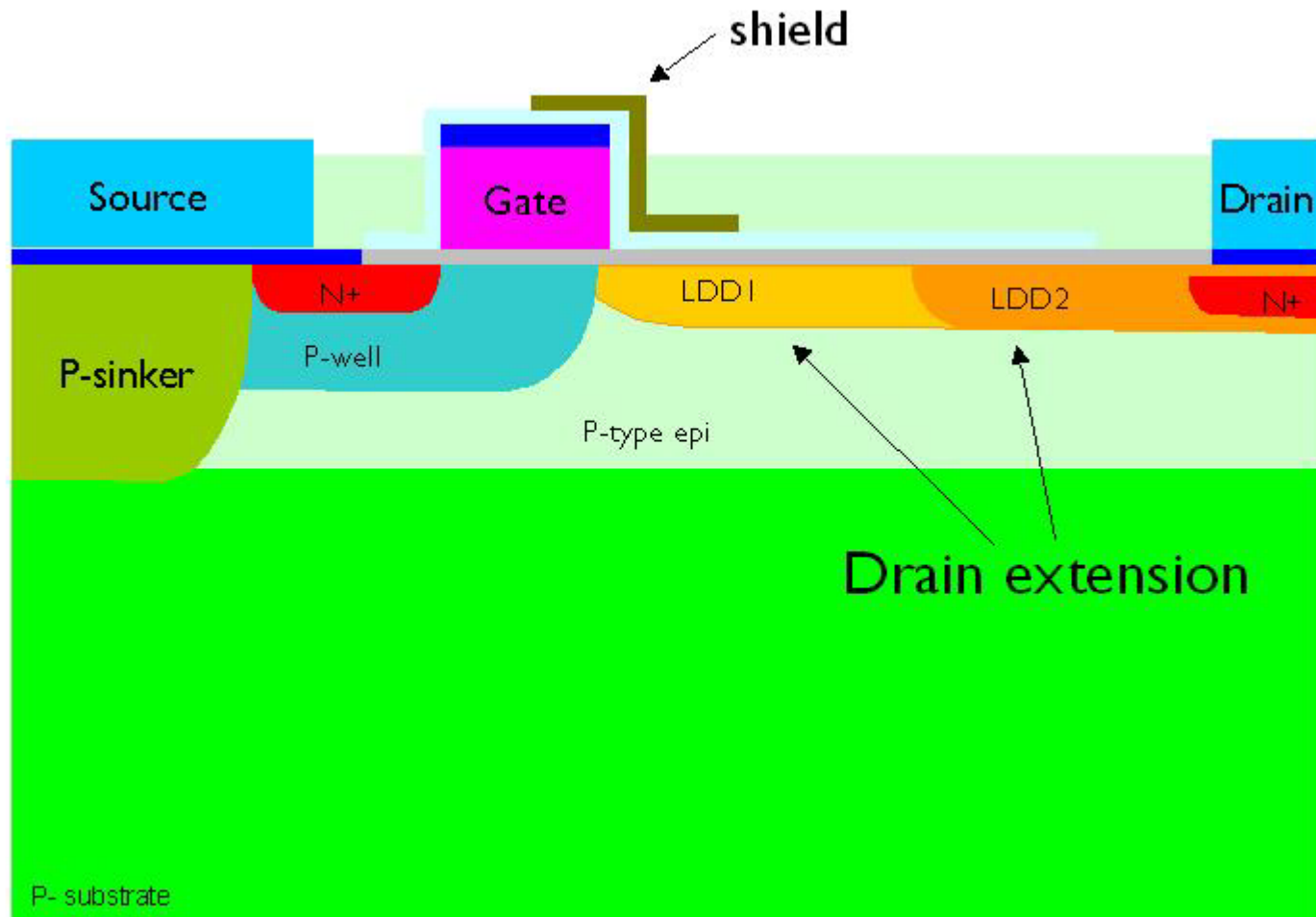
**“Schematic” Thermal Resistance
Push-Pull Transistor
(split out per section)**



**“Schematic” Thermal Resistance
Total Push-Pull Transistor**

Definition thermal resistance push-pull transistor

LDMOS Structure

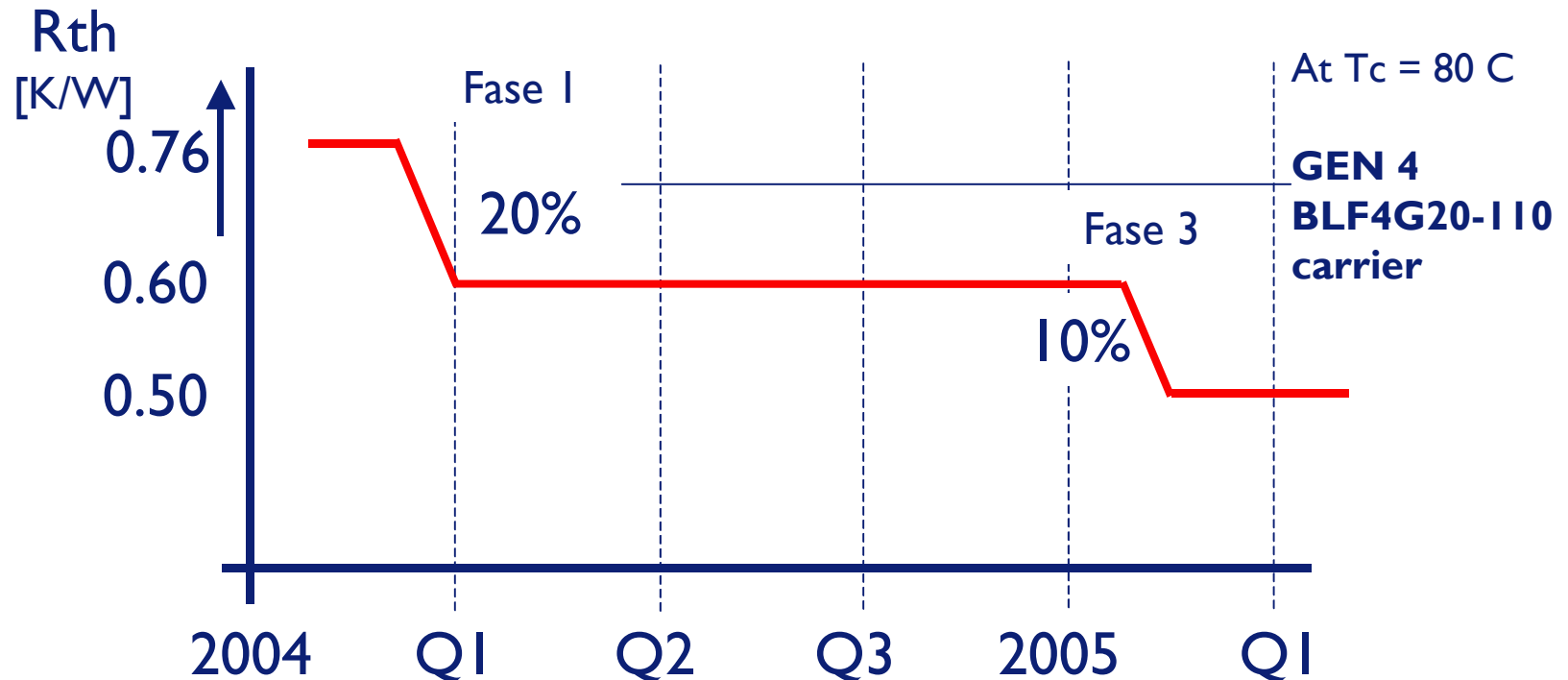


LDMOS Cross Section

- Drain extension sets:
 - I_{dq} drift
 - Breakdown voltage
 - R_{ds-on} (doping amount)
 - I_{dsx} (saturation current / peak power capability)
- Shield sets:
 - Feedback capacitance
 - Field distribution in drain extension (I_{dq} -drift)

Packaging

- Focus
 - lower thermal resistance
 - the package
 - the die layout
 - cheaper
 - plastic
 - cheaper package



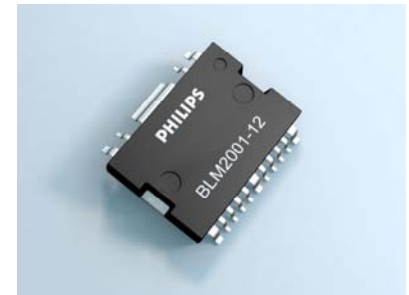
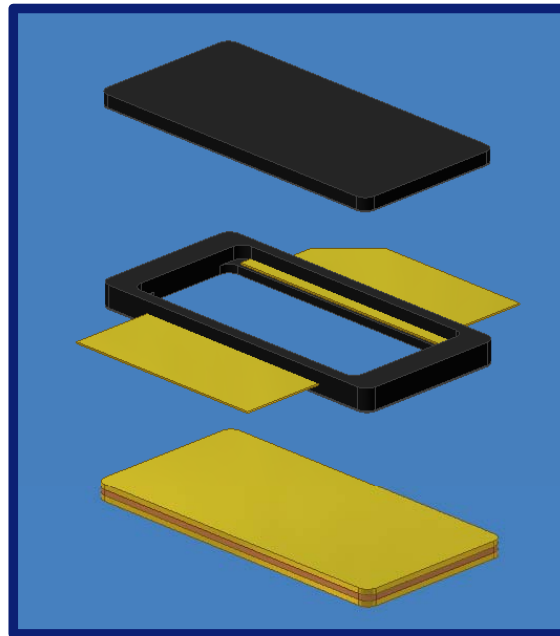
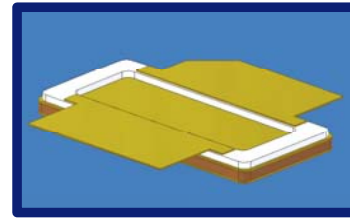
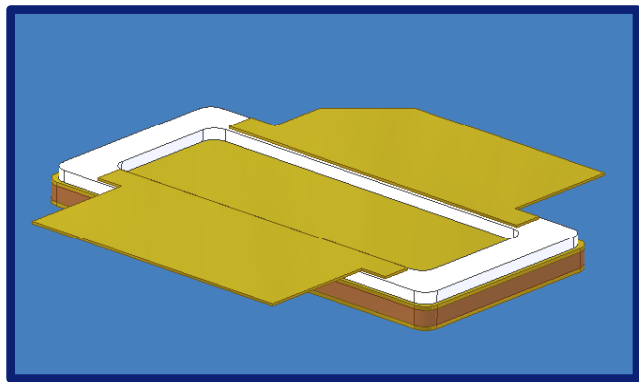
Packaging



Cu - CuMO - Cu



CuW - Cu on top



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Transistor Characteristics

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Typical LDMOS Characteristics

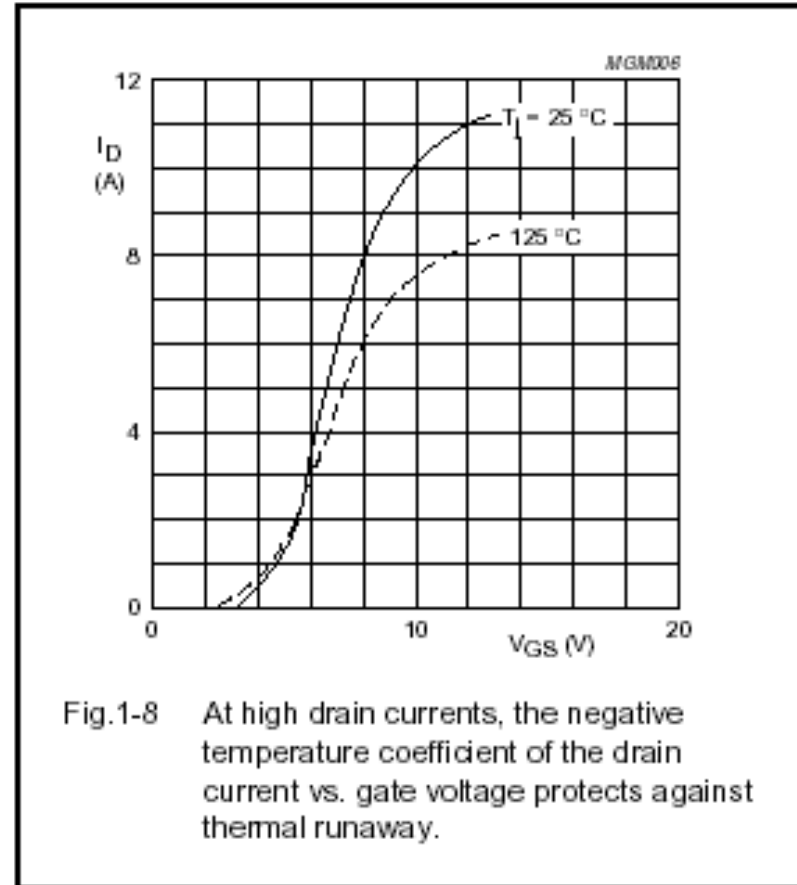
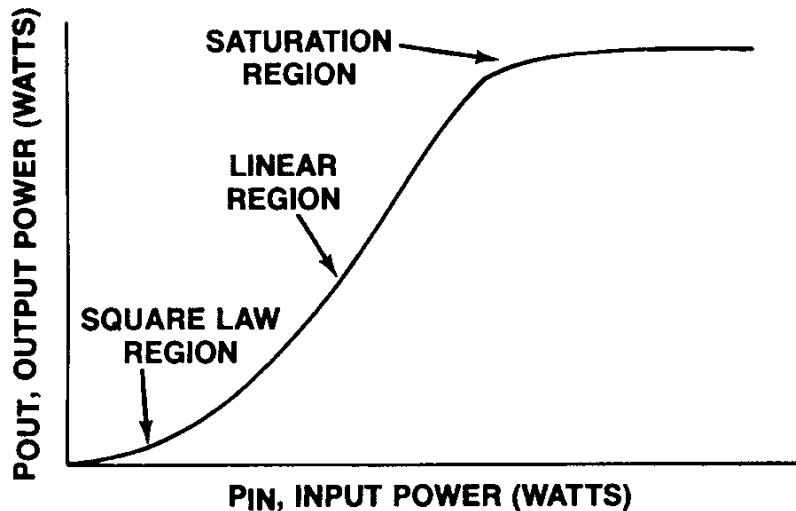
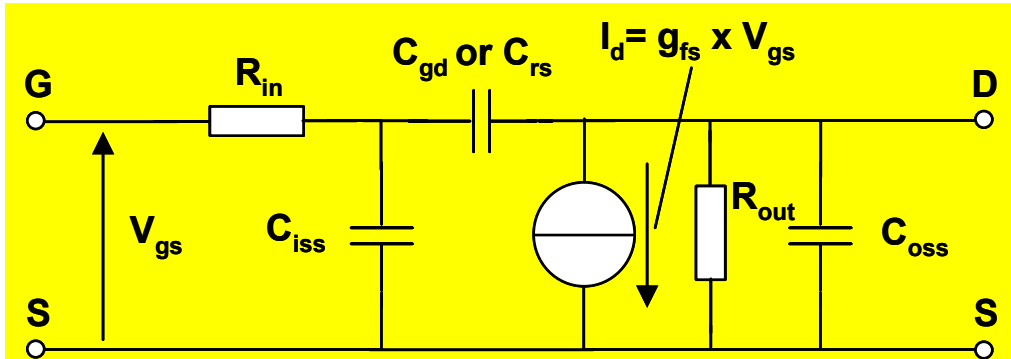


Fig.1-8 At high drain currents, the negative temperature coefficient of the drain current vs. gate voltage protects against thermal runaway.

LDMOS DC Characteristics

CHARACTERISTICS

$T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified.

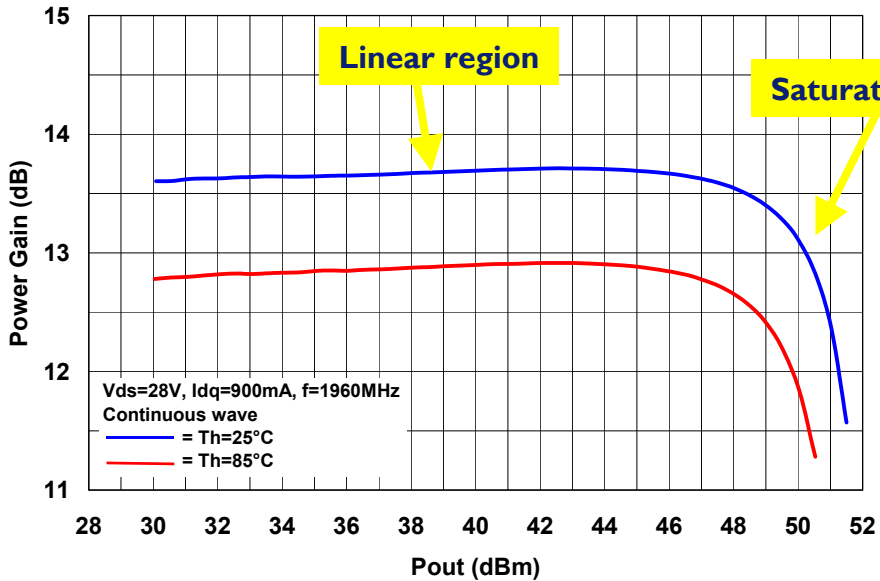
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0; I_D = 2.1\text{ mA}$	65	–	–	V
V_{GSth}	gate-source threshold voltage	$V_{DS} = 10\text{ V}; I_D = 180\text{ mA}$	2.5	3.1	3.5	V
V_{GSq}	gate-source quiescent voltage	$V_{DS} = 28\text{ V}; I_D = 900\text{ mA}$	–	3.5	4.5	V
I_{DSS}	drain-source leakage current	$V_{GS} = 0; V_{DS} = 28\text{ V}$	–	–	2	μA
I_{DSX}	on-state drain current	$V_{GS} = V_{GSth} + 9\text{ V}; V_{DS} = 10\text{ V}$	27	30	–	A
I_{GSS}	gate leakage current	$V_{GS} = \pm 15\text{ V}; V_{DS} = 0$	–	–	200	nA
g_{fs}	forward transconductance	$V_{DS} = 10\text{ V}; I_D = 10\text{ A}$	–	9.0	–	S
R_{DSon}	drain-source on-state resistance	$V_{GS} = V_{GSth} + 6\text{ V}; I_D = 6\text{ A}$	–	0.09	–	Ω
C_{rs}	feedback capacitance	$V_{GS} = 0; V_{DS} = 28\text{ V}; f = 1\text{ MHz}$	–	2.5	–	pF

- $V_{(BR)DSS}$ = break down voltage DS-junction
- $V_{gs\text{th}}$ = GS-voltage at which the device starts drawing current
- V_{gsq} = GS-voltage for a typical I_{dq} (quiescent current)
- I_{dss} = Leakage current due to imperfections in epi-layer with no GS-voltage applied

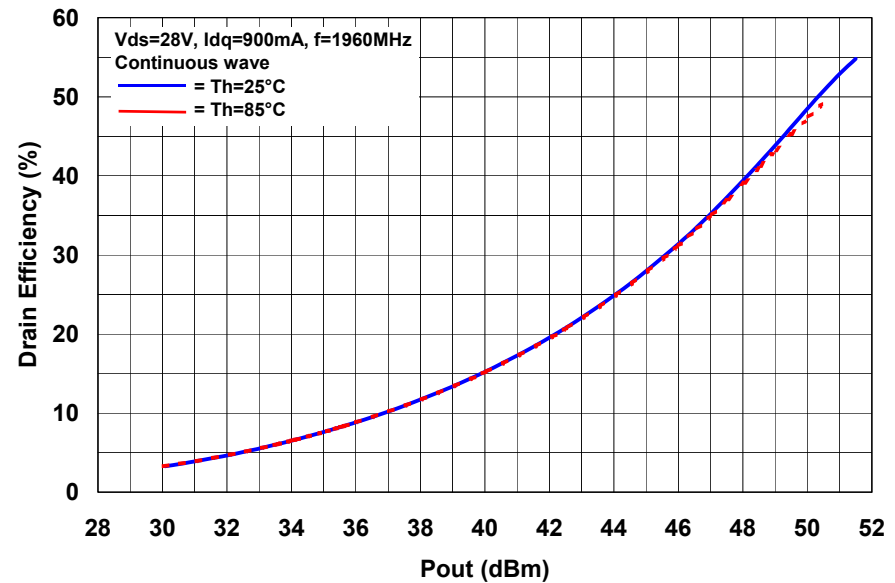
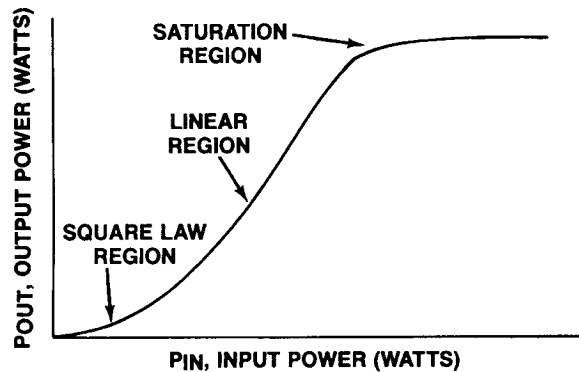
LDMOS DC Characteristics

- I_{dss} = Leakage current due to imperfections in epi-layer with no GS-voltage applied
- I_{dsx} = Maximum *saturated* drain current with high V_{gs}
- I_{gss} = Gate leakage current (oxide and other imperfections)
- G_{fs} = Forward transconductance in Siemens ($S = A/V$)
- R_{ds-on} = Drain source on-resistance (substrate / doping / wire bonds)
- C_{rs} = Feedback capacitance

Typical RF Power Characteristics



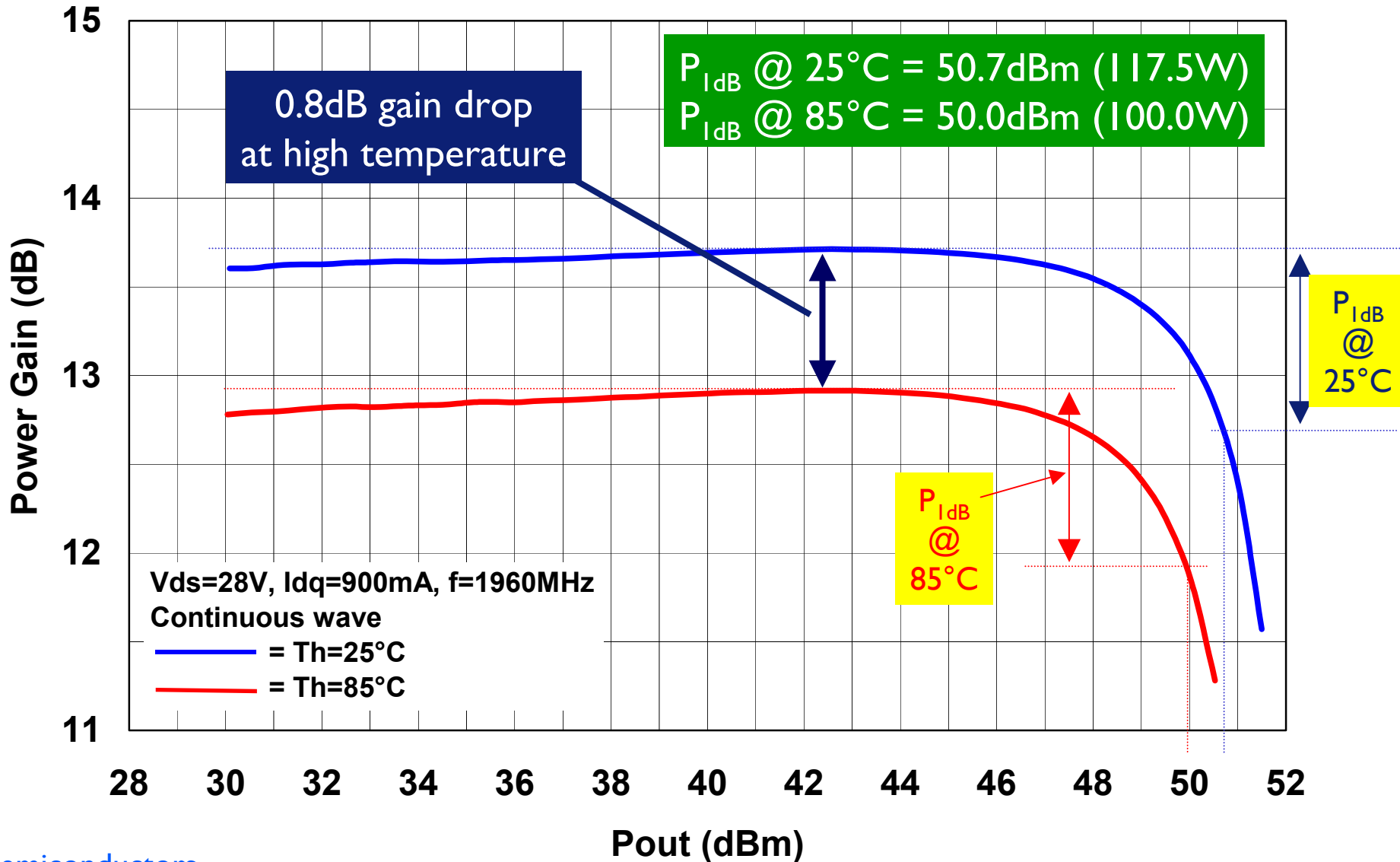
Power gain vs. Pout
&
Efficiency vs. Pout
at different Th
Continuous Wave (CW)



Typical RF Power Characteristics

- $P_{1\text{dB}}$ is the output power level where the power gain is 1 dB compressed.
- The saturation power (P_{sat}) is the output power level where $\Delta P_{\text{out}} : \Delta P_{\text{in}} = 1$
- $P_{1\text{dB}}$ and P_{sat} are (die) temperature dependent, which is the reason why the real P_{sat} is often determined under pulsed conditions to keep the average P_{out} –and thus the die temperature– low

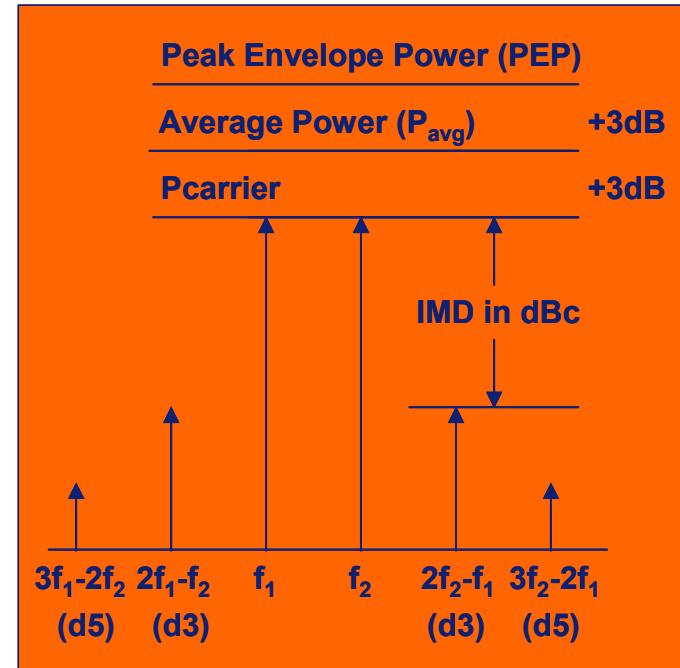
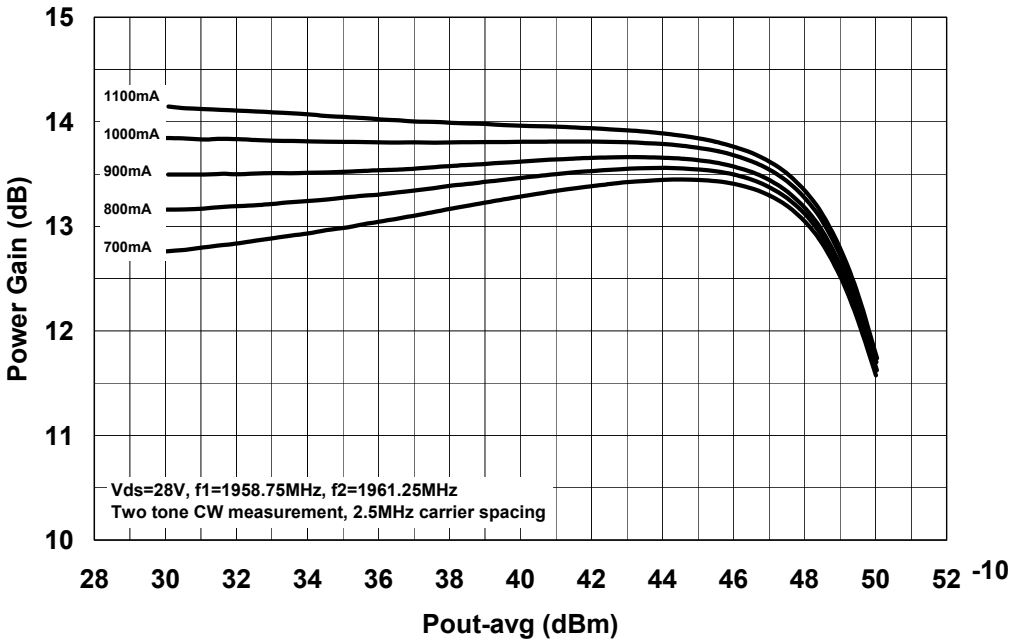
Typical RF Power Characteristics



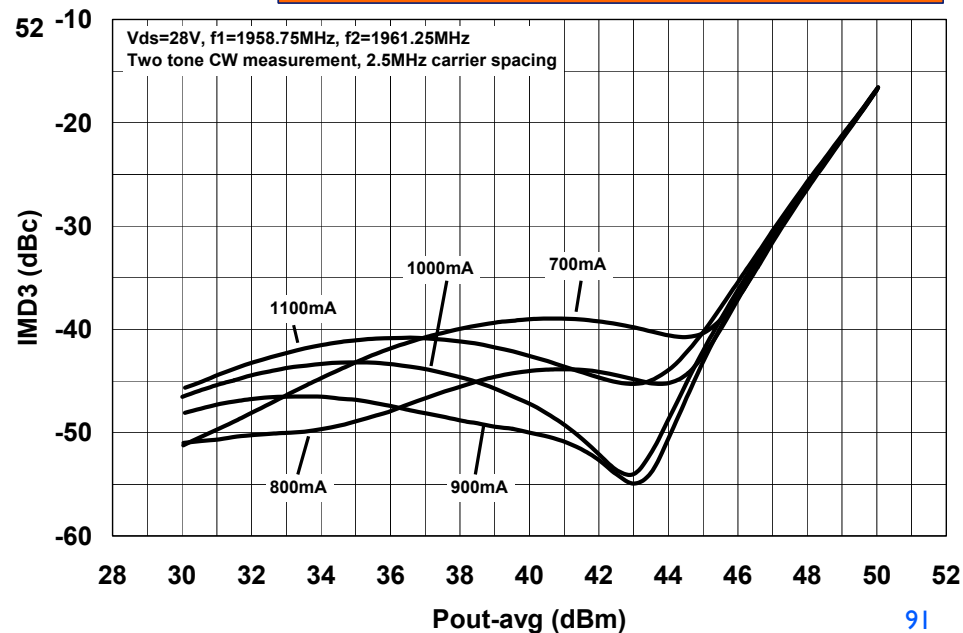
Considerations at high temperature

- The following transistor characteristics have to be accounted for during amplifier design:
 - The gain of a transistor is lower (ca. 0.8dB) at $T_h=85^\circ\text{C}$. This requires a more powerful driver transistor.
 - The P_{IdB} and P_{sat} are lower at $T_h=85^\circ\text{C}$. This has a negative effect on linearity.
 - The transistor life time reduces at higher temperatures.
 - The transistor efficiency does not change a lot at higher temperatures.

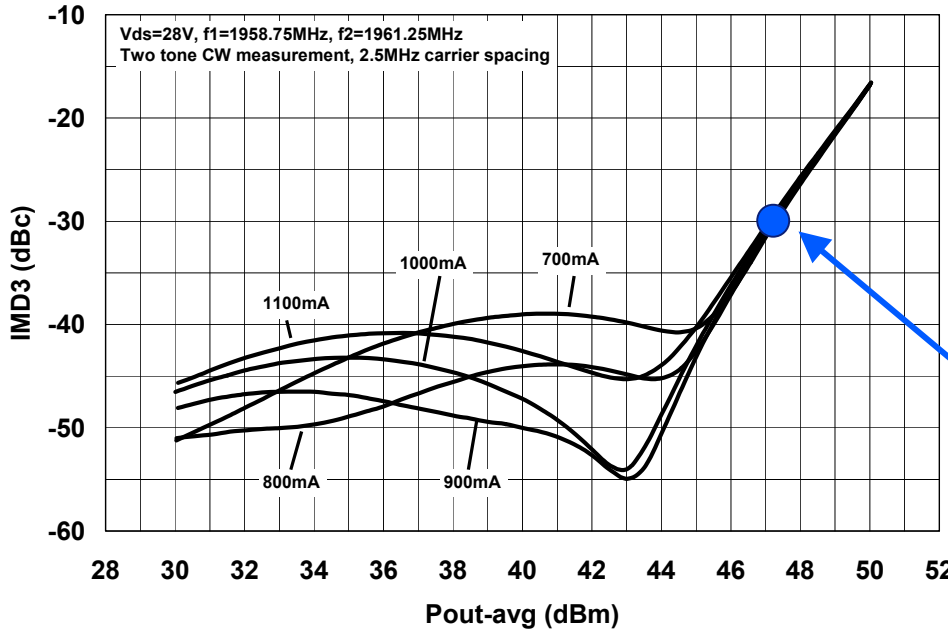
RF Power Characteristics



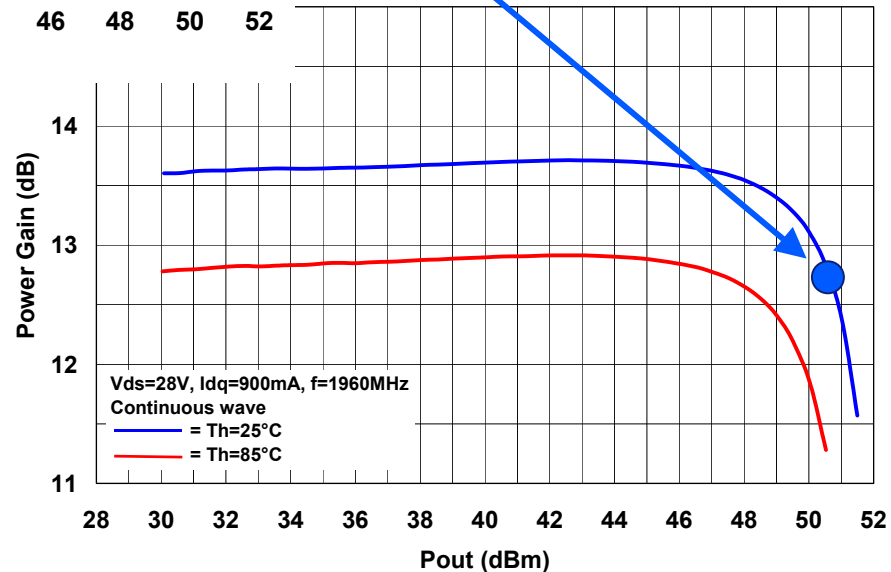
Power gain vs. Pout
&
IMD3 vs. Pout
Two Tone CW



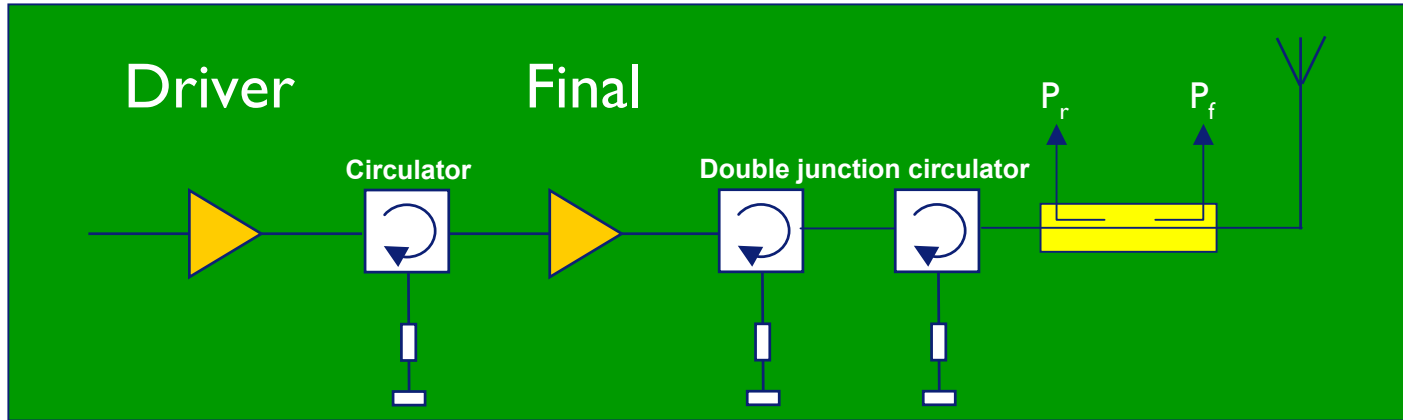
PI dB and 2T CW linearity



P_{1dB} corresponds approximately to -30dBc IMD3 power level (add the 3dB between average and peak power)



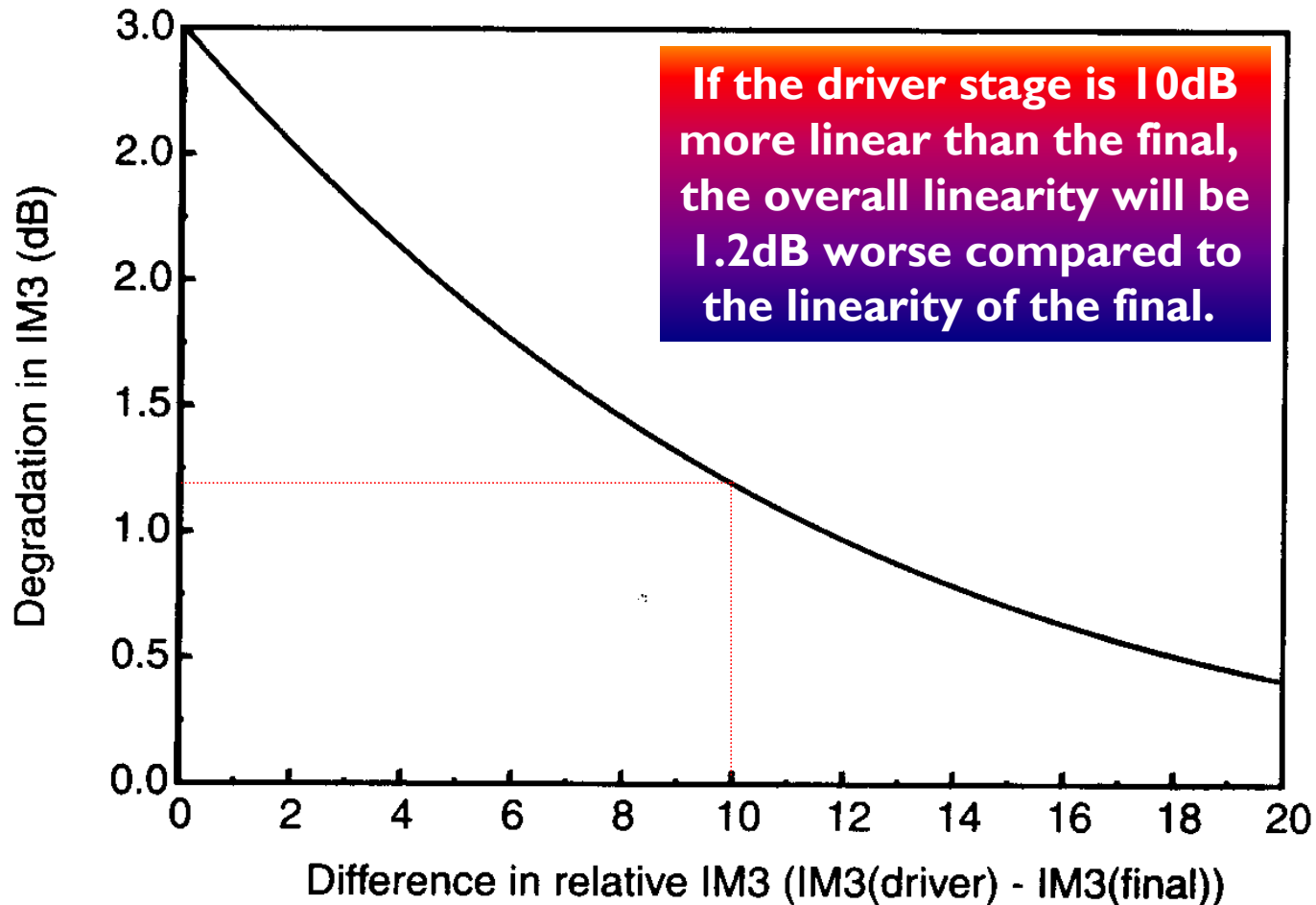
Two Tone Linearity & Multi Stage Amplifiers



- The overall (2T) linearity of an amplifier is determined by the linearity of both the final and driver stage. In this case we'll assume circulators don't degrade linearity which is not true.
- The degradation in IMD3 can be expressed as follows:

$$IMD3 \text{ Degradation} [dB] = 10 \log \left[1 + 10^{\frac{IMD(Driver) - IMD3(Final)}{20}} \right]$$

Two Tone Linearity & Multi Stage Amplifiers



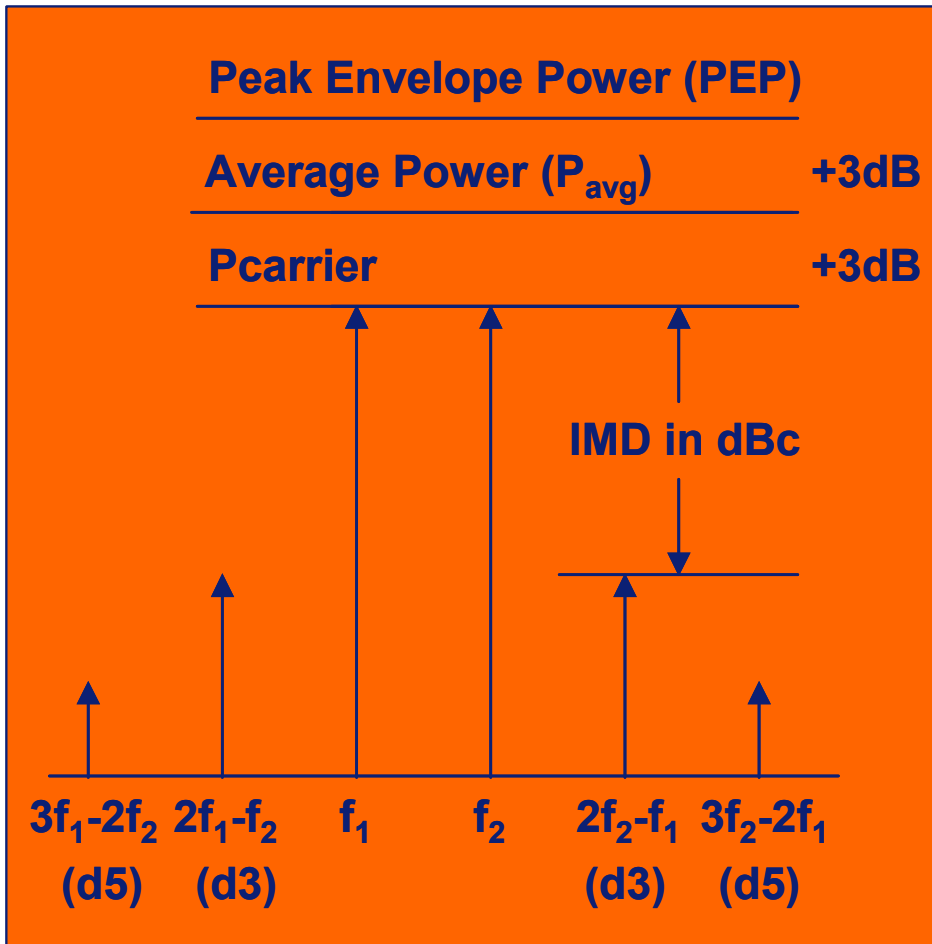
Notes on Peak-to-Average ratio (PAR)

- Peak-to-Average Ratio (PAR) is defined as the *ratio* of the peak power to **average** power.

$$PAR = \frac{\text{Peak Power}}{\text{Average Power}} [-]$$

- When the PAR=2, one also says often: The PAR=3dB ($10\log 2$).

Notes on PAR

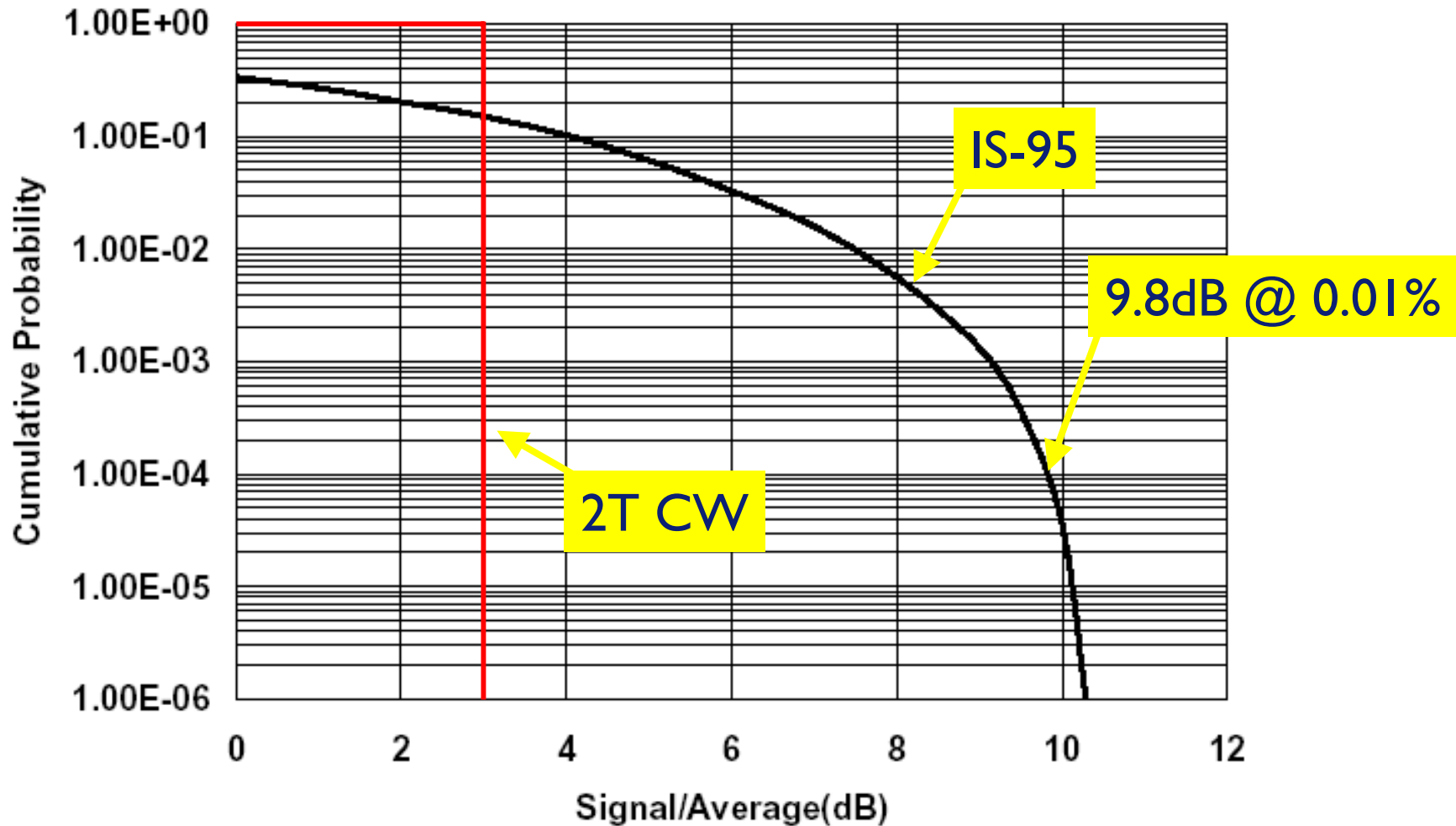


The PAR for a 2-tone CW signal is *always* 2 (or 3dB)

Notes on PAR

- For complex digital modulation schemes, the story is different.
- The PAR is specified at a certain level (in dB), with a certain probability (the chance a certain PAR is reached).
- This probability as a function of PAR is expressed in a **Cumulative Distribution Function** (CDF), often called CCDF (Complementary Cumulative Distribution Function). The probability is expressed in %.
- For instance, the PAR for an IS-95 signal (pilot, paging, sync and 6 traffic channels with Walsh codes 8-13) is: 9.8dB at 0.01% probability

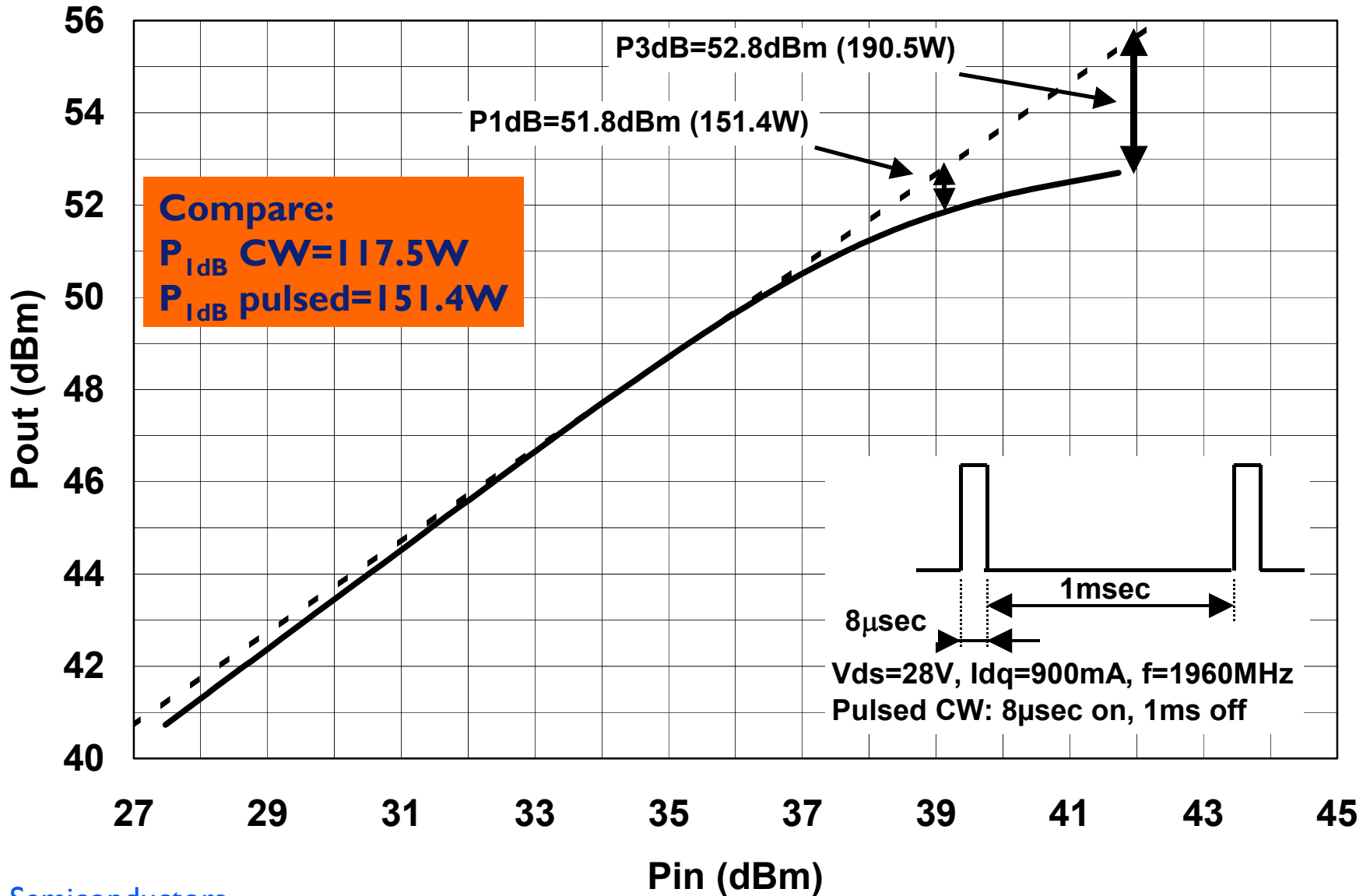
CDF for an IS-95 and 2-tone CW signal



P_{IdB} , P_{sat} and P_{peak}

- In the previous slides it was shown that P_{IdB} and P_{sat} are (die)temperature dependent, i.e.:
 - when the heatsink temperature is high
 - when the device is operating at a high output power, i.e. large current draw, and high dissipation
- That is the reason why the real peak power often is determined under pulsed conditions or at a low average power with spikes on top of that (for instance a CDMA signal).

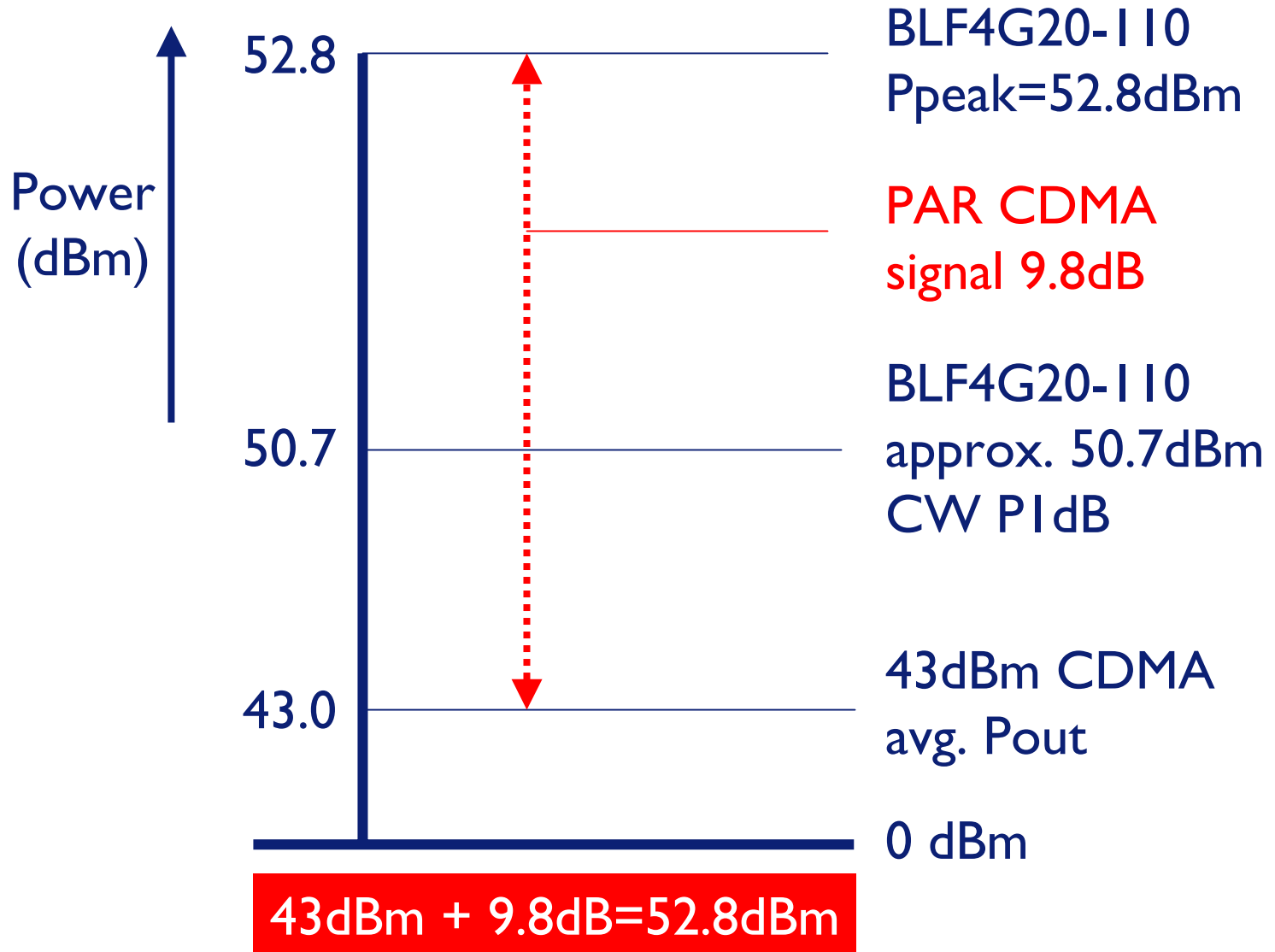
Peak Power Capability



The Importance Of Peak Power Capability

- Peak power capability is of particular interest when the amplifier is used with complex digital modulation signals with a high PAR.
- In that case, the average output power is relatively low, but high peaks can occur in the signal.
- If the high peaks exceed the peak power capability of the device, distortion is introduced.
- A 100W (1 dB, CW) transistor, can typically be used at 20-25W (depending on linearity requirements) average CDMA power with a PAR=9.8dB @ 0.01%.
- Peak power capability is also a measure for how well one can apply pre-distortion (discussed later).

BLF4G20-110B for CDMA (approximation)



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Pulsed Applications

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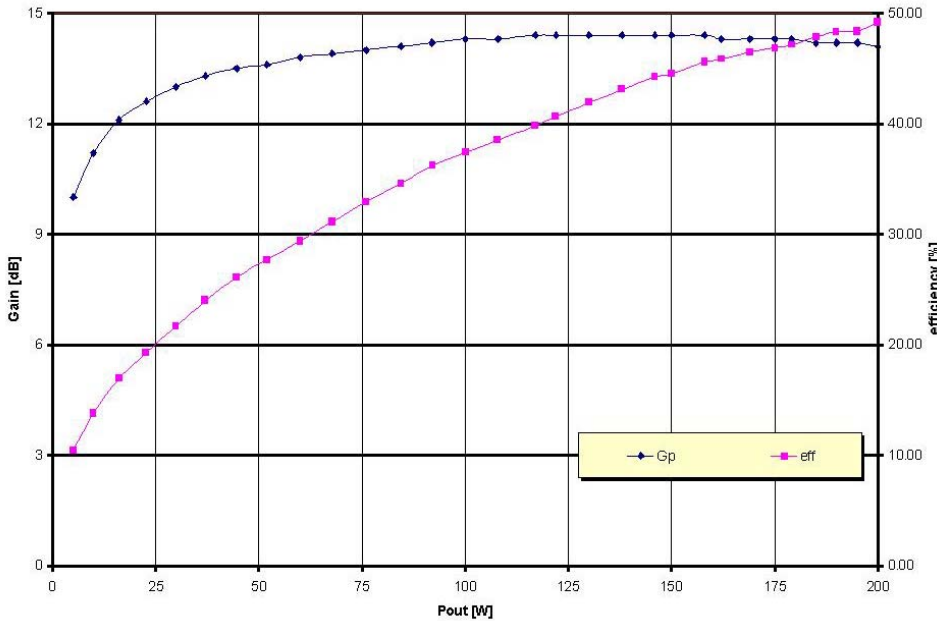
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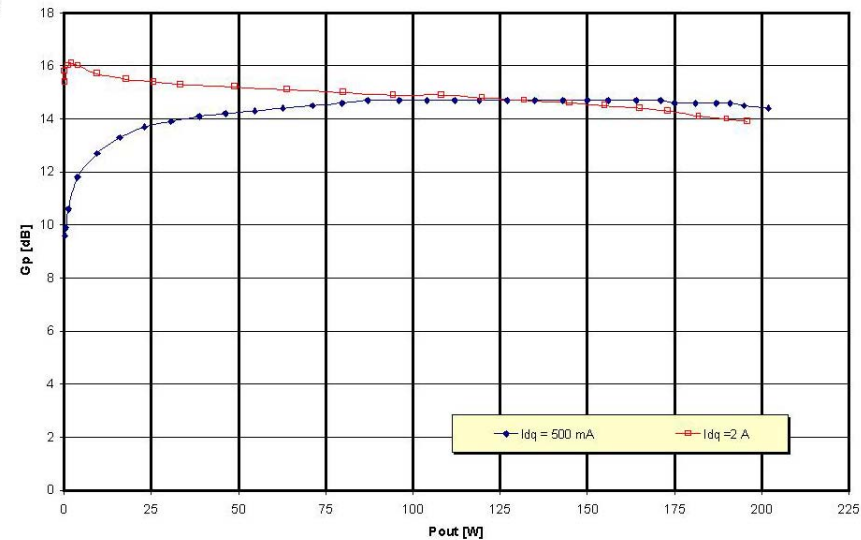
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LDMOS for Pulsed Applications



Main advantages over bipolar

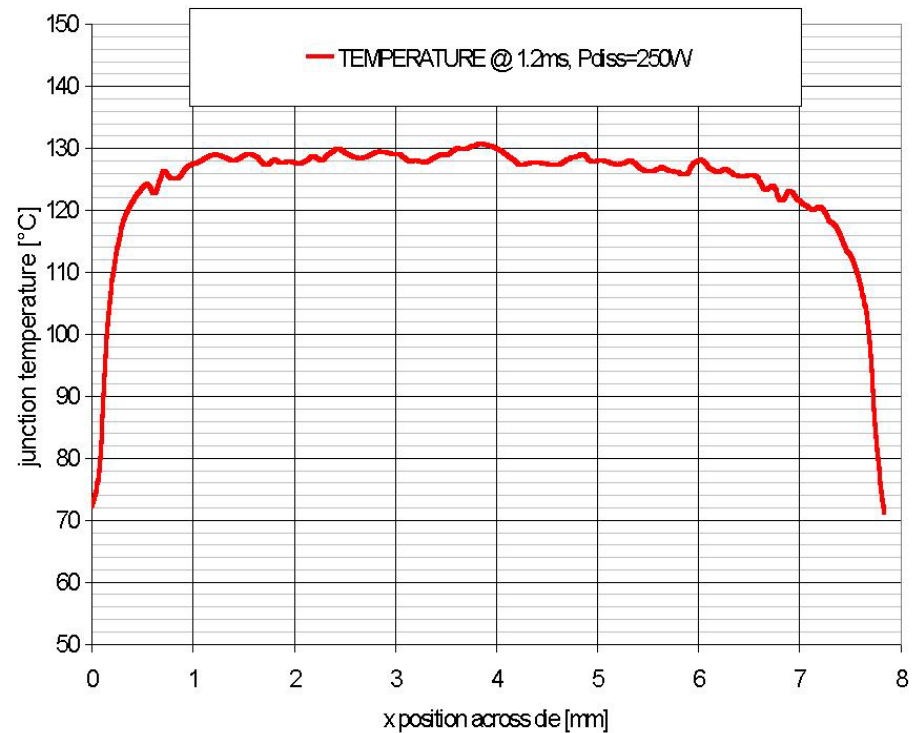
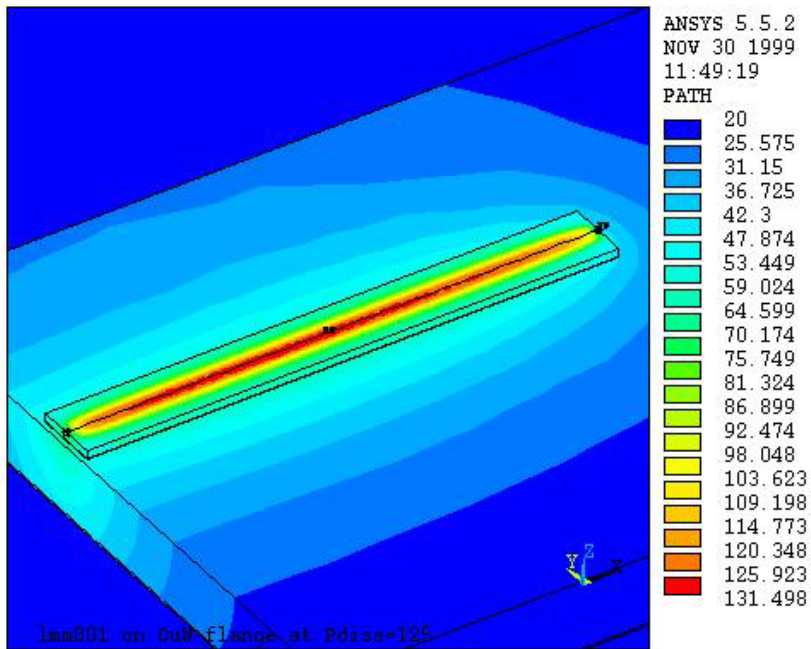
- High gain
- High efficiency
- Good linearity



LDMOS vs. Bipolar (Pulsed)

- Excellent thermal stability: due to negative temperature coefficient
- Excellent ruggedness due to high breakdown voltage of die technology and its good thermal stability
- Pulse shaping easy compared to bipolars by modulating V_{gs}
- Package does not contain BeO, source mounted direct to flange – also better thermal properties.

Thermal Characteristics LDMOS (Pulsed)



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Application Circuits

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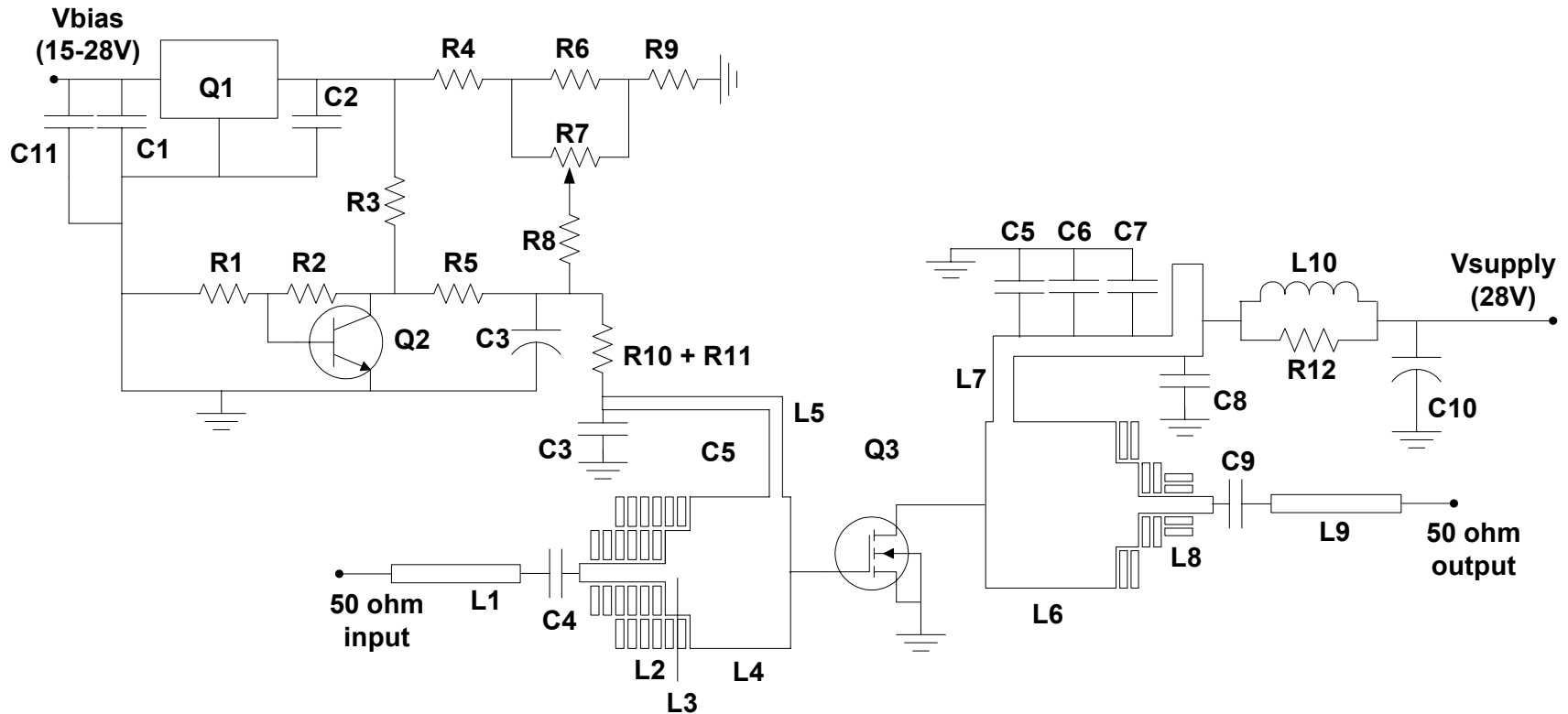
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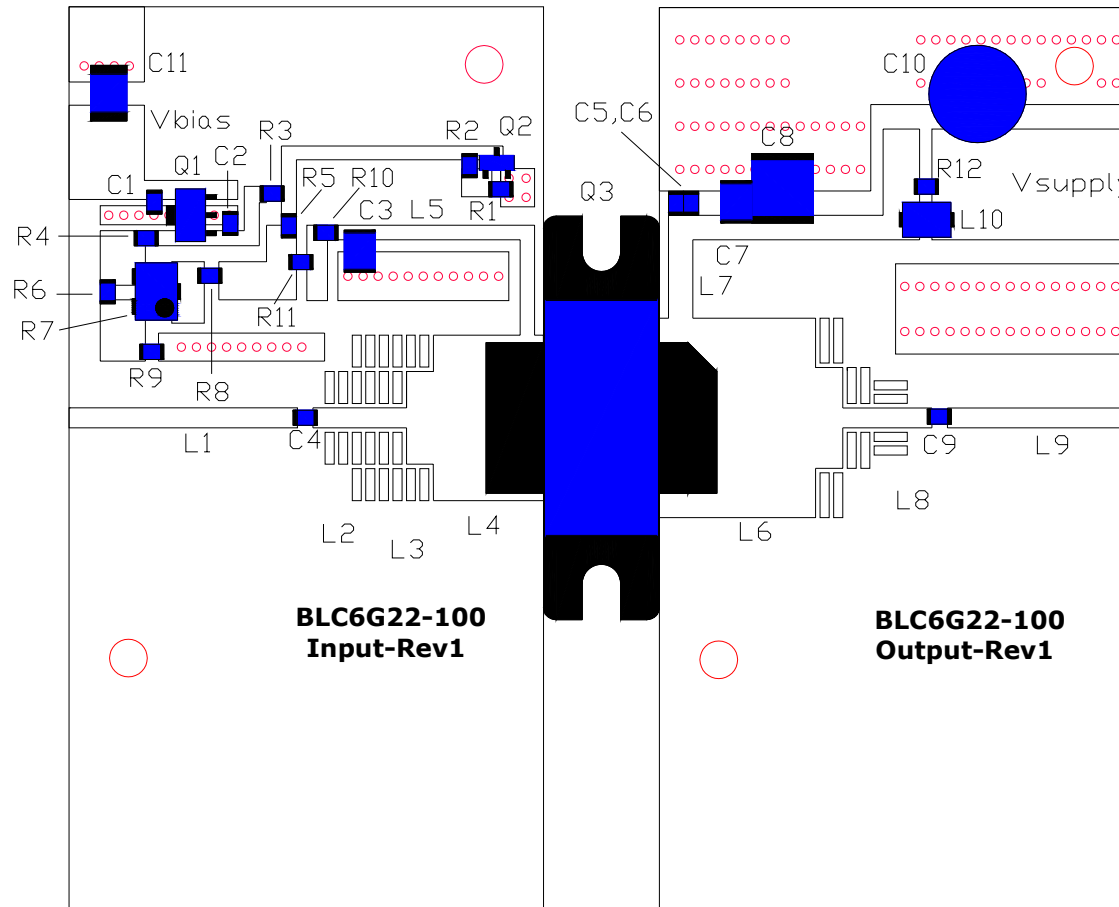
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UMTS Application Circuit

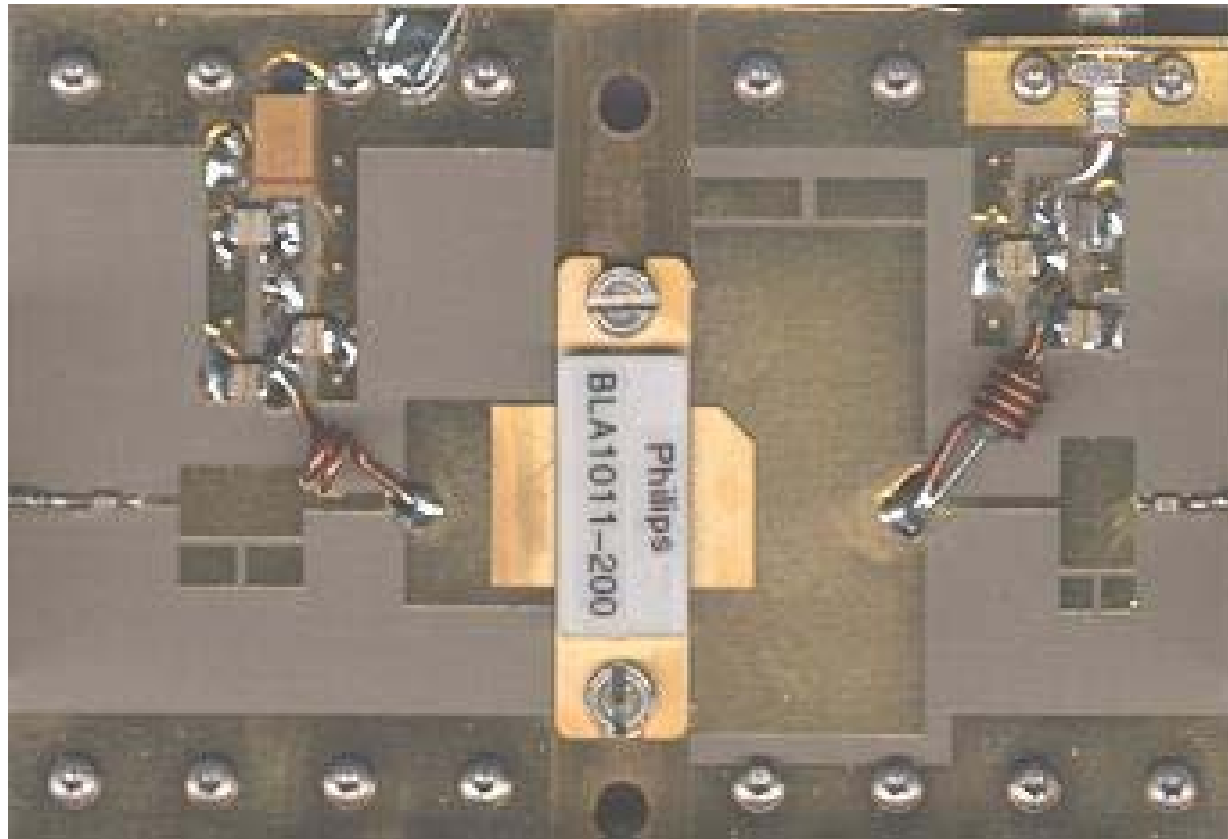


BLC6G22LS-100: 2110- 2170MHz – 100W

Application Circuit BLC6G22LS-100



Application Circuit BLA1011-200



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Thermal Resistance

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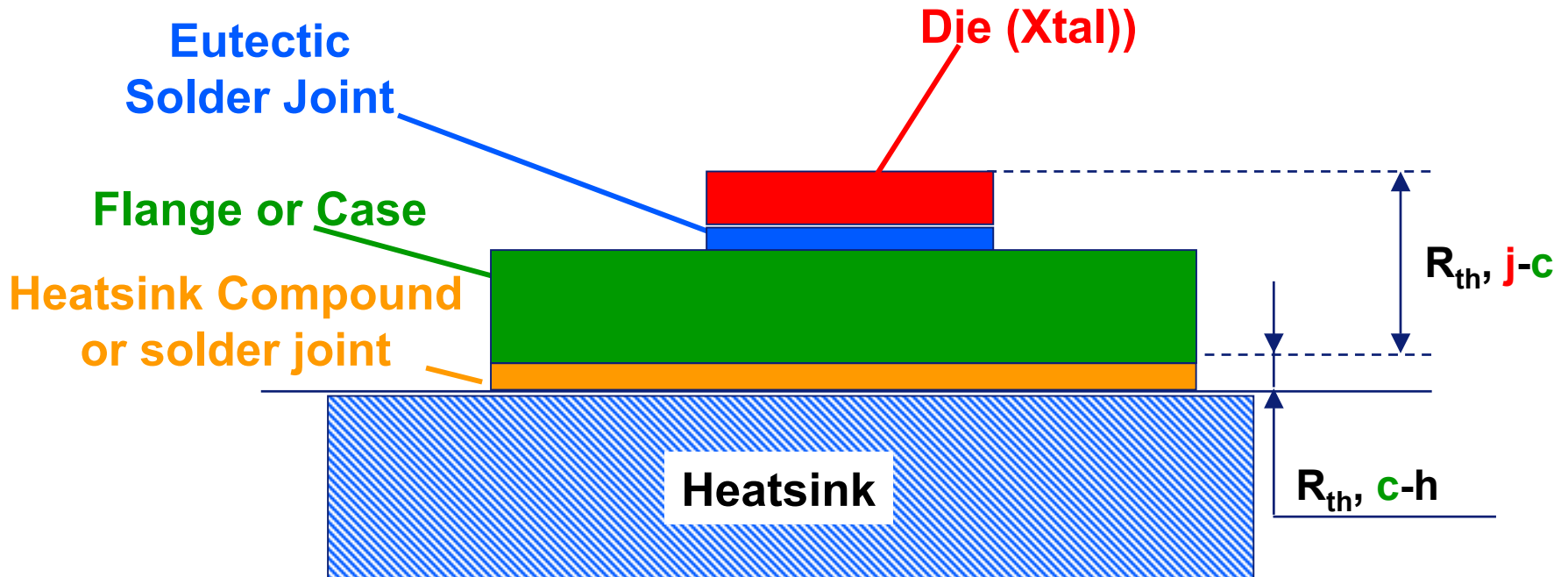
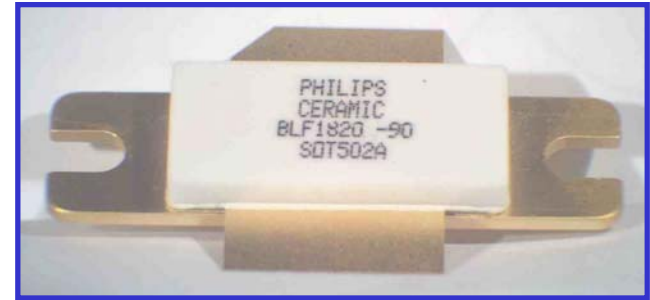
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Transistor thermal resistance



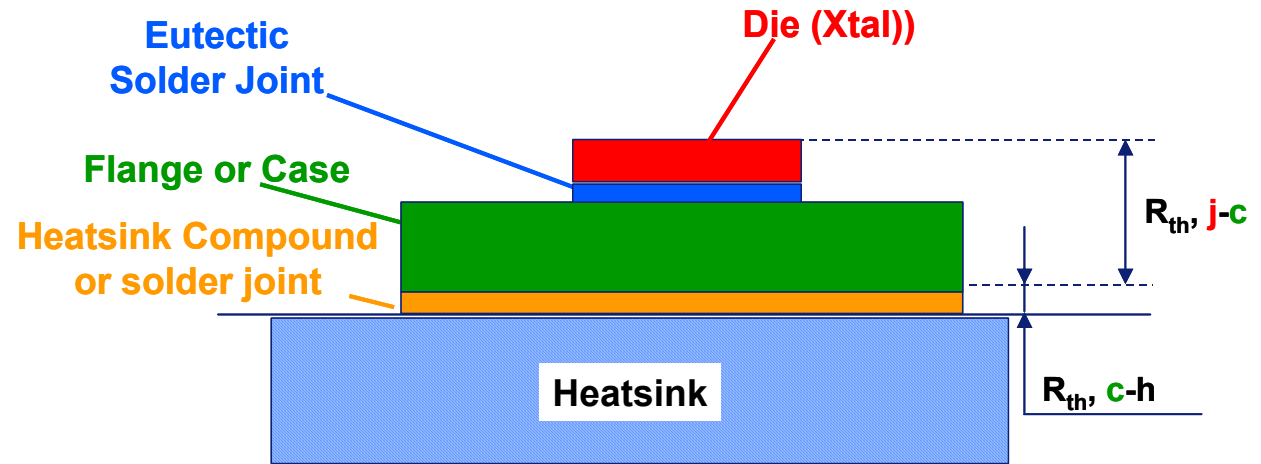
Transistor thermal resistance

$$R_{th} = \frac{\Delta T}{P_{diss}} [K/W \text{ or } ^\circ C/W] \text{ or } \Delta T = R_{th} \cdot P_{diss} [K \text{ or } ^\circ C]$$

- R_{th} is thermal resistance, often also called θ
- ΔT is temperature rise due to thermal interface in K or $^\circ C$
- P_{diss} is the dissipated power in Watts

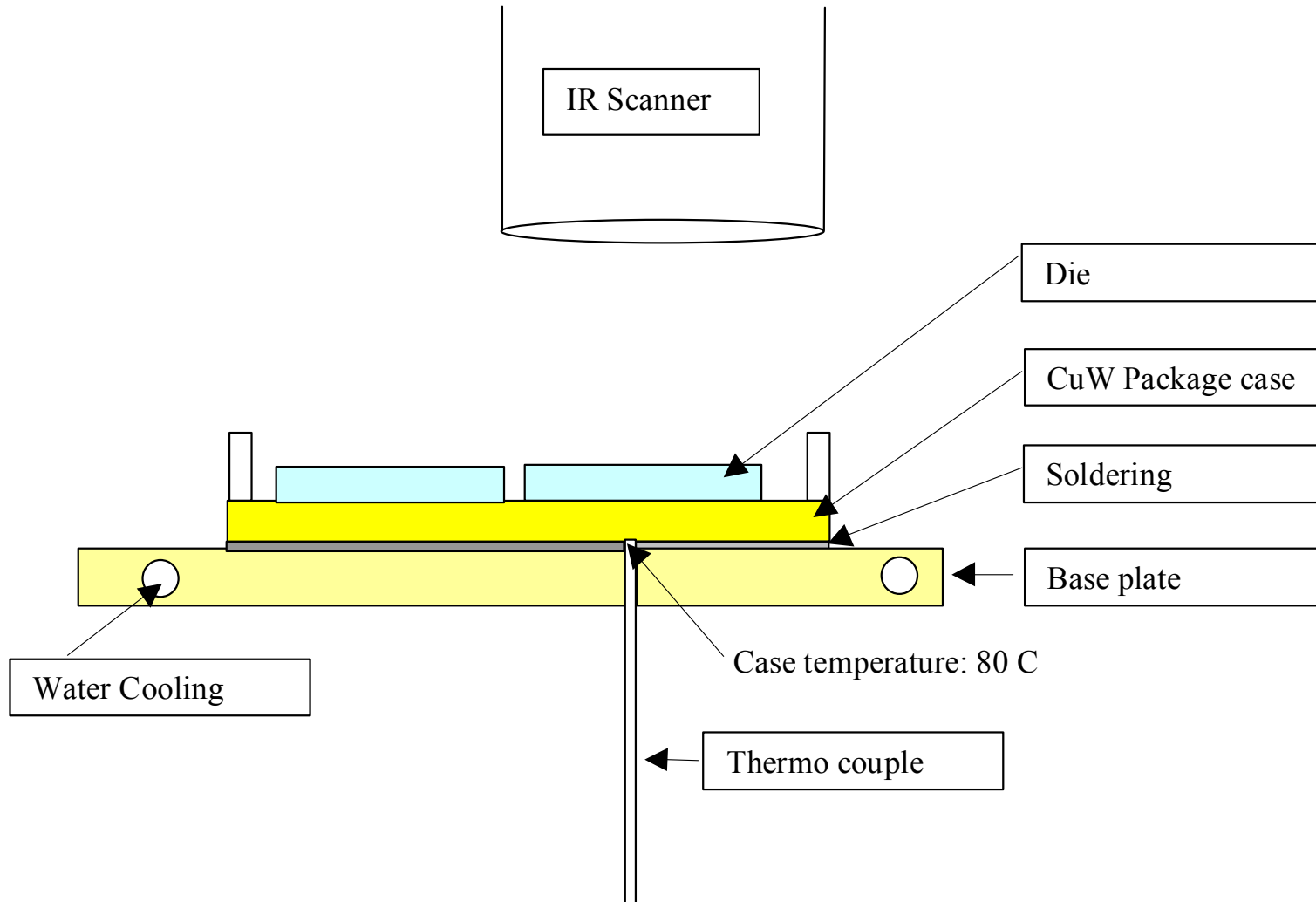
Example: If a transistor dissipates 100W, and the R_{th} is 0.35K/W, the temperature rise is 35 $^\circ C$

Transistor thermal resistance

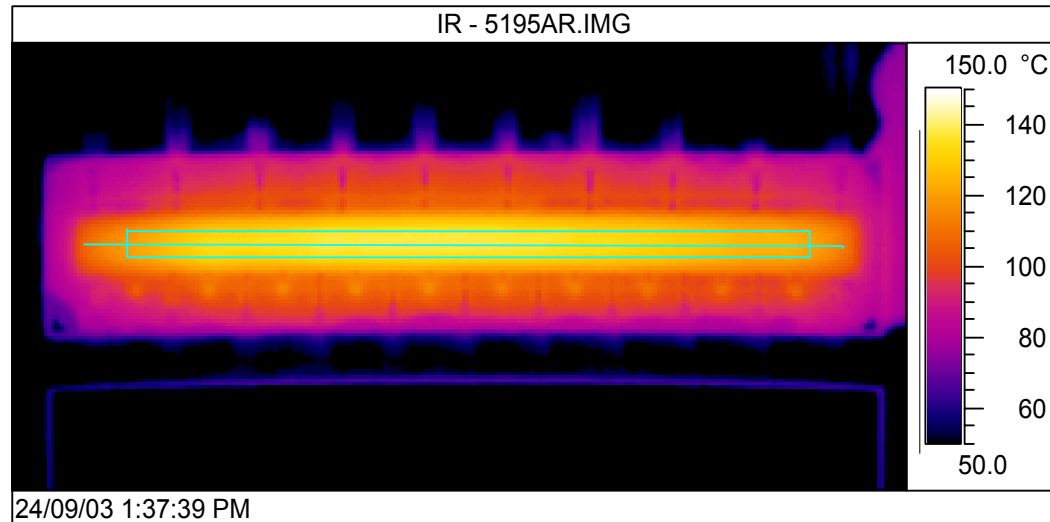
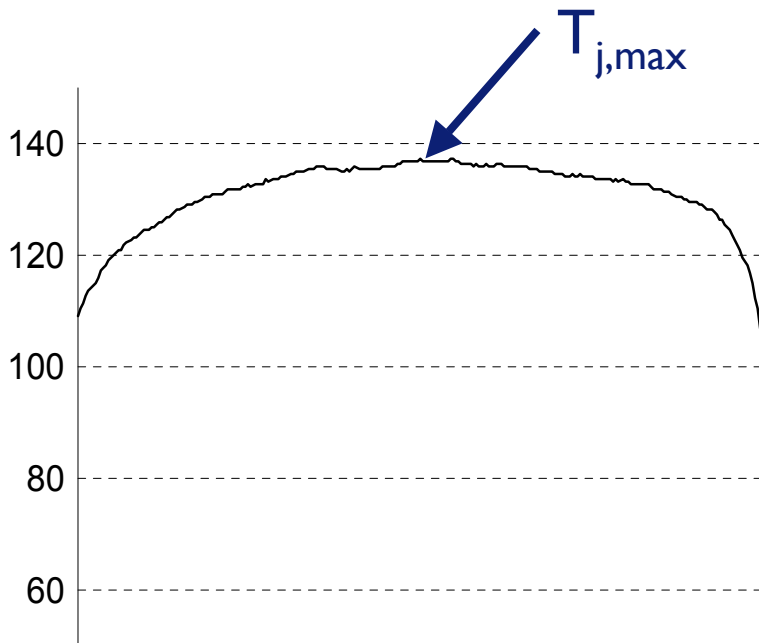


- One can define different thermal interfaces:
 - $R_{th, j-c}$: Junction to Case
 - $R_{th, c-h}$: Case to Heatsink
- In case of a solder joint, the $R_{th, c-h}$ can be (almost) ignored

Infra Red Scanner Setup



Typical IR-scanner data



Rth figures are determined based on *maximum* junction temperatures, not average junction temperatures, thus truly reflecting the worse case situation.

Rth calculations

$$P_{diss} = P_{dc} - P_{rf,out} + P_{rf,in} [Watts]$$

$$P_{dc} = V_{ds} \cdot I_{ds} [Watts]$$

$$P_{diss} = \left(\frac{P_{dc}}{P_{rf,out}} - \frac{P_{rf,out}}{P_{rf,out}} + \frac{P_{in}}{P_{rf,out}} \right) \cdot P_{rf,out} [Watts]$$

$$P_{diss} = \left(\frac{1}{\eta_D} - 1 + \frac{1}{10^{\frac{G_p}{10}}} \right) \cdot P_{rf,out} [Watts]$$

$$\eta_D [no\ dimension], G_p [dB], P_{rf,out} [Watts]$$

R_{th}

$$\Delta T = P_{diss} \cdot R_{th}$$

$$P_{diss} = \left(\frac{1}{\eta_D} - 1 + \frac{1}{10 \frac{G_p}{10}} \right) \cdot P_{rf,out} [Watts]$$

- Looking at the formulas above, one can conclude:
 - In order to minimize the temperature rise:
 - R_{th} should be as low as possible
 - η_D should be as high as possible
 - G_p should be as high as possible
- And that is exactly why our customers want:
 - An LDMOS technology with higher gain and efficiency
 - A die layout that ensures a low R_{th}
 - Thinner die to minimize R_{th}
 - Improved transistor packaging to lower the R_{th}

PHILIPS

Reliability / Electromigration

Korné Vennema

Marketing Application Engineer RF Power Transistors and Modules

Philips Semiconductors

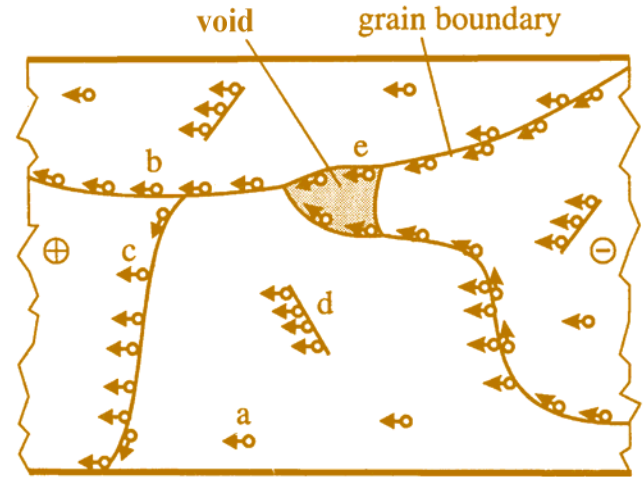
25 Forbes Boulevard,

Foxborough MA 02035

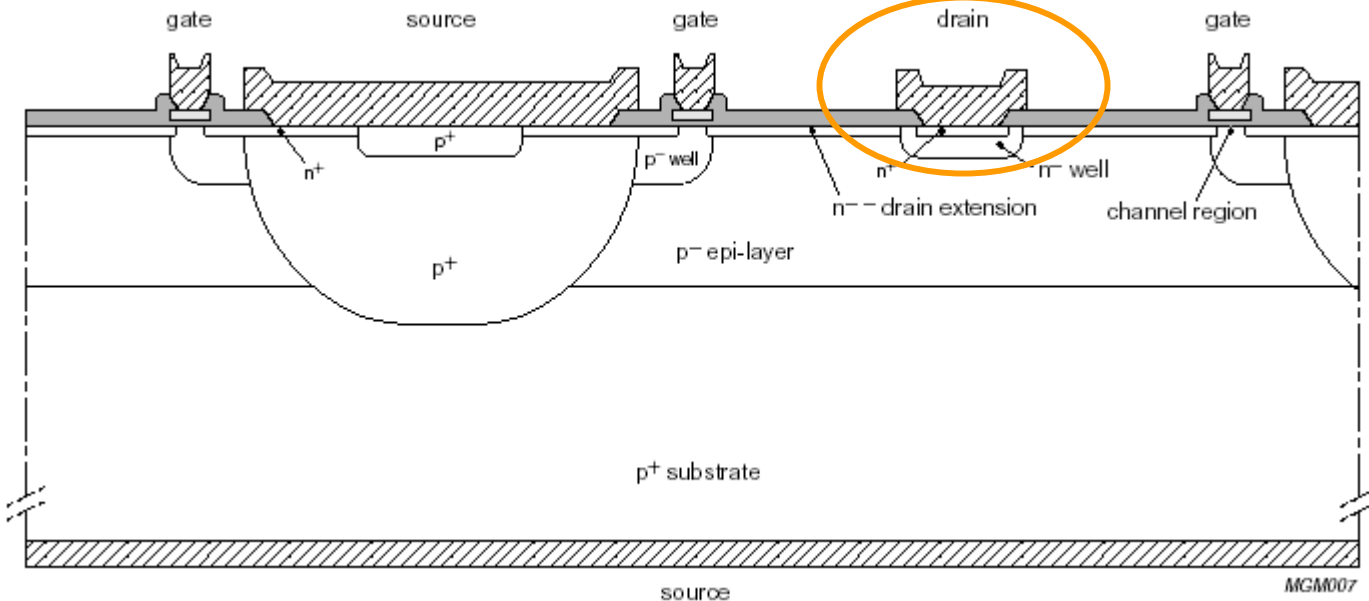
LDMOS Reliability

Electromigration

Electromigration is the dominant wear-out mechanism in LDMOS



Electron flow due to DC current



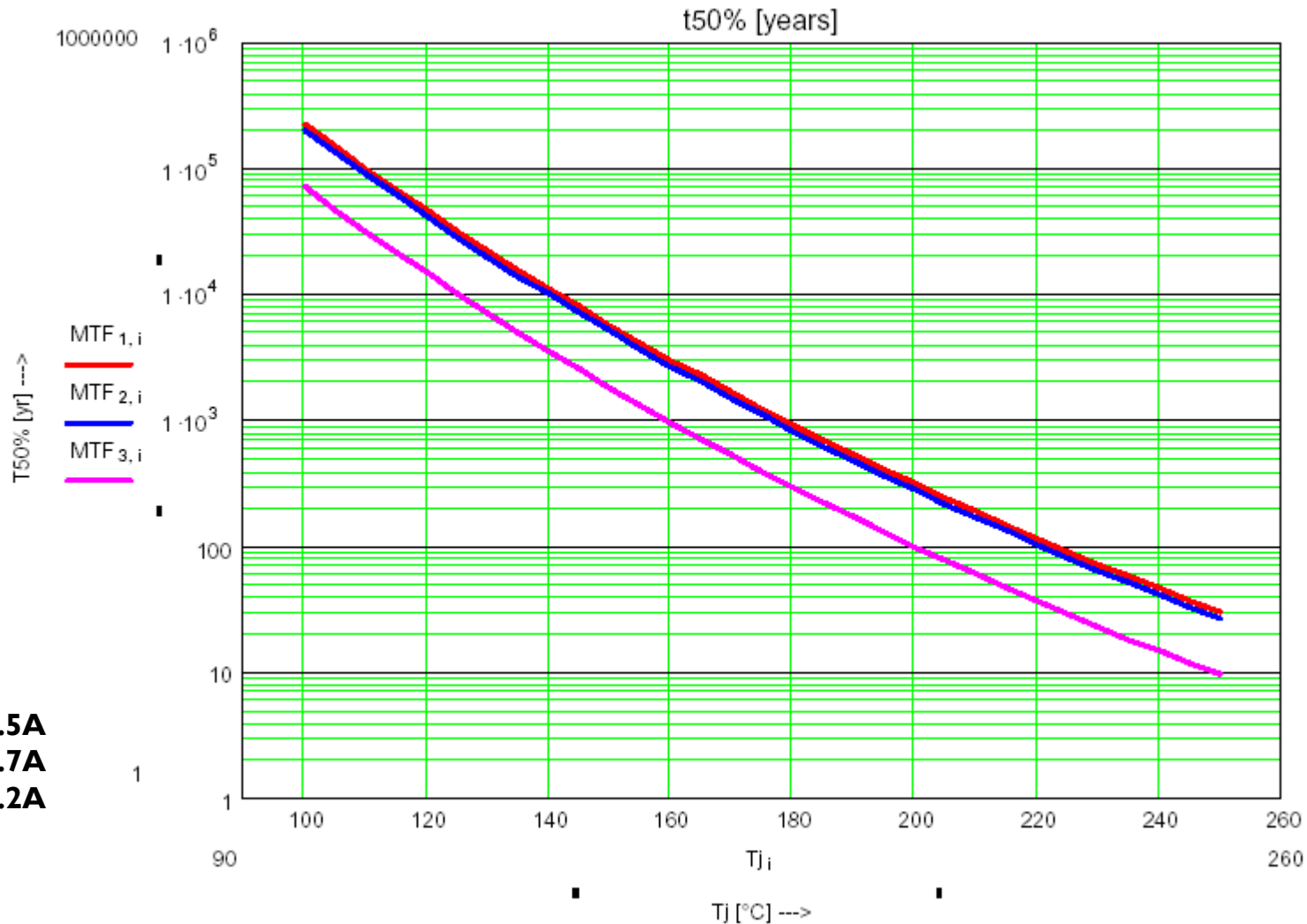
Acceleration Model

Black's equation: $M(\text{edian}) T(\text{ime}) \text{ to } F(\text{ailure}) = \frac{C}{J^n} e^{\frac{E_a}{k_B T}}$

$$\text{or, } \ln(MTF \cdot J^n) = \ln(C) + \frac{E_a}{k_B T}$$

J	: Current density
n	: Current density exponent (n=2)
C	: Constant
E_a	: Activation energy ($E_a=1.0\text{eV}$)
k_B	: Boltzmann's constant
T	: Temperature

MTF for Generation 4 LDMOS



Safe operating temperature GEN4

- There is not one single opinion in the industry about the safe operating temperature of LDMOS devices.
- Some customers want to stay around 150°C, some around 160°C.
- It is completely safe to use Philips LDMOS in excess of 170°, and even then the reliability of our parts is excellent.

Summary

Today, LDMOS is the technology of choice for any RF power amplifier design up to 3.5GHz. LDMOS is the cheap, it is (re) producible, mature and offers state-of-the-art performance characteristics. Further refinement and performance improvements are possible in this technology, however the theoretical limits are being approached.